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X-RAY DIFFRACTION STUDIES OF SILICON AND MERCURY COMPLEXES WITH ORGANIC LIGANDS

A Thesis

presented by

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to the

University of St. Andrews in application for the Degree of Doctor of Philosophy.



DECLARATION

I hereby declare that this thesis has been composed by me, is a record of work done by me, and has not previously been presented for a Higher Degree.

The work was carried out in the research laboratories of the Physics Department, St. Salvator's College,
University of St. Andrews, under the supervision of
Dr. R.C.G. Killean.

Valerie A. Brookeman

CAREER

In July 1965 I graduated with 1st class B.Sc. honours in Physics at St. Salvator's College, University of St. Andrews. In October 1965 with the award of a Science Research Council studentship I was enrolled under general Ordinance 12 as a research student in the Physics Department, University of St. Andrews. In October 1966 I was transferred to Ordinance 16 as a candidate for the degree of Ph.D.

CERTIFICATE

I certify that Valerie Anne Brookeman (née Bain), B.Sc., has spent nine terms at research work in the Physical Laboratory of St. Salvator's College, University of St. Andrews, under my direction, that she has fulfilled the conditions of Ordinance No. 16 (St. Andrews) and that she is qualified to submit the accompanying thesis in application for the Degree of Doctor of Philosophy.

Research Supervisor.

Acknowledgements

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THEORY

1.1 Introduction

The purpose of crystal structure analysis by x-ray diffraction is to postulate a molecular structure whose diffraction spectra match the experimentally obtained set. The principles used are essentially those of physical optics since the x-ray diffraction pattern obtained is the Fourier transform of the object, and a subsequent inverse transform of the diffraction pattern will give the image.

The diffraction pattern is a map of the reciprocal lattice of the crystal; a plane [h,k,l] in real space diffracts x-rays to form the reflection (h,k,l) in reciprocal space, the reciprocal lattice vector $\underline{h}(h,k,l)$ being normal to the plane [h,k,l] of the crystal lattice and of magnitude 1/d where d is the spacing of (h,k,l) planes in the real lattice.

The cyclic nature may be represented schematically as follows:

object \longrightarrow diffraction pattern \longrightarrow image

real space \longrightarrow reciprocal space \longrightarrow real space $\rho(\underline{r}) \longrightarrow F(\underline{h}) = T[\rho(\underline{r})] \longrightarrow \rho(\underline{r}) = T^{-1}[F(\underline{h})]$ $\underline{r}(x,y,z) = \text{vector in real space}$

 $\underline{h}(h,k,1)$ = vector in reciprocal space

T = Fourier transform

T⁻¹ = inverse Fourier transform

 $F(\underline{h})$ = vector amplitude of the radiation scattered by the crystal and received at the point \underline{h} in reciprocal

space
=
$$V \int_{X,Y,Z=0}^{\infty} \rho (\underline{r}) \exp 2\pi i \underline{h} \cdot \underline{r} dV$$
 (1)

where V = volume of the unit cell; $\rho(\underline{r})$ is the electron density at point \underline{r} in the crystal, and since the crystal is periodic in three dimensions may be represented by a three dimensional Fourier series:

$$\rho(\underline{\mathbf{r}}) = 1/V \sum_{\underline{h}} \sum_{\underline{k}} F(\underline{\mathbf{h}}) \exp{-2\pi \mathbf{i} \ \underline{\mathbf{h}} \cdot \underline{\mathbf{r}}}$$
 (2)

The structure factor F(h) is also represented by the equation:

$$F(\underline{h}) = \sum_{j=1}^{N} f_{j}(\underline{h}) \exp 2\pi i \, \underline{h} \cdot \underline{r}_{j}$$
 (3)

where N = number of atoms in the unit cell

$$f_{j}(\underline{h}) = V \int_{x,y,\underline{h}}^{\infty} \rho(\underline{r}-\underline{r}_{j}) \exp 2\pi i \, \underline{h} \cdot (\underline{r}-\underline{r}_{j}) dV$$

$$= \text{scattering factor or form factor for the } j^{th} \text{ atom}$$

$$\text{at position } \underline{r}_{j} \text{ (fractional coordinates } x_{j},y_{j},z_{j})$$

$$F(\underline{h}) = \sum_{j=1}^{N} f_{j} \cos 2\pi \, \underline{h} \cdot \underline{r}_{j} + i \sum_{j=1}^{N} f_{j} \sin 2\pi \, \underline{h} \cdot \underline{r}_{j}$$

= $|F(h)| \exp i \phi$

Thus the structure factor $F(\underline{h})$ is seen to be a complex quantity with magnitude $|F(\underline{h})|$ and phase $\phi = \tan^{-1}B/A$. It is only possible to measure the intensity (=(Amplitude)^2) of the diffracted x-rays, and hence obtain a value for the structure factor magnitude $|F(\underline{h})|$ but not for its phase $\phi_{h,k,l}$. Without knowledge of the phases, equation (2) above cannot be used in determining a representation

of the molecular structure.

However by using a Fourier summation with the squared amplitudes as coefficients, this problem may be overcome since $|F(\underline{h})|^2$ for any reflection is directly proportional to the observed intensity. The relationship of the Patterson function (Patterson, 1934 and 1935), as this synthesis is called, to the electron density function of the crystal may be found by applying the Convolution Theorem.

 $T[F(\underline{h})F*(\underline{h})] = V \int_{0}^{\infty} \int_{0}^{\infty} \rho(\underline{r}) \rho(\underline{r}-\underline{r}') dV = P(\underline{r}') = 1/V \sum_{\underline{h}}^{\infty} \int_{0}^{\infty} F(\underline{h})|^{2} \exp 2\pi i \ \underline{h}.\underline{r}'$ Since $|F(\underline{h})| = |F(\underline{h})|$ by Friedel's Law, the Patterson function may be represented by the series:

$$P(u,v,w) = 1/v \sum_{k=1}^{\infty} \sum_{\ell} |F(\underline{h})|^2 \cos 2\pi (hu+kv+lw)$$
(u,v,w are fractional coordinates)

Thus, a centrosymmetric set of interatomic vectors can be obtained from the measured intensities which has N(N-1)/2 unique vector peaks where N = number of atoms. The interpretation of this vector map is difficult if N is large and is much simplified if "heavy" atoms with high atomic number Z are present in the molecule.

Since the size of each vector peak in the Patterson map is proportional to the product of the scattering factors for the two atoms concerned, the largest peaks can be identified and the positions of the heavy atoms in the crystal lattice found. This is the method used for the solution of the molecular structure of tetrachlorobispyridinesilicon (IV) (SiCl_h,2Py) and described in Chapter 4.

In the investigation of tetrafluorobispyridinesilicon IV (SiF4,2Py)

discussed in Chapter 3 where apart from the Silicon atom, no one atom is much heavier than any other, use was made of the expected relative orientation of atoms and interatomic distances to interpret the Patterson vector set and position some of the atoms. The total scattering power of the atoms thus located was large enough for the investigation to proceed along the same lines as the "heavy atom method".

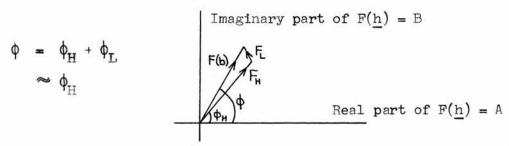
The structure factor for any reflection as given by equation (3) may be expanded in the form

$$F(\underline{h}) = \sum_{i=1}^{M_1} f_{H} \exp 2\pi i (hx_{H} + ky_{H} + lz_{H}) + \sum_{i=1}^{M_2} f_{L} \exp 2\pi i (hx_{L} + ky_{L} + lz_{L})$$

$$= F_{H} + F_{L}$$

where F_H = contribution from the M₁ heavy atoms

 F_L = contribution from the remaining M_2 = N-M₁ light atoms F_H is the dominant term in the expression for $F(\underline{h})$ since $f_H > f_L$, and can be evaluated using the heavy atom coordinates $(x_H y_H z_H)$ found from the Patterson map. Thus the phase ϕ of $F(\underline{h})$ will be determined mainly by the phase contribution ϕ_H , from the heavy atoms, as shown vectorally in the Argand diagram:



The calculated phases ϕ_H are almost equal to the true phases ϕ and are assigned to the experimentally obtained set of structure

amplitudes $|F_0(\underline{h})|$. Using the structure factors $|F_0(\underline{h})|$ exp i ϕ_H in equation (2), a Fourier synthesis of the electron density is computed, which will be sufficiently correct to indicate the positions of the remaining atoms within the unit cell. The final electron density distribution throughout the unit cell obtained from equation (2) is not a perfect image of the object due to termination effects in not summing the series from - ∞ to + ∞ , and due to errors in estimation of structure amplitudes $|F_0|$ from both experimental measurement and physical factors.

1.2 The observed structure amplitude | F (h)

The quantity actually measured in x-ray diffraction experiments, either by photographic or diffractometer techniques, gives the integrated intensity $I(\underline{h})$ of the diffracted beam for each reflection. This is related to the structure amplitude $|F_0(\underline{h})|$ by the following expression, which has its basis in the Thomson theory of the scattering of x-rays by electrons, with subsequent deductions by Bragg, James and Bosanquet (1921).

 $I(\underline{h}) = E(\underline{h}) w/I_o = Q dV = (N^2 \lambda^3 e^4 / m^2 c^4) \times L_p F_o(\underline{h})^2 dV$ (5) where E(h) = total diffracted energy at h

I = intensity of the incident x-ray beam

8v = volume of crystal bathed in x-rays

(assumed so small that absorption effects may be neglected)

w = angular velocity of the crystal, which must be rotated through the region of the Bragg reflection because of the mosaic structure of the crystal.

N = number of unit cells for unit volume

The Polarisation factor $p = \frac{1}{2}(1+\cos^2 2\theta)$ is introduced since the original expression assumed plane polarised incident x-rays. In fact, the characteristic incident beam from the target is unpolarised with a consequent reduction in the diffracted intensity by the factor p, which is independent of the experimental geometry.

The Lorentz factor L is a measure of the relative time opportunity for the various crystal planes to reflect x-rays, and is therefore dependent on the experimental method.

For equi-inclination Weissenberg geometry, which was used for all data collection reported in this thesis, the Lorentz factor can be shown to be $1/\cos^2\mu\sin^2\gamma$ where the axis of rotation of the crystal makes angle $(\pi/2 - \mu)$ with the incident beam and is the projection on the zero level of the angle 20 between incident and reflected beams.

Thus, for one particular crystal using radiation of wavelength λ , equation (5) may be rewritten simply as:

$$|F_{\underline{O}}(\underline{\underline{h}})|^2 = \text{constant } x(\underline{Lp})^{-1} \underline{I}(\underline{\underline{h}})$$
 (6)

A set of relative structure amplitudes may therefore be obtained for use in equation (4).

1.3 The atomic scattering factor

The scattering factor f_j used in calculating $F_c(\underline{h})$ from equation (3) is a measure of the efficiency of the j^{th} atom in scattering x-rays

and is defined such that the atom scatters f times as much as a single electron. It is a function of $\sin\theta/\lambda$ and as θ increases, f decreases because waves scattered by electrons in different parts of the atom interfere destructively. As $\theta \to 0$, f $\to Z_j$, the number of electrons in the atom or ion.

Estimates of atomic scattering factor curves f_{oj} have been calculated for most atoms using various atomic models (International Tables for X-Ray Crystallography, Vol. III, p. 201) but these all assume that the atom is at rest and that the electron density has a spherically symmetric distribution.

The form factor $f_{o,j}$ for the j^{th} atom at rest must be modified to take account of the thermal motion due to temperature. The effect of thermal vibrations is to reduce the structure factor $F_{c}(\underline{h})$ because two equivalent atoms will no longer scatter in phase, since displaced from their true positions. A more realistic scattering factor is:

 $f_{j} = f_{oj} \exp \left(-B \sin^{2}\theta/\lambda^{2}\right) \tag{7}$ The temperature factor $B = 8\pi^{2} \frac{u_{j}^{2}}{u_{j}^{2}}$ where u_{j}^{2} is the mean square atomic displacement (Debye, 1914 and Waller, 1927). B is not easily calculated theoretically and may be found for each atom by comparing $|F_{o}(\underline{h})|$ with $|F_{c}(\underline{h})|$ for successive refinements of a trial structure or obtained from an electron density map (Hamilton, 1955).

The scale and temperature factors may also be found by Wilson's Method (1942) or by taking a compromise between Wilson's plot and

another auxiliary curve. (Rogers, 1954). Rogers (1965) has considered isolating the origin peak of the Patterson, the source of Wilson's equation, and transforming it to minimise the effects of off-diagonal terms.

Although expression (7) is sufficiently accurate in the early stages of structure determination, it does assume isotropic thermal vibration, and during subsequent refinement must be replaced by a more realistic expression, assuming ellipsoidal anisotropic atomic motion (Cruickshank 1956).

$$f_{ij} = f_{0,i} \exp -(B_{11}h^2 + B_{22}k^2 + B_{33}l^2 + B_{12}hk + B_{23}kl + B_{13}hl)$$
 (8)

The anisotropic thermal motion is represented by an ellipsoid of vibration in real and reciprocal space. The six temperature factors B_{ij} for each atom define the principal axes and direction cosines of the ellipsoid.

This was the procedure adopted in the structure analyses described in Chapters 3 and 4.

1.4 Refinement

Once a structural model has been found by the methods already outlined it is necessary to improve the atomic coordinates and temperature parameters by a refinement procedure. This may be done by either Fourier or least squares techniques and since the latter method was used in this work only its relevant theory will be given. The advantages of least squares refinement over Fourier syntheses are that there are no series termination effects, and thus unobserved reflections can be safely excluded. Also, an

estimate of the accuracy of each $|F_0|_{\bf i}$ can be included as a weighting factor w, allotted to each reflection.

The method of least squares in x-ray crystallography consists of minimising the weighted sum of the squares of the discrepancy between the observed and calculated structure amplitudes, namely

$$R = \sum_{i=1}^{m} w_{i} (|F_{o}|_{i} - |F_{c}|_{i})^{2} \text{ (Hughes, 1941)}$$

$$= \sum_{i=1}^{m} w_{i} \Delta_{i}^{2}$$

where m = number of reflections included in the refinement.

R is a minimum when
$$\partial R/\partial u_s = 0$$
 i.e. $\sum_{i=1}^{m} w_i \Delta_i \partial u_s = 0$ (9)

u is one of n parameters to be adjusted.

The Δ_i are not linear in $u_s(s=1\rightarrow n)$ and equation (9) therefore represents a set of n simultaneous non-linear equations.

If however an approximate set of parameters $\mathbf{u'}_{\mathbf{r}}$ is known the Δ , may be expanded to the first order of a Taylor series

$$\Delta_{i} = g_{i} + \sum_{r=1}^{n} (\partial \Delta_{i}/\partial u_{r}) \delta_{r}$$
 where $\delta_{r} = u_{r} - u'_{r}$

Substituting this into equation (9) one obtains

$$\sum_{i=1}^{m} \left[w_{i} \frac{\partial \Delta_{i}}{\partial u_{s}} \sum_{r=1}^{n} \frac{\partial \Delta_{i}}{\partial u_{r}} \delta_{r} \right] = -\sum_{i=1}^{m} w_{i} \Delta_{i} \frac{\partial \Delta_{i}}{\partial u_{s}}$$
(10)

These n equations (for s = 1 \rightarrow n) are the normal equations and are linear in the δ_s which may thus be determined.

The factor $\partial \Delta_i/\partial u_s = -\partial |F_c|_i/\partial u_s$ may be calculated for each of the n parameters (Cruikshank et al, 1961) and the trial values u'_s are substituted into equations (10). The following

procedure is used in programme 3 (Appendix A). Solution of the matrix is much simplified by making the following assumptions:

- 1) no interaction between the parameters of different atoms i.e. set terms of the type $(\partial |F_c|/\partial x_1) \cdot (\partial |F_c|/\partial x_1) = 0$
- ii) no interaction between the coordinate parameters and temperature parameters for the same atom i.e. set terms of the type $(\partial |F_c| / \partial x_i) \cdot (\partial |F_c| / \partial B_i) = 0$

This is the block diagonal approximation (Cruikshank et al, 1961) and reduces the normal equations matrix to the following submatrices:

- N 3x3 matrices for solution of positional parameters
- N 6x6 matrices for solution of anisotropic B_{ij}'s or 1x1 matrix for solution of isotropic temperature parameter B
- N = number of atoms whose parameters are to be determined.

For solution of the shift in scale factor applied to $|F_0|$, a 2x2 matrix is used to take account of the interaction between the scale and overall isotropic temperature factor. This interaction is significant since a small decrease in scale has the same effect as a small increase in the overall B.

In programme A3 Schomaker's correction (1950) is applied to the shifts of the individual temperature factors for each atom. Thus if $\Delta B'$ is the overall isotropic temperature factor change calculated from a 1x1 matrix and $\Delta B'$ is the overall isotropic temperature factor change calculated from a 2x2 matrix (interaction with scale shift allowed for) then:

 Δ_{B} corrected = Δ_{B} apparent + $\Delta_{\text{B''}}$ - $\Delta_{\text{B'}}$

 ΔB_{ij} corrected = ΔB_{ij} apparent + $(\Delta B'' - \Delta B')R_{ij}/\lambda^2$ where the $R_{i,j}$'s are defined as given in Appendix A3.

Use of the block diagonal approximation assumes that the atoms are resolved in Fourier space, and it neglects the effect of the thermal parameters of an atom with large vibration on the coordinates of its neighbours.

The parameter shifts $S_{\mathbf{r}}$ calculated by least squares are generally too large and to prevent the solution oscillating a damping factor is applied to each $S_{\mathbf{r}}$, suggested values being given by Hodgson and Rollett (1963). The possible reasons for the necessity of this fudge factor have been discussed by Cruikshank (1961), Wegener (1961) and Sparks (1961).

An iterative procedure of least squares refinement is followed until $\sum_{i=1}^{m} w_i \Delta_i^2$ has been minimised. An indication of the agreement between the observed structure amplitudes $|F_0|$ and those calculated from the proposed atomic positional and thermal parameters, $|F_c|$, is the R factor $= \sum ||F_0| - |F_c|| / \sum |F_o||$

1.5 Weighting Schemes

For successful use of the least squares method of refinement, sensible weights w_i must be chosen since a bad weighting scheme gives misleading conclusions. The observed structure amplitudes are subject to random and systematic errors due to the crystal itself, the geometry of the experiment and the intensity

measuring procedure.

In order to obtain the most accurate parameters with lowest standard deviation, the best choice is $w_{\mathbf{i}}(\underline{\mathbf{h}}) = 1/\delta_{\mathbf{i}}^2(\underline{\mathbf{h}})$ where $\delta_{\mathbf{i}}^2 = \text{variance of } \Delta_{\mathbf{i}} = (|\mathbf{F}_0|_{\mathbf{i}} - |\mathbf{F}_c|_{\mathbf{i}})$. Two different schemes were used in the refinements (a) for photographic data (b) for the diffractometer data.

(a) Absolute values of w_i are unknown in advance and relative estimates are made, by approximating to a simple function of $|F_o|$. It is assumed that \mathcal{O}_i depends only on $|F_o|_i$ since the uncertainties are more strongly dependent on the random errors in $|F_o|$ than on any other factor. The scheme used must ensure that $\sum w \Delta^2$ is constant for any group of $|F_o|$'s and the one used was:

$$w = [1 + ((kF_0 - F**)/F*)^2]^{-1}$$
 (11)

where F* was taken to be $8F_{\min}$ and F**, $5F_{\min}$. This is similar to that proposed by Cruikshank (1961) where $w = (a + |F_o| + c|F_o|^2)^{-1}$, $a \approx 2F_{\min}$ and $c \approx 2/F_{\max}$, and is effectively $w = 1/F_o^2$, which was the first scheme applied to structure analysis (Hughes, 1941).

(b) For diffractometer collected data with constant time spent on each integrated reflection, Grant et al (1968) have devised a suitable weighting scheme which takes into account not only counting statistical errors but other random errors as well.

Considering counting statistics alone, the least squares weight $w(h) = \frac{4Lp}{l} (\frac{I-B}{l}) = \frac{1}{l}$

$$w(\underline{h}) = \frac{\mu_{Lp}}{K} \left(\frac{I-B}{I+B}\right) = \frac{1}{\sigma_1^2(\underline{h})}$$

where I = peak count and B = background count for $|F_o(\underline{h})|$. However in diffractometer experiments other random errors are significant, for example due to the peak being off centre.

An improved weighting scheme which assumes that for a given crystal the peak shape near the centre is the same for all reflections, is:

$$\frac{1}{w(\underline{h})} = \frac{K}{4Lp} \left(\frac{I+B}{I-B} \right) + e^2 F_0^2(\underline{h})$$

$$= \sigma_1^2(\underline{h}) + \sigma_2^2(\underline{h}) = \sigma^2(\underline{h})$$
(12)

where c is a constant for a given crystal.

Once c has been determined an absolute numerical value of $w(\underline{h})$ may be assigned to each reflection.

By using the G-factor (Kitaigorodski, 1957) as a measure of goodness-of-fit, c² may be calculated relatively simply since

$$g^{2} = \frac{\sum_{h} |\Delta_{(h)}|^{2}}{\sum_{h} |F_{o}(\underline{h})|^{2}} = \frac{\sum_{\sigma^{2}(\underline{h})}}{\sum_{h} |F_{o}(\underline{h})|^{2}}$$

by taking the estimate of $\sigma(\underline{h})$ as $\sigma(\Delta(\underline{h})) = \Delta(\underline{h})$ (Cruickshank, 1949). Substituting equation (12) into this gives:

$$e^{2} = \frac{\sum_{i=1}^{m} (|F_{o}| - |F_{c}|)^{2}_{i}}{\sum_{i=1}^{m} |F_{o}|_{i}^{2}} - \frac{\sum_{i=1}^{m} \frac{K}{4Lp} (\frac{I+B}{I-B})_{i}}{\sum_{i=1}^{m} |F_{o}|_{i}^{2}}$$
(13)

= G²(theoretical) - G²(counting statistics)

K is a scaling factor which must ensure that all the terms in equation (13) are on the same absolute scale.

G(theoretical) is an estimate of the total experimentally obtained discrepancy between all $|F_0|$ and F_c since it is directly

related to the correlation coefficient.

G(counting statistics) is a measure of the error due to counting statistics in the measured intensities, and thus c is equivalent to other errors incurred such as instrument inaccuracy, crystal quality and crystal missetting.

For both sets of linear diffractometer data, collected for SiF_{μ} ,2Py and SiCl_{μ} ,2Py, least squares refinement was continued as far as possible with the weighting scheme (a), and only then was c² calculated from equation (13) using the best set of F_c 's available at that stage. Individual weights according to (12) were then applied to each $|F_c|$ and refinement continued until $\sum_{k} \Delta^2$ was a minimum, and it will be seen in each case, close to its theoretical limit of (m-n) when on an absolute scale, where m=number of observations and n=number of parameters refined.

1.6 Accuracy of results

It can be shown (Cruikshank, 1965) that the estimated variance σ_s^2 of a parameter u_s , given by the variance of the shift δ_s , is: $\sigma_s^2 = (a^{-1})_{ss} \stackrel{m}{\underset{i=1}{\sum}} w_i \Delta_i^2/(m-n)$

where (a⁻¹)_{SS} is a diagonal element of the inverted normal equations matrix (cf. equation (10))

For the diagonal approximation of the normal equations matrix, this equation is simply: $\stackrel{m}{\leq}$ $\stackrel{\lambda}{\sim}$ 2

sequation is simply:
$$C_{s}^{2} = \frac{1}{\sum_{i=1}^{m} w_{i} \left(\frac{\delta |F_{c}|}{\delta u_{s}}\right)} \left(\frac{\sum_{i=1}^{m} w_{i} \Delta_{i}^{2}}{m-n}\right)$$

(Whittaker and Robinson, 1944; Cruikshank and Robertson, 1953).

These expressions are for weights $w_i = k/\delta_i^2$ where the statistical expectation of $\sum w \Delta^2$ is k(m-n) (k being a constant), and assumes that a correct weighting scheme has been used.

The programme used for least squares refinement (A3) calculates
the variances and covariances of the atomic positional parameters

from the formula:
$$\sigma_{sr}^{2} = a_{sr}^{-1} A_{s}^{A} \cos(sr) \sum_{i=1}^{m} w_{i} \Delta_{i}^{2}/(m-n) (A^{2})$$

where A_s and A_r are cell edges and $\cos(sr)$ is the cosine of the angle between edges s and r. a_{sr}^{-1} is an element of the inverted submatrix in the block diagonal approximation of the normal equations matrix.

The errors in bond lengths and angles, which programme A3 also evaluates, are obtained from the following formulae, assuming independent atoms i.e. covariances $\sigma_{\rm sr}^2$ (s \neq r) set equal to zero.

For the error in bond length AB between atoms A and B: $\sigma^2(AB) = \sigma^2(A) + \sigma^2(B) \text{ where } \sigma(A) \text{ and } \sigma(B) \text{ are the standard deviations of atoms A and B in the direction AB.}$

For the error in bond angle β subtended by atoms A and C at atom B:

$$\sigma^{2}(\beta) = \frac{\sigma^{2}(A)}{AB^{2}} + \sigma^{2}(B) \left[\frac{1}{AB^{2}} - \frac{2\cos\beta}{AB \times BC} + \frac{1}{BC^{2}} \right] + \frac{\sigma^{2}(C)}{BC^{2}}$$

$$= \frac{\sigma^{2}(A)}{AB^{2}} + \frac{\sigma^{2}(B)AC^{2}}{AB^{2}BC^{2}} + \frac{\sigma^{2}(C)}{BC^{2}}$$

6(A) and 6(C) are the standard deviations of atoms A and C in the ABC plane in directions perpendicular to AB and BC respectively. σ(B) is the standard deviation of atom B in the direction of the centre of the circle through A, B, and C (Darlow, 1960).

EXPERIMENTAL

This chapter is mainly concerned with the Hilger and Watts linear diffractometer which was used to collect intensity data from single crystals of mercury dibenzyl (MDB), SiF₄,2Py and SiCl₄,2Py. These structures are discussed in detail in Chapters 5, 3 and 4 respectively.

Section 1 is a description of both the mechanical and electronic parts of the instrument. Section 2 describes the faults and errors which were encountered during the use of the instrument over a two year period and sections 3 and 4 discuss the techniques employed once the instrument was eventually operational. While the diffractometer was out of action, photographic methods were adopted for the measurement of diffracted x-ray intensities from SiF_{h} , 2Py, and this procedure is outlined in the final sections. 2.1 The linear diffractometer (Arndt and Phillips, 1959,1961) is an instrument for "automatic" collection of single crystal diffracted intensities and is essentially a mechanical analogue of the Ewald sphere construction of the reciprocal lattice (Ewald, 1921). The condition for a family of planes [hkl] to diffract radiation of wavelength λ according to Bragg's law (2dsin $\theta = n\lambda$) is equivalent to the requirement that the reciprocal lattice point P(hkl) lies on the surface of the Ewald sphere of reflection.

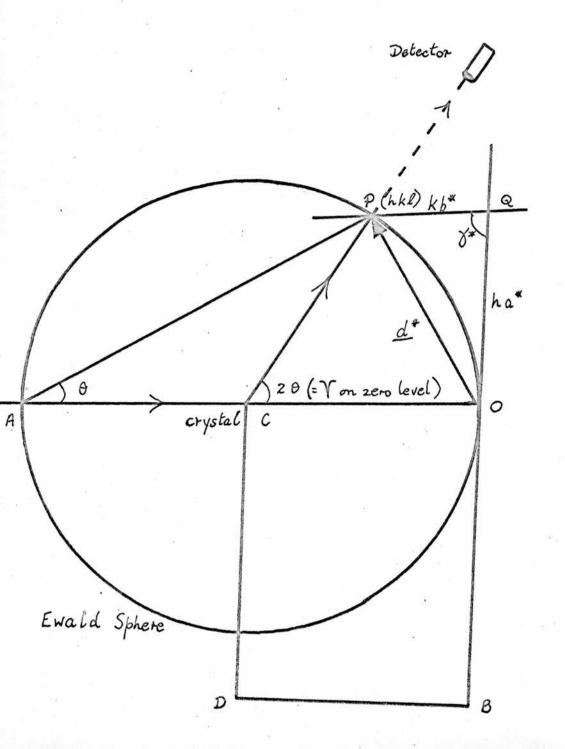


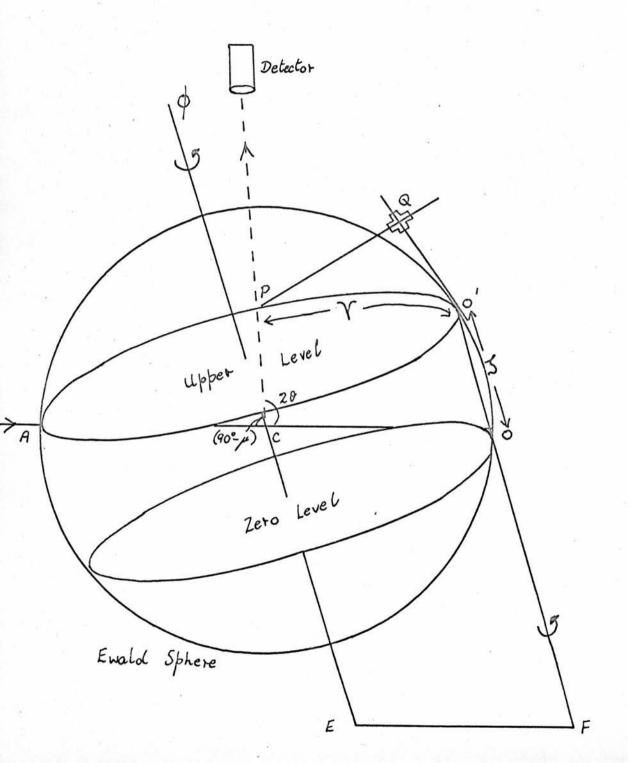
Figure 2.1.1 represents a horizontal section of the Ewald sphere, radius 1 reciprocal lattice unit (r.1.u.), and the two dimensional arrangement of the diffractometer when P(hkl) is in its reflecting position. AC and CP are the incident and reflected beams, C represents the crystal and 0 is the origin of the reciprocal lattice.

OP is the reciprocal lattice vector $\underline{\mathbf{d}}^*$ of the reflection P(hkl) = $\underline{\mathbf{h}}_{\underline{\mathbf{d}}}^* + \underline{\mathbf{k}}_{\underline{\mathbf{b}}}^* + \underline{\mathbf{l}}_{\underline{\mathbf{c}}}^*$, and of magnitude $\lambda/d(hkl)$. d(hkl) is the spacing of the [hkl] crystal planes, represented by AP, perpendicular to $\underline{\mathbf{d}}^*$. The crystal is mounted with a real axis, say $\underline{\mathbf{c}}$, along the goniometer axis ϕ and thus figure 2.1.1 is of the a*b* plane.

The diffractometer comprises three slides representing two reciprocal axes (a* and b*) and a real axis (c), to which the motions of crystal and detector are linked. A detector is placed on the bar CP, of fixed length (= | r.l.u.), pivoted at C and pointing towards C to receive the diffracted beam. The reciprocal axes a* and b* are represented by the slides OQ and QP, pivoted at C and P, with OQ=ha* and QP=kb*(r.l.u.) for the reflection P.

The crystal is pivoted at C, independently of the counter, and is linked by means of the parallelogram CDEO to the motion of the carriage Q along either slide OQ or QP. The crystal carrying arm CD bisects ACP.

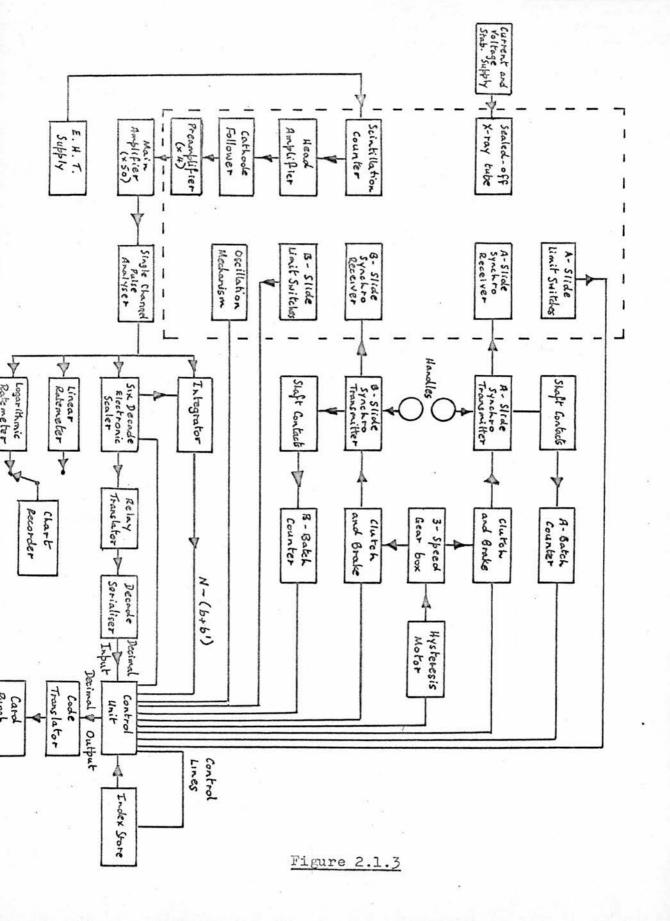
The carriage Q is moved in a linear fashion along either slide by driving the slides; the counter arm and crystal follow, rotating about the goniometer axis, and as successive reciprocal lattice points cut the



surface of the Ewald sphere, the detector is always at the correct angle 20 to the incident beam.

Figure 2.1.2 illustrates the extension of the principle to upper level data collection. Equi-inclination geometry is used since then the upper levels are similar to the zero level. A third slide 00', perpendicular to the plane of the other two, is kept parallel to the crystal axis c by means of a second parallelogram linkage CEFO, which also ensures equal rotation about CE and OO'. Since the x-ray beam is fixed, the whole system of figure 2.1.1 is tilted to give the correct height of level APO' as $\zeta = \frac{1\lambda}{c}(r.l.u.)$ = 00'. The angle of tilt is independently set at $\mu = \sin^{-1} \frac{3}{2}$ to put the counter in the correct orientation at angle (90°-u) to the goniometer axis. Thus on each level, once I and u have been set, only Yand o, the angular positions of the counter and crystal respectively, are changed as P moves round the circle APO' by the usual method of linearly driving the slides O'Q and QP, and the counter moves round the cone of semiangle (90°-µ).

Once the reciprocal lattice of the crystal is correctly orientated with respect to the slide system, the normal measurement procedure for reflections is to track along successive reciprocal lattice rows on each level, keeping the stepping slide fixed on each row at the appropriate value of ha* or kb*, and moving in equal steps of b* or a* r.l.u. respectively along the other scanning slide. Once the counter arm reaches a preset limit switch on a



scan, the next intensity measurement is completed and the stepping slide moves one translation. Scanning continues as before and the process repeated automatically until the whole level is recorded in a zig zag fashion.

A stationary detector-moving crystal technique (Cochran, 1950) is used to measure the integrated intensity of each reflection.

Since the constant speed linear motion of the carriage along the slides produces a very non-uniform rotation of the crystal, an independent constant-speed mechanism (Arndt, Faulkner and Phillips, 1960) is used to oscillate the crystal about the goniometer axis through the region of the Bragg reflection. This enables the usual equi-inclination Weissenberg Lorentz factor to be used.

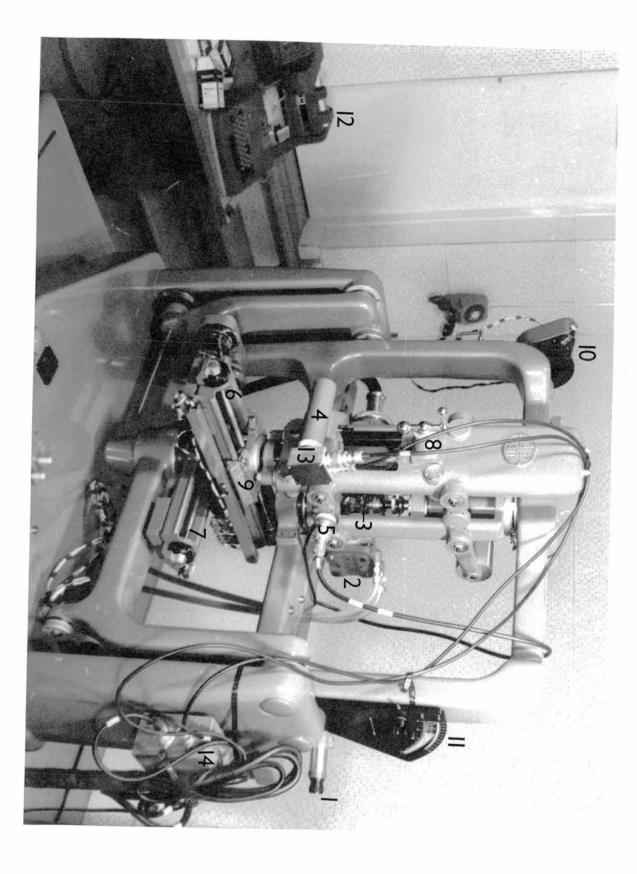
During each measuring cycle an initial stationary background count b is taken for time t on one side of the reflection, after which time 2t is spent counting the integrated peak N as the crystal oscillates. Finally a second background b' is measured for time t on the other side, and the crystal then returns to its ofiginal position. The background corrected intensity of the reflection is thus N-(b+b').

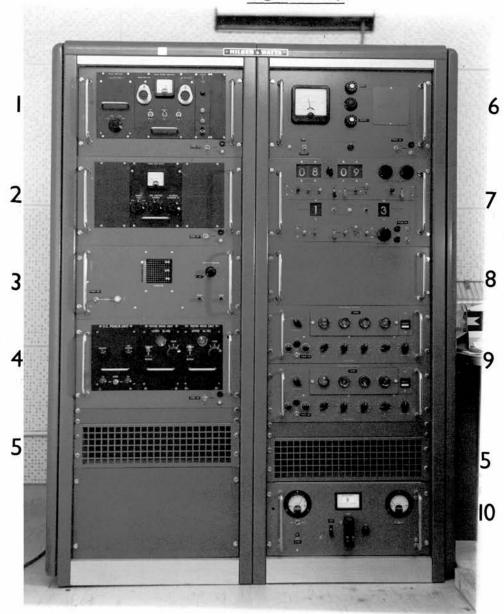
In practice the two oscillation cycles are done on each reflection using a balanced filters unit (Ross, 1928) which sequentially introduces a β filter for the first cycle and an α filter for the second, between the crystal and detector (Zirconium and Strontium respectively for Molybdenum radiation). The filters'

Figure 2.1.4

The linear diffractometer

- 1. Telescope for crystal alignment
- 2. X-ray tube
- 3. Goniometer head
- 4. Scintillation counter
- 5. Balanced filters unit
- 6. Horizontal slides
- 8. Vertical slide
- 9. Sliding carriage
- 10. Crystal oscillation mechanism and ϕ scale
- 11. µ scale for equi-inclination setting
- 12. IBM card punch
- 13. Head amplifier
- 14. Pre-amplifier





The electronic console

- Pulse amplifier, pulse height analyser, N/4 scaler 1.
- 2. Count rate meter
- 3. Racal programmed scaler
- 4. D.C. power and motor drive units
- Blower for cooling batch counters
- 5. 6. Scintillation counter E.H.T.
- 7. Control unit to programme data collection
- 8. Translator unit
- 9. Ericsson batch counters
- 10. Servomex voltage stabiliser

K absorption edges bracket the Kα line of the radiation used and thus the difference between the two background corrected integrated intensities gives the diffracted characteristic Kā radiation.

The sequence of setting, measuring, printing and resetting operations are controlled by sequencing circuits which employ electromechanical devices such as relays, uniselectors and batch counters, and figure 2.1.3 illustrates the measuring and control system. Since Molybdenum radiation was used for all data collection, a scintillation counter was used as detector. The x-ray tube is supplied with smoothed d.c. power which gives x-ray intensity constant to ½%. An I.B.M. card punch was used to output the results; the indices h,k,l of the reflection are punched on one card, together with b₁,N₁,b'₁,b₂,N₂,b'₂, the recorded counts of the two oscillation cycles.

Figures 2.1.4 and 2.1.5 show the diffractometer slide system and electronic console.

2.2 Trials and tribulations

The following instrument faults were encountered when initially attempting to use the linear diffractometer for collection of intensity data:

1. The crystal oscillation mechanism was found to be in error in that the angle of crystal oscillation was not constant for all reflections, and did not equal the angle set. This fault was corrected.

- 2. The goniometer shaft was not long enough for a crystal, mounted on a normal length of fibre, to be centred in the x-ray beam.
 A new extended shaft cannot be used without a goniometer extension because of flexing.
- 5. It was eventually discovered that a misplaced machined stop, for the angle between the horizontal slides, gave rise to serious instrument damage every time this angle was changed from 90° to 60°, which inevitably occurred with the triclinic crystals studied. The centre of the instrument was irreversibly moved and a lengthy repair was necessary.

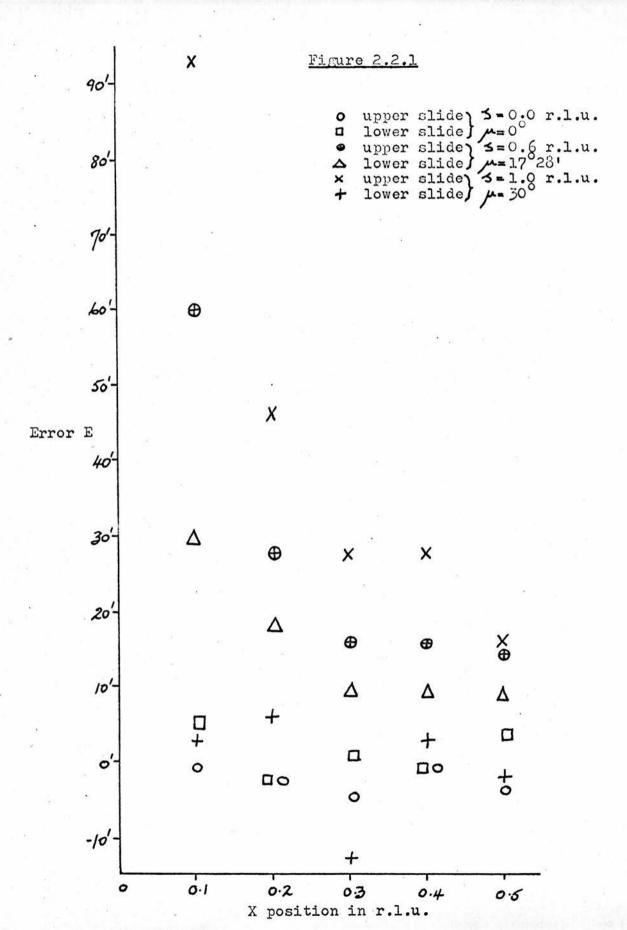
Before the cause of this damage was traced, it was thought that when certain combinations of slide settings and angle between the slides existed, a subsequent scan or step drive, in a direction towards the instrument centre, could cause sufficient strain to move the centre. A scale model of the horizontal slides and pantagraph system (c.f. figure 2.1.1) showed that this effect would be unlikely to cause the amount of movement required, other parts taking the majority of the stress and likely to break first.

4. The first intensity measurements made on the instrument were from a single crystal of mercury dibenzyl (MDB). The quality of zero level intensity data seemed good and a two dimensional Fourier map was satisfactory. The instrument was assumed to be operating equally well for upper levels but the resulting three

dimensional synthesis for MDB indicated that this was not so, and that upper level data was very unsatisfactory. This was confirmed by collecting data from α -glucose monohydrate (Ferrier, Killean and Young, 1962) and α -rhammose monohydrate (Beevers and McGeachin, 1957) and comparing the diffractometer intensities with previously obtained photographic values. The agreement for upper levels was poor in both cases and indeed for α -glucose monohydrate the parameters of the model previously obtained moved to impossible positions on attempted refinement. It was obvious that the same effect would have been obtained with the α -rhamnose monohydrate data.

Careful analysis showed that upper level reflection peaks were displaced from their expected reciprocal lattice positions, and that this movement worsened as the level increased. A simple and quick test of the accuracy of the instrument was devised.

When one horizontal slide is reading zero and the other slide, representing \underline{d}^* (see figure 2.1.1) is driven from +X to -X, then the angle of rotation of the crystal is 20 where $X = 2\sin\theta$. Theoretical and experimental values of 20 may be compared for $X = 0.1 \rightarrow 1$ r.l.u. at intervals of 0.1 r.l.u. for one slide and a similar test made on the other slide. The process was repeated on upper levels for $S=0\rightarrow 1$ r.l.u. at intervals of 0.1 r.l.u. The discrepancy E between the two values of 20 was plotted against X



in each case, and figure 2.2.1 shows the results for 3=0, 0.6 and 1 r.l.u.

It is seen that the inaccuracy in the crystal rotational position ϕ increases as the slide reading decreases, and also to a greater extent as 5 increases. The latter error was finally traced by experimenting to the equi-inclination angle μ scale. It was discovered that the 5 and μ scales on the instrument were not numerically linked, and when μ was set to -sin⁻¹ $\frac{3}{2}$, for a particular level of height 5, it did not in fact equal this equi-inclination angle.

The crystal setting angle ϕ is related to μ by the equation $\phi = 180^{\circ} - \tau - \cos^{-1}((\S^2 + 5^2 + 2)\sin\mu)/2 \cdot \cos\mu)$. \S and τ are the radial and angular coordinates of the reciprocal lattice point. Thus any inaccuracy in the equi-inclination setting μ causes an error in ϕ , and as \S increases so does this error.

Once the μ scale supporting vernier screws were remachined by the manufacturer, the instrument test described above gave a 10 error in crystal position ϕ for both slides on all levels for $\delta > 0.1$ r.l.u. To minimise the effect of this remaining inaccuracy, the detector arm CP (see figure 2.1.1) was kept to one side of the instrument throughout intensity data collection from one crystal.

Armdt and Phillips (1961), Armdt (1963) and Binns (1964)
have considered the setting precision of the linear diffractometer,
and also show the inaccuracy due to backlash of the horizontal
slides settings within 0.1 r.l.u. of their origin. Thus only

reflections with \$>0.2 r.l.u. were used for the crystal setting procedure outlined in the following section.

2.3 Crystal alignment on the linear diffractometer

The object of alignment is to set the crystal with two of its reciprocal lattice axes parallel to the two horizontal slides of the diffractometer. Depending on the crystal system the third reciprocal axis may or may not be parallel to the vertical slide. The best alignment procedure was found to be different for the two cases.

- A. a reciprocal lattice axis coincides with the real axis along the goniometer axis ϕ , as for MDB, mentioned already in section 2.2 and discussed in more detail in Chapter 5.
- B. the triclinic systems of SiF4,2Py and SiCl4,2Py (c.f. Chapters 3 and 4).

For both cases, the crystal is kept centred in the incident x-ray beam by means of the instrument telescope, and, when the peaks of reflections are studied, the crystal oscillation cycle is at the central position. A small collimator (1mm) is used.

A. Once the space group has been established by photographic methods, only approximate crystal setting and lattice parameter measurements need be made with cameras since these can be found more accurately on the diffractometer. For MDB <u>c</u> and <u>c*</u> are

coincident, and lie along the needle axis of the crystal. Using

the diffractometer telescope, it can be approximately set by eye

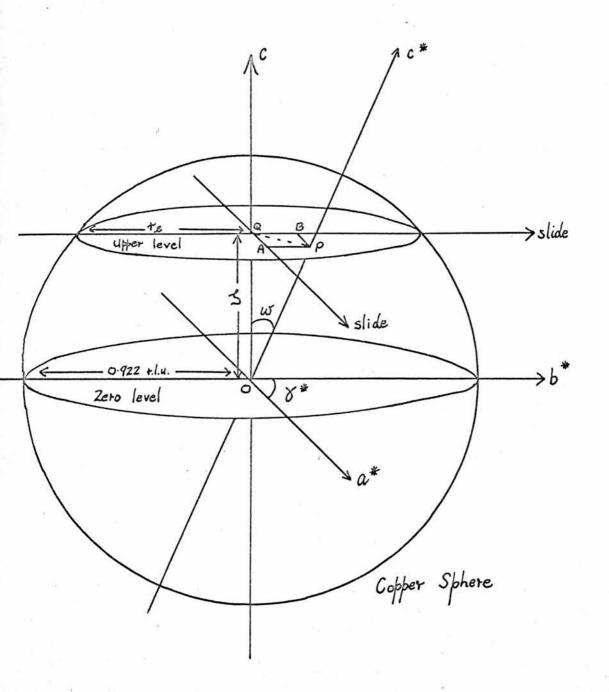
parallel to the vertical slide. A strong OOl reflection is located and the goniometer arcs are adjusted until 360° rotation of the crystal gives constant peak count indicated on the chart recorder. The c* parameter is improved by varying the vertical slide reading, and its associated μ , until maximum constant count is obtained. The c* value and goniometer arc settings are checked and confirmed on other OOl reflections. Now \underline{c} and \underline{c} * are parallel to, and reciprocal lattice planes perpendicular to the vertical slide and goniometer axis.

on the zero level with one slide at zero and the other (90° apart since γ*=90°) at the expected ha* position of a strong hoo reflection, the crystal is rotated until this reflection is found and then clamped on the φ scale at the peak position. The Friedel reflection hoo is also located by driving the slide to -ha*; and the parameter a* refined on both sides of the slide until both reflections are maximised and equal. A similar procedure is followed on the other slide to refine b* without unclamping the crystal, and the values checked against general zero and upper level reflections. Reflection peaks are now within 5-10' of the centre of the oscillation cycle for automatic collection of data. Corresponding Weissenberg photographs are a valuable aid for ease in finding suitable strong reflections.

B. For this category of crystal system a complete and accurate photographic study of the reciprocal lattice was found to be

essential prior to transferring the crystal to the diffractometer. This was achieved using Weissenberg and Precession cameras and the results are given in Chapters 3 and 4 for the two triclinic compounds studied. Since no reciprocal lattice axis coincides with a real axis, the goniometer arcs cannot be set by method A and the crystal is set with a real axis, say c, along the goniometer axis on a Weissenberg camera by the methods of Weisz and Cole (1948) and Davies (1950). Once correct setting was assured, the "sira" wax holding the crystal fibre or tube to the goniometer head was generously coated with shellac to prevent any crystal motion in the event of the wax becoming soft. After transfer to the diffractometer any desired reflection may be located, knowing the orientation of the three oblique reciprocal axes with respect to the goniometer head.

The angle between the horizontal slides is set at γ* and the crystal clamped by eye so that the slides are approximately in the orientation of a* and b*. With the slides reading ha* and kb* r.l.u. for a strong hkO reflection, the crystal is slightly rotated and clamped at the peak position, which for both triclinic crystals, was within 2° of the initial visual setting. Since c* is not perpendicular to the a*b* plane, the plane of the horizontal slides, the effective origin of upper levels is not coincident with the slides both reading zero, and the offsets of upper level origins along both slides must be found. With SiF_h, 2Py



and SiCl₄,2Py strong reflections on several upper levels were maximised by successively varying the slide readings, and the mean offset values used. This assumes that a* and b* values are sufficiently accurate so that their errors do not contribute to the offsets. In both cases the experimentally determined offsets were found to be insignificantly different from the values calculated as follows.

In figure 2.3.1, P represents the intersection of c* with an upper 1-level, Q is the origin of the horizontal slides parallel to a* and b* and QA and QB are the displacements of P along the slides.

$$QA = \delta_{a^*} = \frac{QP \sin QPA}{\sin QAP}$$
 (Sine Rule in ΔQAP)

QP = OPsin ω = 1(λ c*)sin ω ; QAP = 180°- γ * and it can be shown that \cos QPA = $\frac{\cos\alpha*}{\sin\omega}$ where ω =angle between $\frac{c}{c}$ and $\frac{c}{c}$ * = $\cos^{-1}(1/cc*)$.

Substituting into the above equation gives for the offset of P along the a* slide,

$$\delta_{a*} = (1(\lambda c*)/\sin\gamma*) \sqrt{\sin^2\alpha* - \cos^2\omega}$$
 and similarly,
$$\delta_{b*} = (1(\lambda c*)/\sin\gamma*) \sqrt{\sin^2\beta* - \cos^2\omega}$$

With both triclinic crystals refinement of the goniometer arcs setting and lattice parameters was attempted on the diffractometer but no significant improvement could be made on the photographic values due to the number of possible variables

which were difficult to isolate. There are five variables for zero level reflections: the two goniometer arcs, the horizontal slides and γ^* , plus a further three for upper level reflections: the vertical slide setting $1\lambda/c$ and the two offsets. Strong reflections were chosen and by varying in turn the goniometer arcs and slide settings, it was attempted to maximise the peak count.

The remaining setting problem for crystals of type B is to clamp the crystal in the best mean position for all reflections. The method adopted consisted of choosing four strong zero level reflections approximately 90° apart, and initially clamping the crystal at the peak position of one of them. The slides were driven to the other three reflections in turn and the position of arrival on the oscillation scale of and the peak position noted in each case. It was then possible to clamp the crystal to a mean position such that the errors in peak missetting from the point of arrival on automatic scan were minimised and evenly distributed throughout the level. For both triclinic compounds the crystals used for data collection were set to within 10-15' for zero level reflections, using photographic values. The setting was checked on upper levels and again found to be the optimum, although the peak missetting did tend to increase slightly due to additional inaccuracies from the equi-inclination setting and offset values.

2.4 Setting the diffractometer for data collection.

Before data collection can commence the following variables must be selected:

2.4.1 Detector collimator and crystal oscillation angle.

A complete account of collimating and oscillation angle conditions which must be fulfilled to ensure proper measurement of integrated intensities is given by Furnas (1957).

The aim is to have maximum peak to background ratio (this decreases in proportion to the unnecessary background included in the integrated peak count) and backgrounds approximately equal. If the oscillation angle is too small then the background count on one side of the reflection may include part of the peak.

For each crystal studied, several reflections of varying intensities on various levels were selected to test combinations of collimator sizes and oscillation angles. The final values were chosen such that the above criteria were satisfied together with Friedel equivalent intensities being equal to within two or three standard deviations.

For upper level reflections, the crystal is not rotated about an axis perpendicular to the plane of reflection and the effective angular range of the reflections increases (Cox and Shaw, 1930; Tunnell, 1939). A further reason is the vertical divergence of the x-ray beam (Phillips, 1954) especially for reflections near the origin of the horizontal slides. Consequently the oscillation

angles for SiF4,2Py and SiCl4,2Py found most suitable for most of reciprocal space as described above, were too small for the highest levels and had to be increased.

2.4.2 Time spent at each reflection

There is a statistical uncertainty in the measurement of diffracted intensities because of the random nature of emission of x-ray photons. This can be reduced by prolonging the counting process at each reflection for some length of time, but against this must be weighed the amount of time available for data collection.

The total time spent counting may be altered in two ways. The time taken per oscillation cycle may be chosen as $\frac{1}{2}$ or 1 minute (2 motors available) and the number of oscillation cycles measured at each reflection selected.

It was found that the differences between integrated intensities obtained after counting for many oscillation cycles per reflection and those values after only two cycles, were less than the standard deviations \sqrt{N} of the counts themselves. Thus there seemed little justification for spending any more time measuring each intensity than was necessary for two cycles using balanced filters i.e. 1 card per reflection.

Likewise, with time at a premium, the criterion used for choice of oscillation motor speed was the magnitude of the

diffracted intensities from each particular crystal. The largest peaks should give sufficiently high counts without overloading the scintillation counter.

2.4.3 Electronics

The scintillation counter E.H.T. is selected by maximising the peak count of a typical reflection with the pulse height analyser in the middle of its working range. A subsequent pulse height distribution curve gives the optimum low level and window width settings for the P.H.A. The x-ray generator voltage is set at least twice the excitation voltage of the target material, and the current chosen so that the counts obtained are within the desired range.

2.4.4 Collection of data

The maximum attainable Bragg angle θ on the linear diffractometer is 30° and thus only those reflections within a hemisphere of reciprocal space, of radius $2\sin\theta=1$ r.l.u.can be measured. However, although Mo radiation produced all diffracted intensities, the wavelength of copper K α characteristic radiation is used for calculating the structure factors (see programme 3, appendix A).

For radiation of wavelength λ diffracted at the Bragg angle θ , $\sin\theta/\lambda$ is a constant for that particular reflection. When calculating structure factors with $CuK\bar{\alpha}$ wavelength, maximum $\sin\theta$ required is unity and the corresponding $\sin\theta$ value for $MoK\bar{\alpha}$ wavelength is $\lambda(MoK\bar{\alpha}) \times 1/\lambda(CuK\bar{\alpha})$. Thus only those reflections

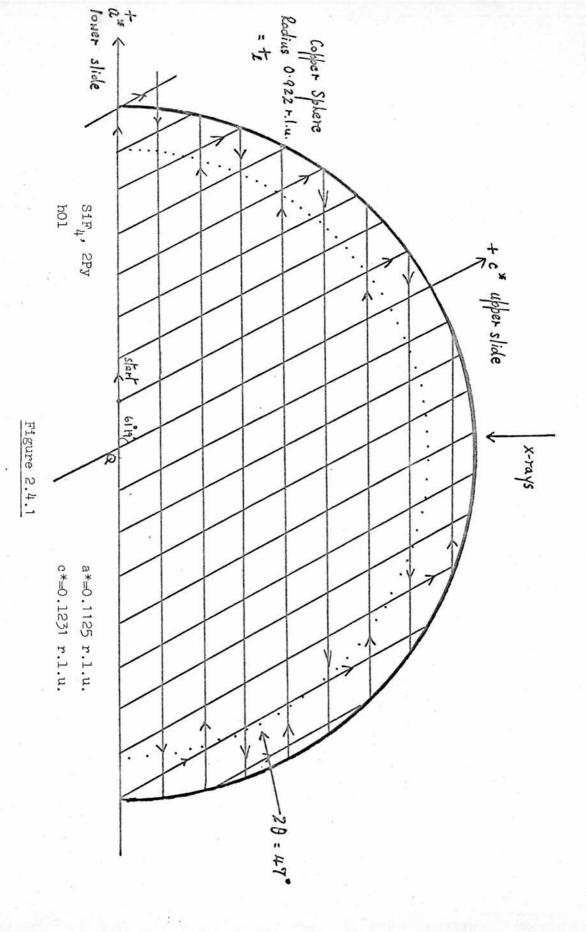
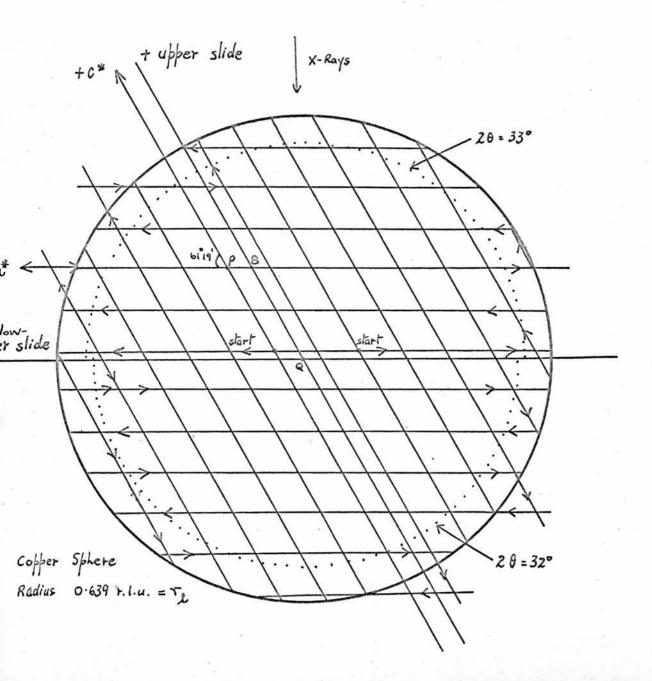


Figure 2.4.2

SiF_{l_i},2Py h6l 3-0.6642 r.l.u. $m=19^{\circ}24^{\circ}$ offset of P along lower slide = PB = 0.0726 r.l.u. offset of P along upper slide = QB = 0.2742 r.l.u.



inside the "copper sphere" of radius 2 x $\lambda(\text{MoK}\bar{\alpha})/\lambda(\text{CuK}\bar{\alpha}) = 0.9219 \text{ r.l.u.}$ need be measured.

The radii r_1 , of the circles of intersection of the copper sphere with each reciprocal lattice level of a crystal mounted on the diffractometer, may be calculated from the formula: $r_1 = \sqrt{(0.9219)^2 - 5^2} \text{ r.l.u. (see figure 2.3.1)}.$

For the triclinic lattices of SiF_{μ} , 2Py and $SiCl_{\mu}$, 2Py, every reciprocal level mesh was drawn on polar graph paper and the zero level only for M.D.B. since all levels are the same. The intersection of the goniometer axis with each level is at the centre Q, also the origin of the diffractometer horizontal slides. Examples of these are shown in figures 2.4.1 and 2.4.2, which are respectively the zero and sixth levels of SiF_{μ} , 2Py (mounted along b). The values of slide intervals, offsets etc. are taken from chapter 3, section 4.

The appropriate circle of radius r_1 is drawn on each diagram and the setting of the \(\) limit switch (maximum 60°) chosen such that minimum time is spent measuring reflections outside the copper sphere. Reflections in both halves of each level, except the zero layer, were collected for the triclinic crystals in a zig-zag scan-step manner as shown and in a direction away from the origin of the slides \(\mathbb{Q} \). The layer plots are a further help in identifying those reflections in the inaccurate region of the instrument within 0.1 r.l.u. of \(\mathbb{Q} \), and those likely to cause

mechanical damage if driven to automatically.

As many reflections as possible are collected on automatic scan, and those near the origin of the horizontal slides are examined. If their backgrounds are very uneven they are centred and collected individually (cf. section 2.2).

Some chosen standard reflection is returned to after each level collected to check that the crystal has retained its correct alignment and has not deteriorated in the incident beam. This also provides a check on the stability of x-rays, detector and counting circuits.

2.5 Photographic method of recording integrated intensities

An integrating Nonius Weissenberg camera (Wiebenga, 1947; Wiebenga and Smits, 1950) was used to record the diffracted intensities of SiF_h , 2Py.

For each equi-inclination Weissenberg level the following values must be set:

- a) equi-inclination angle $\mu=\sin^{-1}(5/2)=\sin^{-1}[\sin \tan^{-1}(2y/D_F)]/2$ 5= height of level in r.l.u. obtainable from a rotation photograph.
 - y = rotation film layer line height in mm.
 - $D_{\rm p}$ = diameter of film cassette = 57.29mm.
- b) shift of layer line screens from the zero level position

 = S.tanµ where S = effective radius of the layer line screens

 (mean of internal and external values) = 24.25mm. The

 ngrrowest possible screen gap of 3mm was used, to reduce

the background.

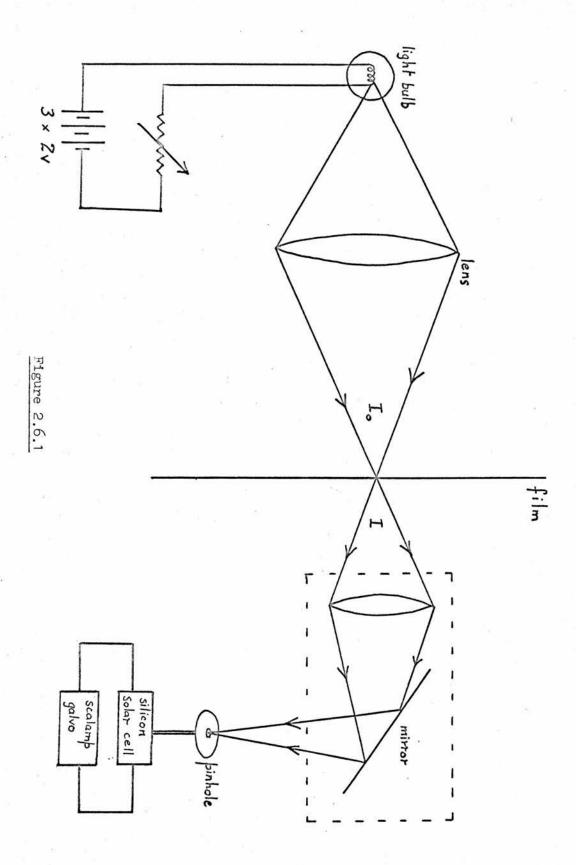
The integrating mechanism on the camera performs two movements at the end of every usual Weissenberg film translation by means of turning through 1 notch a pinwheel with 14 notches.

- a small horizontal translation parallel to the goniometer axis.
- 2. a small vertical rotation about the goniometer axis.

After one complete rotation of the notched pinwheel the film has traversed 14 times, 14 small displacements have been made in both directions and the rotational position of the film cassette returns to its original position. The horizontal displacement may be continued up to 30 times more, when the cassette begins to translate in the opposite direction for a further 14x30 small translations until back at its original position.

For one rotation of the pinwheel, the rotational displacement = total vertical displacement b, and the translation movement = one horizontal step a, and up to 30 or multiples of 30 translation steps may be taken per exposure.

The total displacements must exceed the dimensions of the spots to be measured, the size of the excess determining the size of the integrated intensity plateau. Thus initial trial integration settings were chosen by measuring the average spot size, x and y m.m. horizontally and vertically respectively, and choosing total film displacements of 0.3 m.m. in excess of those



values, giving plateau sizes of approximately $(0.3)^2$ mm². The total vertical displacement b=(y+0.3)mm and the translation step a=(x+0.3)/n mm are set on two scales on the camera. n=number of translation steps in one direction made during the exposure (maximum of 30). These settings must be chosen such that a large plateau region is obtained consistent with no spot splitting, which occurs if the integration steps are too large. This was especially critical for the crystal of SiF₄,2Py since there were powdery fragments surrounding it in the tube.

2.6 Measurement of photographic integrated intensities

For a reflection recorded on film as described in 2.5 the integrated intensity I(h) of x-rays striking the film is the effective intensity of the reflection in the plateau region.

This is linearly proportional to the effective film blackening or optical density D of the plateau and is measured with a Nonius microdensitometer, represented schematically by figure 2.6.1.

The density D at any point is defined by $\log_{10}(I_0/I_1)$, where I_0 is the intensity of light incident on the film, and I_1 is the transmitted intensity received by a solar cell and causing a deflection on the galvanometer.

The effective optical density D of the plateau

- = density of plateau density of background
- = $\log_{10}(I_0/I_p) \log_{10}(I_0/I_p)$
- $= \log_{10}(I_{\rm p}/I_{\rm p})$
- $= \log_{10}(B/P)$

 I_B and I_P are the light intensities transmitted by the background and plateau regions respectively of the film and are linearly proportional to the deflections B and P on the galvanometer. Thus, for any reflection, the integrated intensity $I(\underline{h})$ is proportional to $log_{10}(B/P)$, and for constant I_O for one film, a set of relative intensities recorded on the film is obtained.

At density values beyond a certain value, the relationship with x-ray intensity ceases to be linear, smaller increments of blackening occurring with larger exposure, and thus for all films, only those spots with B/P ratio of less than 12, corresponding to a maximum density of 1.079, were measured on the densitometer. By comparing sets of Friedel equivalent reflections, very light reflections with B/P < 1.1 were found to have such a high measurement inaccuracy as warranted their exclusion too. Thus the range of integrated intensities on one film measurable on the microdensitometer is $0.041 \rightarrow 1.079$.

The film to be measured is inserted in a holder which can be moved by hand vertically or horizontally. A dummy film, indexed by scratching the Weissenberg festoons on it, is fixed above and once aligned with the integrated film, a pointer indicates on the dummy the spot being measured below.

The light intensity I illuminating the film was chosen for each film by varying the rheostat such that on the lightest portion of the film the galvanometer deflection was a maximum but not

off scale.

With a focussed light spot and the smallest available detector pinhole (0.8m.m.) the graining of the films caused such oscillatory galvanometer deflections that the sensitivity of the system had to be reduced. Testing was done on several films to find the conditions for best peak resolution without excessive oscillations, and also for best agreement between Friedel equivalent reflections. A 1m.m. pinhole was eventually used and the light beam unfocussed by moving the light bulb further away from the film (this assumes a one to one correspondence between the light passing through the film and the pinhole).

The peak plateau region of each reflection was located by slowly moving the film until minimum galvanometer deflection P was recorded. The film was then moved vertically to either side to obtain background galvanometer readings B₁ and B₂ with mean B. White radiation streaks if present are therefore included in the background.

THE CRYSTAL AND MOLECULAR STRUCTURE OF TETRAFLUOROBISPYRIDINESILICON (IV)

3.1 Introduction

Long wavelength infrared spectroscopy is now widely used to investigate the structure of coordination compounds, and it is important that in some selected cases other physical techniques should be used to confirm the spectroscopic conclusions. No adducts of silicon tetrahalides, of the type Si(Halogen), (Ligand), have been examined in detail by single crystal x-ray techniques although the infrared spectra have been reported and interpreted usually in terms of six coordinate cis or trans geometrical isomers. The infrared spectrum of SiF₄,2(NC₅H₅) has been interpreted in terms of a trans octahedral stereochemistry (Beattie and Webster, 1965; Campbell - Ferguson and Ebsworth, 1967) on the basis of one i.r. absorption line in the Si-F stretching region.

3.2 Description of crystals

The crystals were supplied by Dr. M. Webster and had been prepared by heating the solid compound SiF₄,2Py with excess pyridine in sealed tubes and allowing the tubes to cool slowly. Using a dry-box the better crystals were transferred to lithium borate glass capillary tubes and well sealed as these crystals must be kept moisture free.

Preliminary small oscillation x-ray photographs were taken to determine which of the incapsulated crystals were suitable for single crystal x-ray diffraction study. This was difficult to decide on the basis of a microscope examination only, as generally they were of poor quality, being fairly large and fragmented.

Only one single crystal was found in the first sample and it was used to determine the space group and unit cell dimensions before it was unfortunately knocked off the goniometer. A second sample of crystals again produced only one suitable crystal,

1.3mm long and 0.6mm x 0.5mm cross-section and this was used for the structure determination, both by photographic and diffractometer methods. This second crystal was lying in the Lindemann tube in approximately the same orientation as the initial crystal.

3.3 Unit cell dimensions

Rotation and equi-inclination Weissenberg photographs were taken using a Unicam camera for initial approximate measurements of the cell parameters, and indicated that no cell angles were equal to 90°. Since it was impossible to remount the crystal in its tube in a different orientation on the goniometer head, it was transferred to a Buerger precession camera on which all necessary photographs for a complete study of reciprocal space could be taken, and with greater accuracy than on the Unicam camera.

Using copper radiation, a prominent reciprocal axis a* was aligned parallel to the goniometer axis by the method of Fisher (1952 and 1953)

and an A-faced reciprocal cell with all sides and angles unequal was located. From it a suitable triclinic primitive (P) cell was found (a*p along the dial axis) and its lattice parameters were determined. Since not all real angles were ≥90°, a Delaunay reduction was performed (Delaunay, 1933) to find the reduced (R) primitive cell.

The vector transformations obtained were:

$$\underline{\mathbf{a}}_{R} = -\underline{\mathbf{b}}_{P} - \underline{\mathbf{c}}_{P} ; \qquad \underline{\mathbf{b}}_{R} = \underline{\mathbf{a}}_{P} ; \qquad \underline{\mathbf{c}}_{R} = \underline{\mathbf{c}}_{P}$$

$$\underline{\mathbf{a}}_{R}^{*} = -\underline{\mathbf{b}}_{P}^{*} ; \qquad \underline{\mathbf{b}}_{R}^{*} = \underline{\mathbf{a}}_{P}^{*} ; \qquad \underline{\mathbf{c}}_{R}^{*} = \underline{\mathbf{c}}_{P}^{*} - \underline{\mathbf{b}}_{P}^{*}$$

It was therefore possible by making appropriate changes to the goniometer arcs and dial readings on the camera, to locate the reduced triclinic cell itself (b* along the goniometer axis) and measure its lattice parameters directly.

The following factors were considered in obtaining accurate reduced cell parameters:

- (i) The crystal setting with b* along the dial axis was checked for the four dial positions with hkO and Okl parallel to the film cassette.
- (ii) The horizontal and vertical separations of pinhole marks were measured on undeveloped and normally developed film. Negligible difference was found and thus no correction was made for film shrinkage.
- (iii) The crystal to film distance F, on the Buerger precession camera, was calibrated as described in Appendix B and gave F=59.74mm.

The final reduced triclinic cell parameters are:

$$a = 7.234$$
 $b = 6.420$ $c = 6.987$ (± 0.008) $\alpha = 109^{\circ}43'$ $\beta = 114^{\circ}35'$ $\gamma = 95^{\circ}42'(\pm 10')$

Volume $V = 266.71 \pm 0.06 \text{Å}^3$

Measured density = 1.16 + 0.04gm/cc

Calculated density with 1 molecule per unit cell = 1.63gm/cc

The space group is Pl or Pl if the molecule has a centre of symmetry.

Linear absorption coefficient μ for MoK $\bar{\alpha}$ = 2.6cm⁻¹

For collection of intensity data, the crystal was realigned with the <u>b</u> axis of the reduced cell along the goniometer axis, and reflections on equi-inclination Weissenberg photographs were indexed with respect to the reduced cell. This is especially tricky for a triclinic cell since the direction of displacement of upper level reflections relative to the zero level is important, and if this shift is small, careful study must be made to ensure that the axes are correctly orientated consistent with maintaining a right handed set and all reciprocal angles acute.

The results from a study of the compound SiF₄,2Py using the linear diffractometer for measurement of diffracted intensities are given in section A (3.4-3.7), and the photographic results in section B (3.8-3.11).

Photographic work was well under way by the time diffractometer data were collected, but due to the much longer time taken for photographic measurements, the linear data were used for the Patterson and initial Fourier syntheses from which the structure was essentially solved. Comparisons between the two final structural models, obtained after refinement using both sets of data, are given at the end of the chapter in section 3.12.

Section A Linear Diffractometer Data

3.4 Measurement of intensities

The same crystal used for the photographic recording of integrated intensities was afterwards transferred to the linear diffractometer, once it was operating satisfactorily, and set up for data collection as described in Chapter 2 (2.3 and 2.4).

The following values were selected:

1.5mm detector collimator 2°45' oscillation angle

2 oscillation cycles 1 minute oscillation motor

P.H.A. : low level = 20 volts, window width = 40 volts.

Generator: 40kV 16mA

Scanning (lower) slide interval = a* = 0.1125 r.l.u.

Stepping (upper) slide interval = c* = 0.1231 r.l.u.

Angle between slides = β * = 61°19'

Spacing on vertical slide between equi-inclination k levels = $\lambda/b = 0.1107 \text{ r.l.u.}$

As discussed in section 2.3, the displacements of upper level origins relative to the horizontal slides were found experimentally, and the values used for collection of data from the kth level were:

Offset along the upper c* slide = 0.0457 x k r.l.u.

Offset along the lower a* slide = +0.0121 x k r.l.u.

These experimental values compare favourably with those calculated later as described in 2.3, and equal to 0.0452 and 0.0127 r.l.u.

respectively. Missetting of a reflection by 0.0006 r.l.u. is not significant since an integrated count is taken.

Intensity data were collected by the method described in section 2.4.4 from levels k=0→7 using Mo radiation (see figures 2.4.1 and 2.4.2 of the zero and sixth levels.) At the 5th level it was noticed that the background counts on either side of the peaks had become very unequal, even for reflections >0.1 r.l.u. from the slides origin. It was discovered that, when the crystal oscillation mechanism was in its "CENTRE" position, it was 10' away from the true centre of the oscillation range. This instrument error was subsequently corrected for future data collection but no doubt contributed to the unequal backgrounds found with this crystal. Intensity profiles of reflections on the highest levels were very uneven due to the quality of the crystal and very elongated. Consequently, according to the discussion in section 2.4.1, the oscillation angle was increased, for the remainder of data collection from h51-h71, to a maximum of 5°35'. This was sufficiently large to encompass the error in peak missetting, which for h51-h71 was as much as 30' for some reflections for the reasons given in 2.3. Using some reflections on h51-h71 for testing, the net integrated intensity on automatic scan with this increased oscillation angle was always within two standard deviations of the value obtained when the peak was centred by hand. Background counts were now approximately equal again, and to compensate for the subsequent decrease in total count,

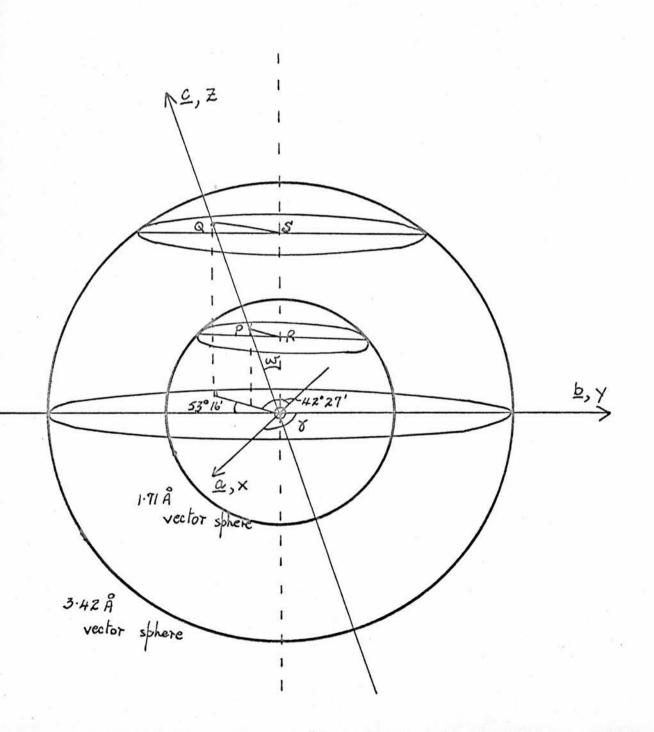
the generator current was increased to 20mA.

Scaling between the two sets of intensity data collected under different conditions was accomplished using those ten largest h51 reflections common to both and with \$ > 0.2 r.l.u.

3.5 Data processing and Patterson and Fourier syntheses.

The data cards from the linear diffractometer were processed using programmes 1 and 2 as described in Appendix A to give a set of $|F_0|^2$ and $|F_0|$ values. The multiplying factor for the h51-h71 intensity estimates to put them on the same scale as the h01-h41 data was 1.427, applied in programme 2 as part of the scale factor. The "R" factor for the h51 reflections used for scaling = $\sum |\Delta(\underline{h})| \sum I(\underline{h}) = 0.048$ where $I(\underline{h}) = 1.427$ x (intensity with maximum oscillation angle and $\Delta(\underline{h}) = I(\underline{h}) - 1.427$ x (intensity with maximum oscillation angle). Hence the scaling process will cause only a 2.4% error in $|F_0|$ values. No correction for absorption was made since the effect is small with Mo radiation, and considering the irregular shape of the crystal and its enclosure in a tube, difficult to evaluate significantly.

A Patterson synthesis was calculated with programme A4 using $1285|F_0|^2$ values. 31 sections were computed for z/c = 0-1, and on each section $x/a = 0-\frac{1}{2}$ and y/b = 0-1, all at intervals of 1/30. Since the Si-F bond length in $[SiF_6]^2$ — ion is 1.71Å, this is probably the order of magnitude of the bond in the SiF_4 ,2Py molecule, and thus a vector sphere of radius 1.71Å, centred at the origin of the Patterson vector set, was considered. To confirm the existence of possible peaks on



the sphere's surface due to Si-F vectors, vectors of length 3.42Å were also located.

In figure 3.5.1, 0 is the origin of vector space and centre of both spheres. The decreasing radii of the circles of intersection of the spheres with the computed Z sections are calculated from simple geometry. The direction of displacement of the intersections P and Q of the Z axis with successive sections makes angles 42°27' and 53°16' with the -X and -Y axes respectively when projected on to the XY plane as shown. PR=OP since = Zsinces -1(1/cc*). Thus for each Z section whose origin is P or Q, the position of R or S, the centre of the appropriate circle, may be found.

The computed values of P(u,v,w) at mesh points near the vector spheres were plotted on polar graph paper, and remembering that the Patterson function is centrosymmetric and utilising all equivalent parts of the vector set, pictures of both hemispheres for vectors ~1.7 and 3.4Å were obtained.

Three regions with high P(u,v,w) values were located on the smaller hemisphere and the coordinates of their peak positions determined. The lengths of these interatomic vectors and the angles between them were calculated to be 1.95, 1.49, 1.52Å and 88.5°, 93.4°, 90.5°, which is quite satisfactory.

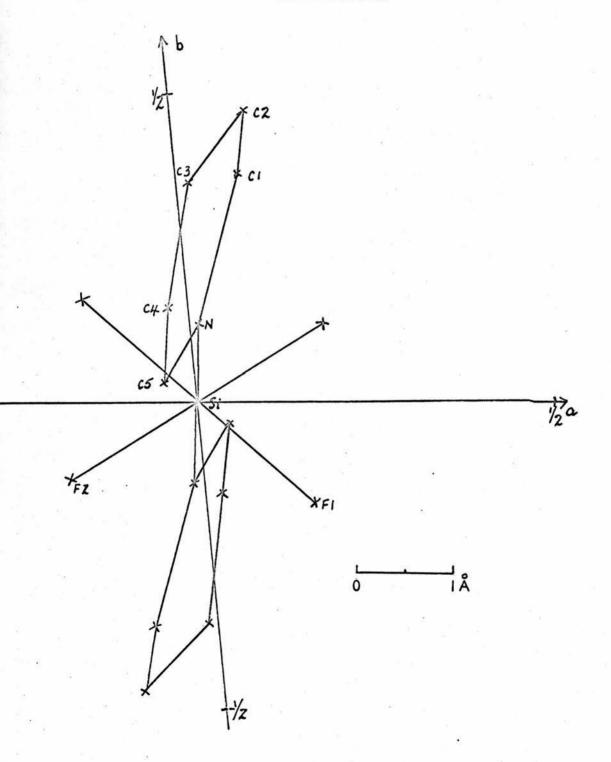
Corresponding peaks in the same orientation appeared on the larger hemisphere confirming that the above three vectors, together

with those related by the centre of symmetry, are the four Si-F and two Si-N bonds in the molecule. No attempt was made to distinguish between them because of the approximate equality of the sizes of the F and N atoms (Z=9 and 7 respectively).

The triclinic vector set is difficult to interpret and it was decided not to look further for interatomic vectors involving the carbon atoms but to feed the $|F_0|$ values obtained already and the coordinates found above into a structure factor calculation, according to equation (3), section 1.1, using programme A3.

The silicon atom was placed at the origin of the unit cell, which for space group P1 may be chosen anywhere. The six vector peaks therefore give directly the atomic coordinates of 4 fluorine and 2 nitrogen atoms and were allocated according to a cis-configuration in order to bias away from the expected trans-configuration of the molecule (see section 3.1).

The first calculation of structure factors F_c was performed with no refinement to obtain a correct scale factor $\Sigma |F_c|/\Sigma |F_o|$ to be applied to the $|F_o|$ values in the second cycle, again with no refinement on the atomic parameters. According to the theory given in section 1.1 the calculated phases assigned to the $|F_o|$'s will not be exactly correct since no carbon atoms have been included. However the Si,4F and 2N atoms ($\Sigma Z^2 = 618 \times \Sigma f^2$) form the majority of the scattering power of the molecule (ΣZ^2 for the remaining 10 carbon and 10 hydrogen atoms= 370) and later inclusion of the other atoms will not greatly alter



the phases of reflections with large $|F_0|$ and F_c values. 138 such reflections from the second cycle output of programme A3 were used to compute a Fourier synthesis throughout the unit cell using programme A4 and as described in section 1.1 (equation (2)).

Seventeen regions of high electron density were found in the three dimensional Fourier map corresponding to all the atoms except hydrogens in the SiF₄,2Py molecule. The coordinates of the centres of the peaks are shown in figure 3.5.4 projected on to the ab plane (the displacement of increasing Z section origins was calculated earlier-see figure 3.5.1). The molecule has a trans configuration and the pyridine ring geometry is sensible.

3.6 Structure refinement

A structure factor calculation, computed using the seventeen atomic positions gave an R value (see section 1.4) of 0.27 (once the scale factor for the |F| values had been determined as before). Assuming space group P1, a few cycles of least squares refinement of the scale factor, atomic coordinates and isotropic temperature factors (see section 1.4) reduced this to a minimum of 0.214. For all reflections, the real part A of F was very much greater than B (see section 1.1) and the departure of the structure from Pī was less than the standard deviations of the atomic coordinates.

Refinement was thus continued with space group Pī, the Si atom being placed at the centre of symmetry (0,0,0). The Si formfactor values were halved (see Appendix A5) and the positions of only 2 fluorine,

Table 3.6.1

<u>k-level</u>	1st Scale factor S	2nd Scale factor S2
0	0.958	0.9821
1	0.951	0.9991
2	0.979	0.9908
3	0.941	0.9882
4	1.021	0.9324
5	0.937	0.9691
6	0.958	0.9142
7	0.891	0.9494

1 nitrogen and 5 carbon atoms given in the directives for programme A3 since the asymmetric unit of the unit cell contains only half the molecule. Further refinement reduced R to 0.20 when the latest isotropic B values, given below, were converted to anisotropic B_{ij}'s by programme A3. R fell instantly to 0.168.

ATOM Si F1 F2 N C1 C2 C3 C4 C5

B 2.657 3.915 3.786 2.726 3.171 3.808 4.297 3.948 3.373

During subsequent cycles, the following operations were executed:

- (i) Because of inaccuracies in instrument and crystal setting, a separate scale factor $S_1 = \sum_{c} |F_c| / \sum_{c} |F_c|$ was found for each k level of intensity data collected, using the largest values and programme A6. They are given in table 3.6.1 and were applied to the $|F_c|$ values.
- (ii) The positions of the five hydrogen atoms in the pyridine ring were calculated as described in Appendix C using the latest coordinates of the other atoms. At this stage R=0.149 and the parameter shifts were reduced to the 4th decimal place. The H atomic coordinates are given in the final table of coordinates 3.7.1. It was not felt necessary to recalculate them since subsequent molecular geometry was sufficiently good (see section 3.7). Each H atom was given the last isotropic B value of its corresponding carbon atom (see above), since the thermal motion will be similar, and no least squares refinement was attempted on the hydrogen parameters.

(iii) Reflections outside the copper sphere (section 2.4.4) were removed and also those with net intensity estimate I less than 20 counts, since they have large counting statistics errors.

(iv) k level scale factors S_2 were calculated for the second time using all the latest $|F_c|$ and $|F_c|$ values for each level and are listed in table 3.6.1.

Successive cycles of least squares refinement on the 79 parameters were performed with the remaining 959 intensities until minimum $\sum_{W} \Delta^2 \text{ was reached and R=0.0887.} \quad \text{A card output of this best cycle to date was taken.}$

So far the weighting scheme given by equation (11), section 1.5 had been used (F_{min}=0.44) but now the more realistic scheme (equation (12), section 1.5) for diffractometer data was applied by means of programmes 7-11 (see Appendix A).

The scale factor K/4 applied to each level of data during the processing of (I+B)/(I-B) (from A7) must be carefully evaluated so that K is the correct factor to put the (I+B)/(I-B) values on to the same absolute scale as the latest values of $|F_0|^2$ and $|F_0|^2$. For SiF₄,2Py, therefore, K is the product of four terms: (the original scale factor for processing each k level of diffractometer intensities) x (level scale S₁)² x (level scale S₂)² (see table 3.6.1) x (latest structure factor scale in A3)².

Substituting the results of three summations by A8 and A9 into equation (13), section 1.5, gave c^2 =0.010836, c=0.1041,

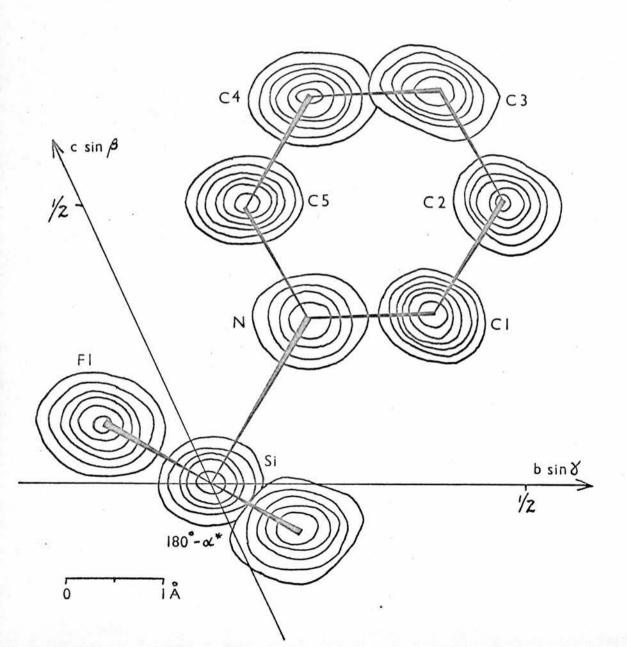
Figure 3.6.1

A composite map of electron density in SiF_4 , 2Py viewed along <u>a</u> (from sections nearest centres of peaks).

C1-C5: first contour at $2e/\mathring{A}^3$, then at $1e/\mathring{A}^3$ intervals.

N,F1,F2: first contour at $2e/\mathring{A}^3$, then at $2e/\mathring{A}^3$ intervals.

Si: first contour at 5e/Å3, then at 5e/Å3 intervals.



G(counting statistics) = 0.0329 and G=0.1092. These values indicate that, as expected, the error in intensity measurement by the linear diffractometer due to counting statistics is much smaller than other errors, and hence the decision to record only two oscillation cycles at each reflection is justified (see section 2.4.2).

The factor D = $0.99/\sqrt{w_{max}}$, which is used to obtain a scaled set of \sqrt{w} values in the correct format for use in programme A3, was 0.1371. The resulting output from A11 becomes the new input for further cycles of SFLS calculations. The first cycle with this weighting scheme gave a significantly smaller $\sum_{w} \Delta^{2}$.

After three more cycles, a card output was taken and programme A12 used to find those reflections with a difference Δ between the observed and calculated structure amplitudes greater than 3 or 4 standard deviations $\mathfrak{c}(=1/\sqrt{m})$. As many as 34 reflections had $\Delta > 3 \, \mathrm{c}$ (on an absolute scale), probably because of the crystal quality, its surrounding tube and the inexact setting of the triclinic crystal on the diffractometer. 17 reflections with $\Delta > 4 \, \mathrm{c}$ were probably subject to non-random errors in intensity measurement and were given zero weight. Four of these reflections were in the inaccurate region of the instrument, near the origin of the horizontal slides (see section 2.2), and another reflection (5,0,2) proved to be a Renninger reflection, discussed in section 3.10. No obvious cause of the large inaccuracy in the other 12 intensities could be detected.

Structure refinement continued until, after five further cycles, $\sum_{W} \Delta^2$ was minimised and R=0.0758. $\sum_{W} \Delta^2$ computed by A3 is on the basis of the scaled \sqrt{W} values, and hence absolute $\sum_{W} \Delta^2 = (\text{scaled} \sum_{W} \Delta^2)/D^2$. Account must also be taken of any change in the SFLS scale factor between the calculation of absolute \sqrt{W} values and this final cycle.

The final F_o and F_c values, $(F_o)_L$ and $(F_c)_L$, are listed in table A at the end of the thesis. $\sum_{l}^{m} w \Delta^2 = 901.186 \text{ on an}$ absolute scale and since (m-n) = 959-79 = 880, $\sum_{l} w \Delta^2/(m-n) = 1.024$, which is close to its theoretical limit of unity (see section 1.5).

A Fourier synthesis was computed from the experimental $|F_0|$ values with the phases (+1 or -1) calculated from the final structural model. See figure 3.6.1.

3.7 Discussion

The final fractional coordinates and their standard deviations for the atoms in the asymmetric unit are given in table 3.7.1 and anisotropic temperature factors in table 3.7.2. A perspective view of the structure along the b axis is shown in figure 3.7.1, drawn by the computing department programme PAMOLE.

Programme A5 was used to compute interatomic bond lengths and angles and these are listed in tables 3.7.3 and 3.7.4 together with their standard deviations obtained from the final SFLS calculation. No standard deviations are available for those values involving hydrogen atoms since they were not included in least squares refinement.

0.0000	0.0004	0.0004	9000.0	0.0008	0.0009	0.0008	0.0008	0.0007					
00000	0.1081	0.0893	0.2929	0.3030	0.5078	0.7104	0.6981	0.4917	0.1500	0.5059	0.8658	0.8462	0.4800
000000	0.0004	0.0004	0.0005	0.0007	0.0007	0.0008	0.0008	0.0008					
00000	-0.1314	-0.1005	0.2735	0.4813	0.6743	0,6601	0.4420	0.2533	0.4861	0.8313	0.7991	0.4286	0.0954
00000	0.0004	0.0004	0.0005	0.0007	0.0007	0.000T	0.0007	0.000T					
0.000	0.1723	-0.1529	0.1437	0.2070	0.3090	0.3457	0.2776	0.1813	0.1765	0.3555	0.4174	0.3076	0.1325
Si	된	FZ	N	5	C5	63	む	ਨ	H1	H2	H3	H4	H5
	000000 000000 000000 000000	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081	0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893	0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929	0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.3030	0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.3030	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.3030 0.30457 0.0007 0.6601 0.0008 0.7104	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.3030 0.3030 0.3097 0.0007 0.5078 0.3090 0.0007 0.6601 0.0008 0.6981	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.1437 0.0007 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.3030 0.3030 0.3090 0.0007 0.6601 0.0008 0.5078 0.2776 0.0007 0.6601 0.0008 0.6981 0.1813 0.0007 0.2533 0.0008 0.4917	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.2070 0.0007 0.4813 0.0007 0.3050 0.3050 0.3090 0.0007 0.6743 0.0007 0.5078 0.3090 0.0007 0.6601 0.0008 0.5078 0.2776 0.0007 0.4420 0.0008 0.6981 0.1765 0.0007 0.4861 0.1500	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1514 0.0004 0.1081 0.1059 0.0004 0.0893 0.2070 0.0007 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.2030 0.2030 0.2531 0.0007 0.2539 0.0008 0.4917 0.1765 0.0007 0.2533 0.0008 0.4917 0.1765 0.2533 0.8313 0.2539	0.0000 0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.2070 0.0007 0.4813 0.0007 0.2929 0.2070 0.0007 0.4813 0.0007 0.5078 0.2929 0.2007 0.6601 0.0008 0.5078 0.2756 0.0007 0.6601 0.0008 0.6981 0.1813 0.0007 0.4420 0.0008 0.4917 0.1765 0.4861 0.0008 0.4917 0.4174 0.7991 0.8658	0.0000 0.0000 0.0000 0.0000 0.0000 0.1723 0.0004 -0.1314 0.0004 0.1081 -0.1529 0.0004 -0.1005 0.0004 0.0893 0.1437 0.0005 0.2735 0.0005 0.2929 0.2070 0.0007 0.4813 0.0007 0.5030 0.3497 0.0007 0.6743 0.0007 0.5078 0.2457 0.0007 0.6743 0.0008 0.7104 0.2776 0.0007 0.4420 0.0008 0.6981 0.1813 0.0007 0.2533 0.0008 0.4917 0.1765 0.8313 0.8513 0.5059 0.4174 0.7991 0.8868

Table 3.7.2

Anisotropic temperature factors x 10

Atom	B ₁₁	B ₂₂	B 33	B ₂ 3	B ₁₃	B ₁₂
Si	167	243	193	165	169	52
F1	26 3	314	270	184	159	213
F2	260	342	292	165	341	43
N	167	257	244	196	224	6 3
C1	217	265	282	209	255	158
C 2	226	279	3 5 9	209	261	170
C 3	207	346	283	46	178	101
C4	2 23	406	258	174	247	79
C 5	217	3 6 3	25 3	268	237	77

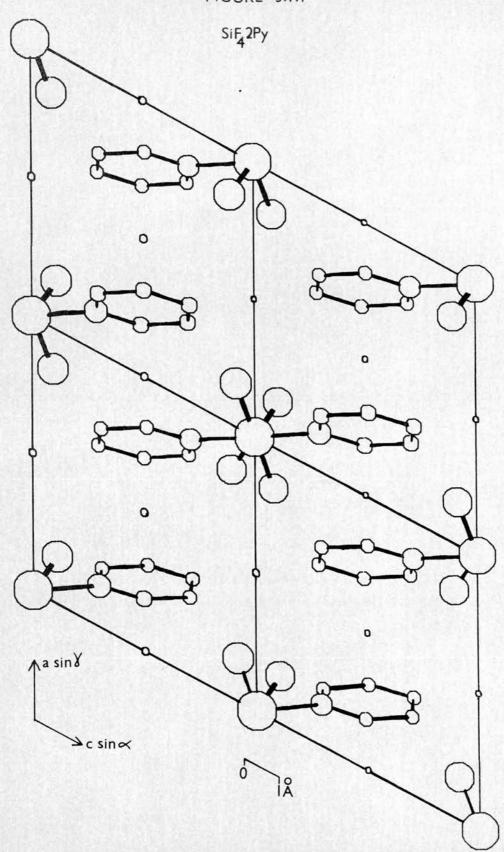


Table 3.7.3

Intramolecular bond lengths

Bond	Length (Å)	<u>ε(Å)</u>
S1-F1	1.640	0.003
S1-F2	1.653	0.003
S1-N	1.948	0.005
N-C1	1.335	0.006
C1-C2	1.368	0.011
C2-C 3	1.365	0.009
C3-C4	1.399	0.008
C4-C5	1.360	0.011
C5-N	1.354	0.007
C1-H1	1.010	
C2-H2	1.037	
C 3 -H 3	1.015	
C4-H4	1.001	
C5-H5	1.004	

Table 3.7.4

Intramolecular b	ond angles (°)	<u> </u>
F1-Si-F2	90.2	0.1
F1-S1-N	90.4	0.2
F2-S1-N	90.0	0.2
S1-N-C1	121.6	0.4
S1-N-C5	119.5	0.4
C1-N-C5	119.0	0.6
N-C1-C2	122.1	0.5
C1-C2-C3	120.3	0.5
C2-C3-C4	117.2	0.7
C3-C4-C5	120.7	0.5
C4-C5-N	120.8	0.5
N-C1-H1	115.6	
C2-C1-H1	122.3	
C1-C2-H2	118.9	
C3-C2-H2	120.7	
C2-C3-H3	123.1	
С4-С3-Н3	119.7	
C3-C4-H4	118.0	
C5-C4-H4	121.3	
C4-C5-H5	121.7	
N-C5-H5	117.6	

A5 gave the shortest intermolecular distances (< 3.2Å) as (in Å): F2-H3 H1-H4 H2-H5 C2-H5 C5-H2 F1-H1 F1-H2 F1-H3 2.890 2.720 2.599 2.453 2.643 3.132 3.113 2.571 Due to steric hindrance of the hydrogen atoms with the fluorine atoms of adjacent molecules, the plane of the pyridine ring does not bisect the angle F1-Si-F2. By dropping perpendiculars from C4 and C5 on to the line joining F1 and F2, and applying simple geometry, it was calculated that atoms C4 and C5 are rotated about the Si-N-C3 axis towards F2 by 9.4°. The angle Si-N-C3 is 180° and there are no unduly short intermolecular distances.

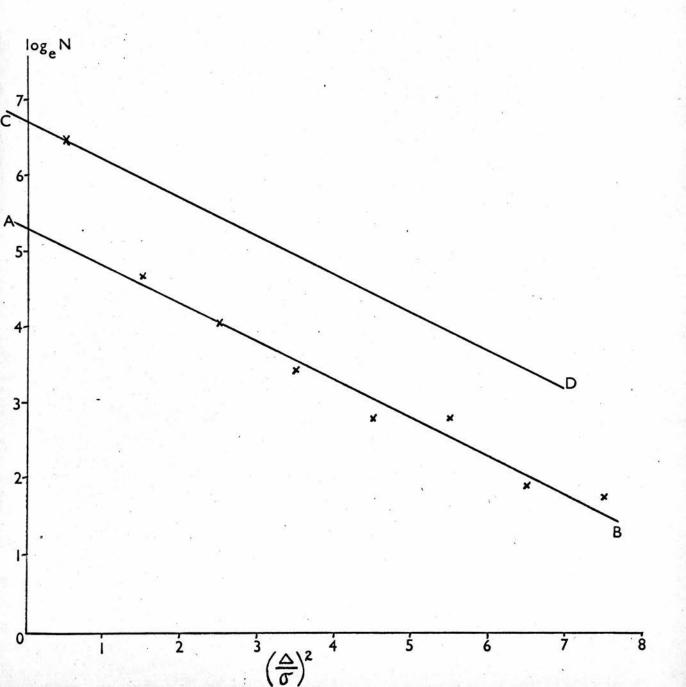
The best plane through the five carbon atoms was calculated as described in Appendix D. It is given by lx'+my'+nz' = p with respect to orthogonal axes (x', y', z') chosen according to Appendix C. l=+0.93799, m=-0.32126, n=+0.13024 and p=+0.02138Å. The perpendicular distances of the atoms from this plane are (in Â):

Si	N	C1	C 2	C3	C4	C 5
-0.021	-0.007	-0.008	+0.008	+0.000	-0.008	+0.008
F1	F2	H1	H2	Н3	H4	Н5
+1.296	-1.011	-0.009	+0.012	-0.012	+0.013	+0.010

The deviations of Si and N are not significant and thus the Py-Si-Py part of the molecule is planar. The pyridine plane is confirmed to lie nearer F2 than F1.

The Si-F1-F2 plane, l'x' + m'y' + n'z' = 0, was also calculated

Figure 3.7.2



and the angle between the two planes, given by $\cos^{-1}(11'+mm'+nn')$, found to be 89°15'. 1' = +0.06058, m' = +0.48878, n' = +0.87030.

With respect to the oblique axes of the reduced triclinic cell, the pyridine ring plane is : $\frac{x}{a} + \frac{y}{b} + \frac{z}{c} = 1$; where $a = +0.02215\text{\AA}$, $b = -0.06655\text{\AA}$ and $c = -0.10291\text{\AA}$ are the intercepts on the axes (see Appendix D).

If the weights assigned to the diffractometer intensities according to equation (12), section 1.5 and as described in section 3.6 are absolute, then the distribution of Δ/σ values (= $\sqrt{w}\Delta$) should obey a Gaussian curve: $N = \frac{1}{G\sqrt{2\pi}} \exp{-\frac{1}{2}(\frac{\Delta}{G})^2}$.

In order to check this, programmes A13 and A14 were used to plot $\log_e N$ v. $w\Delta^2$ where N is the number of reflections with $w\Delta^2$ values in each of the 16 intervals from 0-16 (the 17 reflections with $|W| |\Delta| > 4$ having been removed). The resulting graph is shown in figure 3.7.2. Points with $(\Delta/\sigma)^2 > 8$ have been omitted because of the small number of reflections in each of these intervals. The best least squares straight line AB through all points except the first was evaluated by the computer library programme CLPOLF. Its slope = -0.50= -B and intercept on $\log_e N$ axis=5.33= $\log_e A$, where N=Ae^{-B(Δ/σ)². B equals the theoretical value of $\frac{1}{2}$. The deviation of the first point with $(\Delta/\sigma)^2 = 0 \rightarrow 1$, from this normal distribution could be because reflections, too small to be recorded by the linear diffractometer and with $(\Delta/\sigma)^2 > 1$, have been omitted. If included, N might increase for all points except the first one,}

keeping them linear with slope = $-\frac{1}{2}$, to give the normal distribution represented by the line CD, with intercept = $\log_{a} A = 6.75$.

Section B Photographic Data

3.8 Measurement of intensities

The linear diffractometer not yet being operational due to the faults discussed in section 2.2, integrated intensities were recorded on equi-inclination integrated Weissenberg photographs for $k=0\rightarrow 7$ as described in section 2.5 Test photographs were taken of sections of various k levels with different integration settings a and b (see section 2.5) and different exposure times. The range of x-ray intensities diffracted by SiF_{4} , 2Py was very large and as seen in section 2.6, only a certain range of spot density can be measured on the microdensitometer. Thus the film pack technique (DeLange, Robertson and Woodward, 1939; and Robertson, 1943) was employed with two films per exposure: an "industrial G" film (nearer the x-rays) and a less sensitive, smaller grained B film (Iball, 1954). The following exposures per level were found to be the optimum using $MoK\overline{\alpha}$ radiation:

- 1. Films G₁ and B₁. Each spot traversed 4 x 30 times (~53 hours) with vertical displacement b=0.6mm and translation step a=1.5/30 = 0.05mm. 40kV 20mA.
- 2. Films G_2 and B_2 . Each spot traversed 15 times (~ 7 hours) with b=0.6mm and a=1.5/15 = 0.1mm. 40kV.

 10mA for h0l h3l 20mA for h4l h5l

Table 3.8.1

Level	No. of films	<u>S</u> 1= <u>G</u> 1/ <u>B</u> 1	<u>s</u> 2= <u>B</u> 1/ <u>G</u> 2	S = G 2/B2	No. of different reflections
h01	4	3.278	3.974	3 .980	96
h11	4	3 .945	3 .53 0	3.420	150
h 2 1	4	3 .57 6	3 .782	3.936	157
h 3 1	4	3 .598	4.294	4.171	151
h41	4	2.335	2.852	4.668	109
h 5 1	3	3 .7 37	2.069		92
h 61	2	3 .961			84
h 7 1	2	3.743			45

The shorter exposure B₂ film must contain the strongest reflections, light enough for accurate densitometer measurement, and the longer exposure G₁ film, as many measurable weak reflections as possible.

All the films for one level were processed together in complete darkness by agitating in fresh developer. It is essential that each film on one level contains a sufficient number of measurable reflections common to the next strongest and weakest films so that the scale factors between the films on each level may be calculated. The factors to scale all films per level up to the G₁ film are given in table 3.8.1. The vast majority of a total of 1535 reflections were measured by Mrs. J. Page, as described in section 2.6. Of these about half were used for inter-film scaling, 884 unique intensity estimates remaining, as listed in table 3.8.1.

The accuracy in intensity measurement was found by comparing Friedel equivalent intensities on both halves of three hol films. The mean ratios of such intensities were 1.06, 1.07, 1.09. The mean intensity reduction between the G and B films in a pack is 3.72 (from the 13 values in table 3.8.1) and its standard deviation of 0.52 implies 14% accuracy.

3.9 Data processing

Precession photographs had been taken for scaling the intensity estimates between k levels but were not used since the diffractometer data were now available. By comparing the largest photographic

intensities from each level with the equivalent diffractometer values, a scale factor was found for each level to put all the photographic data on the same scale as the diffractometer intensities.

Programme A2 was used to apply these scale factors and Lp corrections and obtain |F| values.

By this time a set of atomic coordinates for the molecule had been obtained from the solution of the Patterson vector set and subsequent Fourier map described in section 3.5.

3.10 Structure refinement

The latest Pī atomic coordinates and anisotropic temperature factors from the present stage of refinement of the structural model from the diffractometer data (section 3.6) were used for an SFLS calculation by programme A3 together with the photographic $|F_0|$ values. The calculated hydrogen parameters (section 3.6 and table 3.7.1) were also given but not included in least squares calculations. The first calculation gave R = 0.230 and before refinement on the 79 parameters, those reflections outside the copper sphere ($\sin\theta > 0.461$) were removed.

During refinement, each pair of $|F_o|$ and $|F_c|$ values was examined, and those reflections with a large discrepancy between them and between the diffractometer $|F_o|$ value were traced back to the film measurement stage. Some errors were found and corrected: namely, reflections misindexed, specks of dust on the film measured instead

of the actual spot which often was invisible, mispunched intensities on cards and some reflections included twice.

A scale factor $\sum |F_c|/\sum |F_o|$ was calculated for and applied to each k level (see section 3.6).

<u>Level</u> h01 h11 h21 h31 h41 h51 h51 h71 <u>Scale</u> 0.9505 0.9891 0.9938 0.9352 1.1466 0.9232 0.8674 0.7677

When structure refinement had progressed to the stage where R = 0.126, it was decided to check the space group by moving the atoms away from their centrosymmetric configuration (m = 771, n = 79) and proceeding with refinement using space group P1 (m = 771, n = 154). After several cycles R and $\sum \Delta^2$ reached minimum values, R at 0.134. Since $\sum \Delta^2/(m-n)$ had increased to 1.32 x its value when Pī was assumed and the molecular geometry was not so sensible, the centrosymmetric nature of the molecular was confirmed.

Weighting scheme (a) (equation (11), section 2.5) was used throughout, being the most suitable for the photographic data $(F_{min} = 0.84)$.

The (5, 0, 2) reflection, having extremely poor agreement between F_0 and F_c , was omitted from the refinement procedure which was continued with the other 770 reflections until minimum $\sum w\Delta^2$ and R=0.0960 were obtained. With (5, 0, 2) included, final R=0.0975, which was thought to be satisfactory in view of the quality of the crystal, its incapsulation and the errors involved in

Table 3.11.1

	_	~	•	1255011	10	٠.			-	
c (z/c)	0.000	90000	0.000	0.0011	0.001	0.0016	0.0016	0.0015	0.001	
2/0	00000	0.1090	0.0894	0.2910	0.3026	0.5067	0.7111	9869.0	0.4898	
ع(y/b)	00000	0.0010	0.0010	0.0013	0.0017	0.0018	0.0020	0.0020	0.0017	
g/k	0.0000	-0.1309	-0.0984	0.2706	0.4781	0.6750	0.6608	0.4432	0.2525	
$\sigma(x/a)$	000000	0.0008	0.0008	0.0010	0.0013	0.0014	0.0014	0.0014	0.0013	
x/a	000000	0.1721	-0.1511	0.1422	0.2054	0.3100	0.3482	0.2804	0.1809	
\tom	S1	된	F2	N	5	23	3	き	છ	

Table 3.11.2

Anisotropic temperature factors x 10⁴

Atom	B ₁₁	B ₂₂	B ₃₃	B ₂ 3	B ₁₃	B ₁₂
Si	112	3 25	155	145	142	34
F1	179	404	218	165	85	188
F 2	201	3 90	241	140	2 57	- 40
N	124	322	195	152	128	96
C1	160	3 09	205	95	155	108
C2	184	33 5	284	170	181	6 3
c 3	165	442	250	88	208	134
C4	200	489	152	109	169	47
C5	158	371	17 3	123	135	6 3

the photographic measurement of intensities.

The (5, 0, 2) reflection $(F_0 \gg F_c)$ is probably a Renninger reflection (Renninger, 1937) caused by double diffraction from the $[2, 0, \bar{1}]$ and $[\bar{4}, 0, \bar{1}]$ crystal planes. Using the polar plot of hol level (figure 2.4.1) the Ewald sphere of reflection was found to pass through the reciprocal lattice points $(2,0,\bar{1})$ and $(\bar{4},0,1)$ simultaneously. The $(2,0,\bar{1})$ and $(\bar{4},0,1)$ reflections are very large and fairly large respectively, as seen in Table A where the final F_0 and F_c values, $(F_0)_p$ and $(F_c)_p$, are listed. For the photographic data, the listed indices of reflections are the Friedel equivalents of those measured $(k = 0-\bar{7})$ since diffractometer intensities were measured for k = 0-7.

3.11 Molecular geometry

The final atomic coordinates of the refined structural model obtained from photographic intensities are given in table 3.11.1 together with their standard deviations. Hydrogen coordinates are not listed since they have been given already in table 3.7.1. Anisotropic B_{ij}'s are tabulated in table 3.11.2, and intramolecular bond lengths and angles and their standard deviations in tables 3.11.3 and 3.11.4.

A scan of interatomic bond lengths and angles by programme A5 showed that, as obtained before for the structural model from diffractometer intensities, the angle Si-N-C3 is 180° and the shortest intermolecular distances are equal to those given in

Table 3.11.3

Intramolecular bond lengths

Bond	Length (Å)	<u>σ(Å)</u>
Si-F1	1.639	
S1-F2	1.637	
Si-N	1.932	0.012
N-C1	1.329	0.013
C1-C2	1.379	0.012
C2-C 3	1.375	0.015
C3-C4	1.395	0.017
C4-C5	1.376	0.012
C5-N	1.347	0.012
C1-H1	1.019	
C2-H2	1.027	
С3-Н3	1.011	
C4-H4	1.005	
C5-H5	1.004	

Table 3.11.4

Intramolecular bond	angles (°)	<u> 6(°)</u>
F1-S1-F2	90.1	
F1-S1-N	90.2	
F2-S1-N	89.5	
Si-N-C1	121.8	0.8
S1-N-C5	120.2	0.8
C1-N-C5	118.0	0.7
N-C1-C2	123.6	0.9
C1-C2-C3	119.2	1.0
C2-C3-C4	117.1	0.8
C3-C4-C5	120.8	1.0
C4-C5-N	121.2	0.9
N-C1-H1	116.3	
C2-C1-H1	120.0	
C1-C2-H2	120.5	
C3-C2-H2	120.3	
C2-C3-H3	123.4	
С4-С3-Н3	119.4	
C3-C4-H4	118.5	
C5-C4-H4	120.8	
C4-C5-H5	121.1	
N-C5-H5	117.7	

section 3.7. Again, the pyridine ring is rotated, by 9.1°, towards F2 to ease the steric repulsion between hydrogens and fluorines of adjacent molecules.

The least squares best fit plane (see Appendix D) through C1-C5 was calculated to be:

-0.93866x' + 0.32269y' - 0.12158z' = 0.00135 with respect to orthogonal axes x', y', z' (see Appendix C). Atomic deviations from this plane are (in $^{\text{A}}$):

Thus, it is again apparent that Si and N lie on the plane, which is nearer F2 than F1. The Si-F1-F2 plane was also calculated with respect to x', y' and z': 0.06250x' + 0.49309y' + 0.86773z' = 0. The angle between it and the plane of the pyridine ring is 90°17'.

In terms of the reduced triclinic cell axes, the pyridine ring plane is:

$$-\frac{x}{0.00140} \frac{y}{0.00419} \frac{z}{0.00630} = 1$$

3.12 Conclusion

Structural models have been found for SiF4, 2Py from intensities measured by diffractometer and photographic techniques. Comparison

of both sets of results, given in tables 3.7.1 - 3.7.4 and 3.11.1 - 3.11.4, indicates no significant differences in atomic parameters and molecular geometry.

The values of 1,m and n for the best fit pyridine plane, $1x^{\dagger} + my^{\dagger} + nz^{\dagger} = p$, calculated for both models (sections 3.7 and 3.11) differ in the third decimal place. The angle between the planes is 30' and their separation, given by $p_1 + p_2$ since they are fractionally on opposite sides of the origin (Si atom), is 0.023\AA . The angle between both Si-F1-F2 planes is 17' and their 1,m and n values also differ in only the third decimal place.

The final R factor for the linear diffractometer data, 0.0758, is lower than that for the photographic observations (0.0975) and the standard deviations of the diffractometer model are smaller (cf. tables 3.7 and 3.11). This is a consequence of the greater precision of the counter data and the larger number of reflections measured (m = 959 and 771 respectively).

Thiourea has also been used for a comparison of counter and photographic observations (Truter, 1967) and gave similar results.

The centrosymmetric trans configuration of SiF₄,2Py in the solid state confirms the conclusions obtained from infrared spectroscopy and is similar to that claimed for tetrachlorobispyridinegermanium (IV) (Hulme, Leigh and Beattie, 1960). Their crystallographic deductions are based on one two dimensional Patterson map using 32 structure factors, the space group being

postulated mainly on this basis.

The molecules of $SiF_{\frac{1}{4}}$, 2Py are arranged in the lattice with the pyridine rings stacked one above the other, almost normal to a of the reduced triclinic cell. Hence the separation of adjacent pyridines is $\approx \frac{1}{2}a = 3.62\text{Å}$.

4. THE CRYSTAL AND MOLECULAR STRUCTURE OF TETRACHLOROBISPYRIDINESILICON (IV)

4.1 Introduction

The infrared spectrum of solid SiCl₄,2(NC₅H₅) has been interpreted as the basis of a cis geometrical isomer from both the number and position of Si-Cl stretching vibrations (Beattie et al, 1964). A single crystal x-ray examination of the compound was briefly reported in the same paper (Hulme, personal communication). Statistical tests (Howells, Phillips and Rogers, 1950) gave inconclusive results, but a trans configuration was excluded and a cis isomer postulated.

The i.r. spectrum of SiCl₄,2Py in the solid state has also been reported by Campbell-Ferguson and Ebsworth (1967) and agrees with the earlier work, although they suggest the prescence of polymeric cations. More recent Raman spectroscopy measurements have led to a revised and more cautious view on the stereochemistry of the Si (Halogen)₄, 2 Pyridine systems. A single crystal x-ray examination of SiCl₄,2Py was undertaken, to establish its structure unambiguously.

4.2 Description of crystals

The crystals of SiCl₄,2Py had been prepared by the same method used for SiF₄,2Py but were of poorer quality and were sealed in pyrex tubes. The crystals were supplied by Dr. M. Webster.

Triclinic cell parameters were established using the best crystal in an initial sample, and considerable time was spent trying to set this crystal on the linear diffractometer as described in section 2.3 for collection of intensity data. The crystal was fragmented and powdery, and the intensity profiles of reflections, seen on the chart recorder by tracking through the oscillation scale, were of the forms:



The profile of any one reflection did not remain the same when different portions of the rather long crystal were centred in the x-ray beam. Intensity profiles worsened as 3 increased and Friedel equivalent intensities on the zero layer were very unequal.

It was impossible to set the crystal either such that the main intensity peak was isolated and set for all reflections at the centre of the oscillation range, or such that the whole profile of all reflections was included in even the maximum oscillation range.

Thus the linear diffractometer could not be used for measurement of intensities from this fragmented triclinic crystal. Intensity estimates could have been obtained from integrated photographs, but by this time a second sample of crystals was available. The best single crystal it produced [0.7mm by (0.6 x 0.4) mm²] had an

additional small fragment enclosed with it in the pyrex tube, and this was seen from photographs to produce additional spots.

These however were generally well separated from the main reflections, and hence this crystal was used for an x-ray diffraction study.

4.3 Unit cell dimensions

Preliminary rotation and equi-inclination Weissenberg photographs were taken with a Nonius camera using Mo radiation and indicated that the crystal was triclinic. The most prominent unit cell was chosen, c along the goniometer axis, and values of c, a*, b* and γ^* were obtained. By considering the Weissenberg geometry and the displacement of upper level reflections, the cell axes were labelled such that a right-handed system was maintained with real angles obtuse and reciprocal cell angles acute. Absences noted were: h + k = 2n + 1; k + 1 = 2n + 1, h + 1 = 2n + 1. This cell is therefore centred on all faces.

For further information the crystal was transferred to a Nonius precession camera and c* was aligned along the dial axis. Zero, first and second layer photographs with a and b perpendicular to the film cassette were taken. The chosen unit cell was confirmed to be an F cell and its parameters accurately determined, giving:

$$a_F = 13.071 \text{Å}$$
 $b_F = 12.540 \text{Å}$ $c_F = 8.247 \text{Å}$ $\alpha_F = 95^{\circ}8'$ $\beta_F = 99^{\circ}7'$ $\gamma_F = 104^{\circ}40'$

Volume = 1279.26A3

Measured density = (1.71 ± 0.02) gm/cm³

Calculated density = 1.70 gm/cm for 4 molecules in the F cell.

Only a primitive cell may be reduced by the method of Delaunay (1933) and suitable parameters were found from the following vector transformations:

$$\underline{a}_{p} = \frac{1}{2}\underline{b}_{F} + \frac{1}{2}\underline{c}_{F}$$
; $\underline{b}_{p} = \frac{1}{2}\underline{a}_{F} + \frac{1}{2}\underline{c}_{F}$; $\underline{c}_{p} = \frac{1}{2}\underline{a}_{F} + \frac{1}{2}\underline{b}_{F}$

This P cell had all real angles acute and a Delaunay reduction was performed. Four steps were necessary to give six negative scalar products $\underline{a}.\underline{b}$, $\underline{b}.\underline{c}$, $\underline{c}.\underline{a}$, $\underline{a}.\underline{d}$, $\underline{b}.\underline{d}$ and $\underline{c}.\underline{d}$, where \underline{d} = $-(\underline{a} \ \underline{b} \ \underline{c})$, and hence all angles obtuse. The three shortest vectors obtained for the reduced cell were:

$$\underline{a} = \underline{a}_{P} = \frac{1}{2}\underline{b}_{F} + \frac{1}{2}\underline{c}_{F}$$

$$\underline{b} = \underline{b}_{P} - \underline{c}_{P} = -\frac{1}{2}\underline{b}_{F} + \frac{1}{2}\underline{c}_{F}$$

$$\underline{c} = -\underline{b}_{P} = -\frac{1}{2}\underline{a}_{F} - \frac{1}{2}\underline{c}_{F}$$

giving reduced triclinic cell parameters:

$$a = 7.189$$
Å $b = 7.806$ Å $c = 7.152$ Å

$$b = 7.806$$

$$c = 7.152$$
Å

$$\alpha = 117^{\circ}9'$$

$$\beta = 90^{\circ}3'$$

$$\alpha = 117^{\circ}9^{1}$$
 $\beta = 90^{\circ}3^{1}$ $\gamma = 113^{\circ}27^{1}$

Volume = 319.36Å3

Calculated density for 1 molecule in the reduced cell is 1.71gm/cm3. The space group is P1 or P1.

Linear absorption coefficient $\mu = 9.9 \text{cm}^{-1}$ for MoK α radiation.

If a zero scalar product occurs, which means one 90° angle, then the Delaunay reduction is ambiguous, since by "changing the sign" of the zero term, another tri - obtuse cell

may be obtained, perhaps with shorter axes (Patterson and Love, 1957). Consequently since β above is effectively 90°, the alternative reduced cell was determined, but found to have one longer axis. Hence the reduced cell with the three shortest non-coplanar translations is as given above.

The orientation of the crystal in the pyrex tube was such that it was impossible to align any of the reduced cell axes along the goniometer axis, without causing awkward absorption effects due to very different path lengths through the pyrex for different reflections.

Consequently, since c_F lay approximately along the length of the tube, the necessary goniometer arcs' movements were calculated and c_F was accurately realigned along the goniometer axis for measurement of diffracted intensities on the linear diffractometer. Reflections were initially indexed and collected with respect to the F cell, but converted to reduced cell indices for subsequent calculations.

Throughout the measurement and calculation of lattice parameters, reference was made to Hulme's published parameters for SiCl₄,2Py (Beattie et al, 1964) but no similarity or relationship between them and the values reported in this thesis could be detected.

A rough check of the published values was made, using only what information was available; namely the lattice parameters of the triclinic body centred I cell which was used for intensity data collection, and the "reduced" cell values, supposedly related to the I cell by the matrix given as:

$$\begin{bmatrix} \underline{a} \\ \underline{b} \\ \underline{c} \end{bmatrix} = \begin{bmatrix} 1 & 0 & 0 \\ \frac{1}{2} & \frac{1}{2} & \frac{1}{2} \\ \frac{1}{2} & \frac{1}{2} & -\frac{1}{2} \end{bmatrix} \begin{bmatrix} \underline{a}_{\underline{I}} \\ \underline{b}_{\underline{I}} \\ \underline{c}_{\underline{I}} \end{bmatrix}$$

If this matrix is applied to the I cell then one obtains the published primitive cell axes, but angles which are all acute and equal to 180° minus the published values. A Delaunay reduction on this cell gives a reduced cell unlike both Hulme's and the one determined above. Due to this inconsistency and the conclusion that the given I cell must also be incorrect, no confidence can be placed in these earlier crystallographic deductions about SiCl_h, 2Py.

4.4 Measurement of intensities

Generator: 40kV 16mA

The crystal was set on the linear diffractometer as described in section 2.3 and intensity data were collected for $l_F = 0 \rightarrow \overline{10}$ using Mo radiation (see section 2.4).

1½ mm collimator 2°45' oscillation angle
2 oscillation cycles ½ minute oscillation motor
P.H.A.: E.H.T. = 1045 volts, low level = 30 volts,
window = 38 volts.

Experimentally determined offsets for upper level 1_{E} :

- 0.0146 x 1 r.l.u. along the lower a* slide
- 0.0086 x $l_{\rm F}$ r.l.u. along the upper $b_{\rm F}^{\star}$ slide

Calculated offsets: - 0.0143 r.l.u. and - 0.0081 r.l.u. respectively.

For levels with even l_F , only reflections with both h_F and k_F even are present, and for odd l_F , $h_F = 2n + 1$ and $k_F = 2n + 1$. Hence, to avoid counting systematically absent reflections, the intervals on each level were set as:

scanning (upper) slide interval = $2b^*_F$ = 0.1183 r.l.u. stepping (lower) slide interval = $2a^*_F$ = 0.1144 r.l.u. Angle between slides = γ^*_F = 74°13'

Since the indices recorded on cards by the linear (h_L, k_L, l_L) increase by 1 after each interval, the resulting intensities will not be correctly indexed with respect to the F cell. For $l_F = 2n$, $h_F = 2h_L$ and $k_F = 2k_L$. For $l_F = 2n + 1$, the $(1,1,l_F)$ reflection was labelled $(0,0,l_F)$ with respect to the diffractometer and thus $h_F = 2h_L + 1$ and $k_F = 2k_L + 1$.

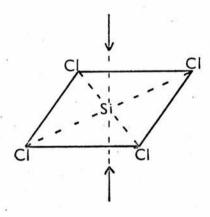
Several reflections with very uneven backgrounds were examined with reference to the Weissenberg photographs, and found to consist of the main peak, set to within 20', plus a small adjacent peak due to the extra fragment of crystal present in the tube (see 4.2). These reflections were corrected.

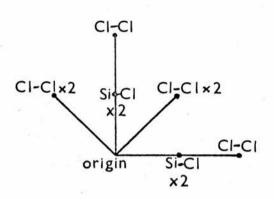
For the highest levels, $l_F = 9$ and $\overline{10}$, the oscillation angle was increased to 5°20' for the reasons given in sections 2.4.1

Figure 4.5.1

(A) TRANS

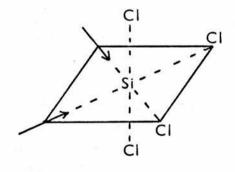
vector space

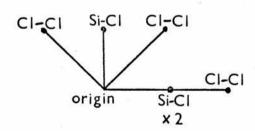




(B) CIS

vector space





plus 4 more vectors out of the plane.

and 3.4. 56 reflections on hk8 were recollected and used for scaling between the two sets of data.

4.5 Data processing and Patterson and Fourier syntheses

The diffractometer data cards were first reindexed for the F cell by programme A15, and then processed by A1 and A2. The additional multiplying factor for data with $l_F = \bar{9}$ and $\bar{10}$, to put them on the same scale as the rest, was 1.694. No absorption corrections were made. The F cell indices of the set of |F| and $|F|^2$ values were changed to those of the reduced primitive cell (see section 4.3) by programme A16. Reflections outside the copper sphere, and those with zero |F|, were removed, prior to computing a Patterson synthesis with the remaining 1360 $|F|^2$ values. The same intervals were taken as for SiF_h , 2Py in section 3.5.

The first problem was to determine from the Patterson map if possible, whether the one molecule in the reduced cell was cis or trans. The interatomic vectors involving chlorine atoms will give much larger peaks than other vectors, since Z = 17. Cl (Unlike SiF₄,2Py, where a Fourier synthesis was necessary before its trans nature was established). The vector sets, for the silicon and four chlorine atoms in both cases, are illustrated in figure 4.5.1. There are 10 interatomic vectors but in the trans case (A), only 6 are unique. They are planar as shown and 4 have double weight. For a cis configuration (B), there are 9

unique vectors, 5 in a plane and only 1 of double weight.

The expected relative sizes of these vector peaks are given by:

$$Si - C1 \approx Z_{C1} \times Z_{Si} = 238 \times 2 = 476$$

$$C1 - C1 \approx Z_{C1}^2 = 289 \times 2 = 578$$

Hence the largest peak expected is (C1-C1) x 2 or (Si-C1) x 2 for either vector set (A) or (B) respectively.

Since six large peaks were found in the computed vector map, and the largest was 3.2Å from the origin, a trans configuration was indicated. It was discovered that, of these six peaks, two of equal height, had coordinates which were almost half those of another two equally sized peaks. The peak height of the former was 1.66 times that of the latter, and since the expected ratio (Si - Cl) x 2 / (Cl - Cl) is 1.65, these vectors were undoubtedly pairs of Si - Cl (double weight) and Cl - Cl vectors respectively.

The six vectors were finally and unambiguously allocated according to case (A), figure 4.5.1 and thus the trans configuration of the molecule was confirmed. Mean ratio of peak heights $(Cl - Cl) \times 2 / (Si - Cl) \times 2 = 1.3$; expect 1.2. The difference between the coordinates of every pair of vector peaks was calculated, and found to equal the coordinates of another vector, or the difference between another two vectors i.e. all vector coordinates obtained from the Patterson map tied in with vector set (A) to within 2/240 th's of the reduced cell edges.

The lengths of both Si - Cl vectors were calculated to be 2.14 and 2.18 Å and the angle between them 91°44'.

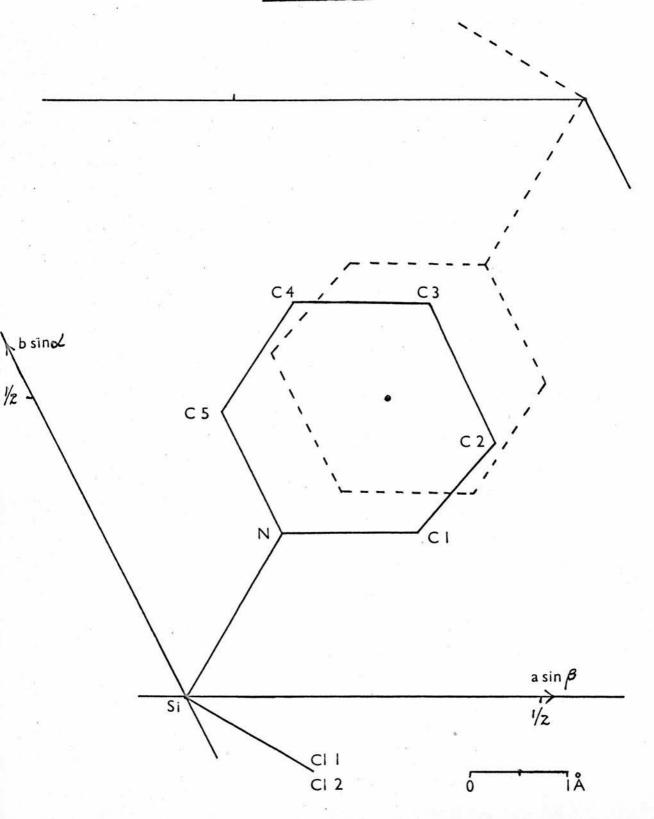
Placing the silicon atom at the origin of the reduced unit cell, the coordinates of the Si - Cl vectors position the two chlorine atoms directly (plus another 2 chlorines related by the centre of symmetry) and a structure factor calculation was computed using these coordinates and the set of F_0 's with reduced cell indices.

After one cycle to obtain a sensible scale for the $|F_0|$'s, another was computed (no least squares refinement) whose output was used for a Fourier synthesis with x/a, y/b, z/c from $0 \rightarrow \frac{1}{2}$,1,1 respectively at intervals of 1/30. The R factor for the largest $|F_0|$ and $|F_0|$ and $|F_0|$ are values was 0.26. The electron density map will be centrosymmetric because the chlorines were put in with centrosymmetric coordinates, and therefore all $|F_0|$'s = 0.

As discussed in section 1.1, not all the phases calculated from the contributions of the heavy atoms located from the Patterson map will be correct. For the centrosymmetric case, this means that not all reflections will have the same sign for F as was calculated for F_H . Considering the function $(\sum f_H^2/\sum f_L^2)^{\frac{1}{2}} \approx (\sum \frac{2}{\sum L}^2)^{\frac{1}{2}} = 1.70$ for this case, about 88% of the $|F_0|$ terms in the computed electron density function will have had their signs correctly determined (Sim, 1961).

A pyridine ring was identified from the Fourier; nine regions

Figure 4.5.2



of high electron density appeared, whose centres are shown plotted in figure 4.5.2, looking vertically down the c axis of the reduced triclinic cell. The projection of \underline{a} onto this plane perpendicular to \underline{c} is a $\sin\beta$, and of \underline{b} , b $\sin\alpha$. The angle between them = 180° - $\gamma*$.

4.6 Structure refinement

Once the $|F_0|$ scale had been adjusted, the first meaningful R factor was 0.245 for a structure factor calculation using the reduced cell coordinates for Si, Cl1, Cl2, N and Cl - C5 obtained from the Fourier. The space group was initially chosen as Pī. If the structure is not centrosymmetric, it will not refine and its molecular geometry will be poor with large standard deviations. The Si atom was given an isotropic temperature factor of 2 and the remaining atoms B = 4, being approximately the corresponding values for SiF_h , 2Py (see section 3.6).

After a few cycles of least squares refinement of the 34 parameters, R had slightly increased, and although the scale shift was very small, $\sum |F_0| \gg \sum |F_0|$. The B shifts for Cl1 and Cl2 were large and negative and since they are the largest scatterers, it was concluded their thermal parameters were too high, causing the calculated F's to be too small. It is also seen from equation (7), section 1.3, that this effect should increase with sine, and this was observed.

Hence the chlorine isotropic temperature factors were decreased to 2, and four further cycles were sufficient to reduce all coordinate

and B shifts to the 3rd and 2nd decimal places respectively. At this stage R = 0.146 and the B values were :

Si C11 C12 N C1 C2 C3 C4 C5
1.768 2.431 2.391 1.987 3.087 3.102 2.341 2.750 2.301

Before converting these to anisotropic B_{ij} 's, hydrogen coordinates with respect to the reduced cell were calculated as described in Appendix C for inclusion without refinement in subsequent structure factor calculations. They are listed in the final table of coordinates, 4.7.1. Each H atom was given the last isotropic B value of its corresponding carbon atom (see above). If estimates of the hydrogen positions are not included at this stage, then the ellipsoid of thermal vibration of each carbon will be falsely elongated in the direction towards its bonded H atom, to account for the hydrogen's unincluded contribution to F_c .

Reflections with net intensity estimate I less than 20 counts were removed and refinement of the 79 parameters was continued until after eight cycles R was a minimum at 0.119. A card output was taken and its reduced cell indices were changed to F cell indices by programme A17 in order to find a scale factor for each equi-inclination $l_{\rm F}$ level of data collected. The card output from A17 was sorted into $l_{\rm F}$ levels, and for each level, $\sum |F_{\rm C}|$ and $\sum |F_{\rm O}|$ were computed by A6. The scale factors $\sum |F_{\rm C}| / \sum |F_{\rm O}|$ are:

 1_{F} =0 $\overline{1}$ $\overline{2}$ $\overline{3}$ $\overline{4}$ $\overline{5}$ $\overline{6}$ 7 8 $\overline{9}$ $\overline{10}$ 0.959 1.179 0.933 0.894 0.916 0.934 0.971 0.961 1.070 1.010 1.213

A simple SPS programme applied the appropriate scale to each of the $|F_0|$ values (F cell indices). The indices were converted back to reduced cell values by A16 for further SFIS calculations.

Before layer scaling, nine reflections, all with $h + k = l_F = \overline{l}$, had poor agreement between F_o and F_c , but these discrepancies disappeared afterwards. The $(\overline{l}, \overline{l}, 0)$ reflection also had a large Δ , which was not improved by the scaling procedure. This reflection has indices $(2, 0, \overline{2})$ with respect to the F cell and, although was very close to the origin of the diffractometer slides, had not been centred and measured by hand. Hence it was excluded from the calculation of l_F scale factors and from further structure refinement.

After scaling, R fell to 0.0933 and further cycles, with 1245 reflections, reduced $\sum_{k} \Delta^{2}$ and R to minimum values (R = 0.0872). A more realistic R value with ($\bar{1}$, $\bar{1}$, 0) included was 0.0887.

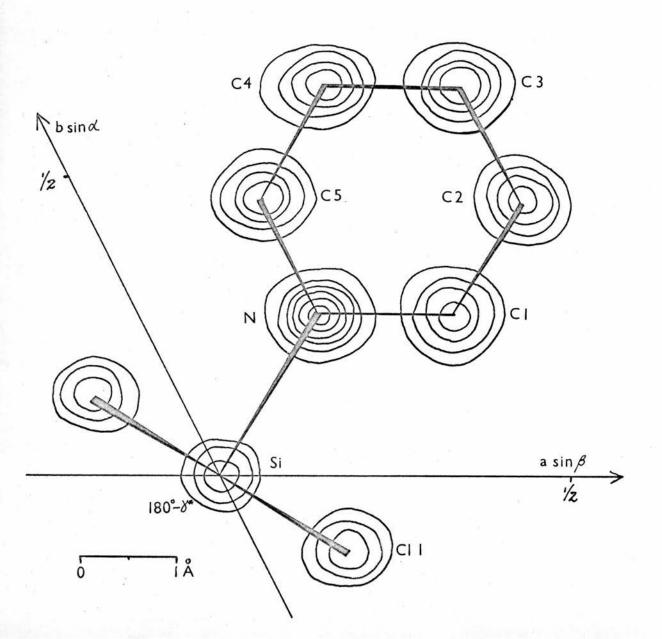
At no time during refinement was it felt necessary to depart from space group Pī, since the molecular geometry was very satisfactory and the R value above is the same as was obtained for centrosymmetric SiF₄,2Py at the same stage (see section 3.6). The deviation of the pyridine rings from a centrosymmetric configuration is less than the standard deviations of the atomic coordinates, and hence too small to be detected. The limiting values of the standard

Figure 4.6.1

A composite map of electron density in SiCl, 2Py, viewed along c (from sections nearest centres of peaks).

Contours at intervals of $2e/\Lambda^3$ for N, Cl-C5 beginning at $2e/\Lambda^3$.

Contours at intervals of $10e/{\rm \AA}^3$ for Si and chlorines, beginning at $10e/{\rm \AA}^3$.



deviations are determined by the quality of intensity data, which in turn is dependent on the crystal quality, setting precision of the crystal, diffractometer and counting statistics errors.

So far weighting scheme (a) (section 1.5) had been used $(F_{\min} = 1.18)$, but now scheme (b) was applied, according to the procedure described for SiF_{μ} , 2Py in section 3.6 and in programmes A7-A11. The (I + B)/(I - B) were processed with respect to the F cell used for data collection. c^2 was calculated = 0.013574 - 0.000977 = 0.012597. Hence c = 0.1122, G = 0.1165 and G(counting statistics) = 0.0313, confirming again that counting statistics errors are very small.

(K/4Lp)(I + B)/(I - B) values were reindexed from the F cell to reduced cell by A16 before using A10 to compute absolute \sqrt{w} for each reflection. A11 applied a scaled \sqrt{w} to each |F| data card for further SFLS calculations (reduced cell indices). D = 0.29013 (see A11 and section 3.6).

The first cycle gave a very much reduced $\sum \Delta^2$ and four cycles later, the card output was used to find reflections with $\Delta > 36$ or 46 (A12): 28 and 10 in number respectively. Two of the latter 10 reflections had been measured near the slides' intersection (one was ($\bar{1}$, $\bar{1}$, 0)). Another six had $1_F = \bar{1}$ ($\mu = 2^{\circ}28^{\circ}$) and since this level had a large scaling factor, it suggests that the diffract meter equi-inclination setting is very sensitive at such small μ . With SiF_h , 2Py this effect did not appear; its smallest $\mu = 1$

Table 4.7.1

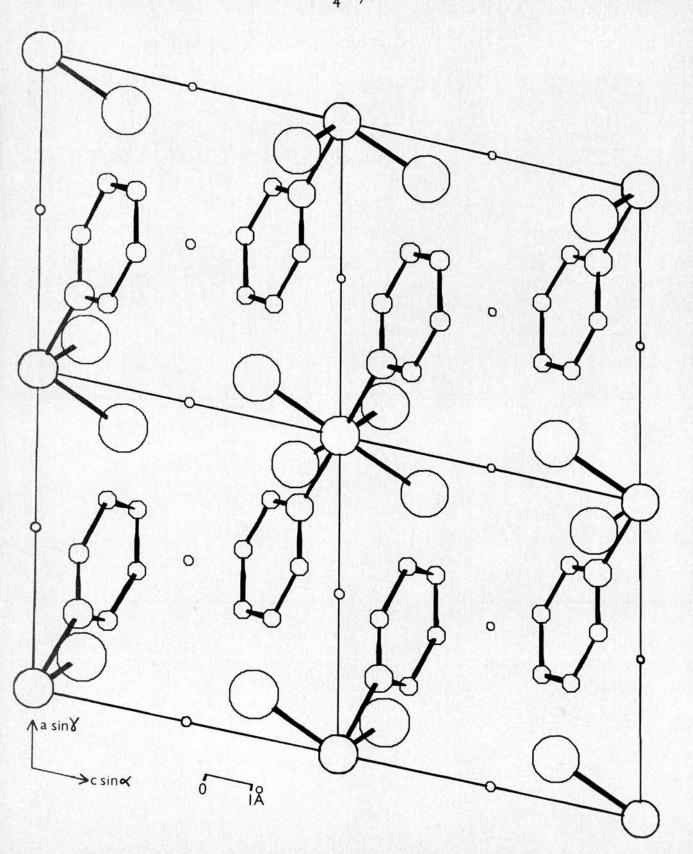
x/a 0.0000 0.1271 0.1270 0.2580	\$\pi(\pi/\pi)\$ 0.0000 0.0002 0.0006 0.0006	y/b 0.0000 -0.1282 -0.1283 0.2716	o.0000 0.0002 0.0002 0.0007	2/c 0.0000 0.1539 -0.2826 0.1369	(z/c) 0.0000 0.0002 0.0002
0.4464	0.0008	0.2713	0.0000	0.1370	0.0011
0.6220	9000.0	0.6509	6000.0	0.3250	0.0010
0.2532	9000.0	9494.0	9000.0	0.2330	0.0010
0.4526		0.1283		9290.0	
0.7668		0.4475		0.2180	
0.7537		0.7901		0.3949	
0.4234		0.7929		0.3897	
0.1167		6474.0		0.2403	

Table 4.7.2

Anisotropic temperature factors x 10

Atom	B ₁₁	B ₂₂	B ₃₃	B ₂₃	B ₁₃	B ₁₂
Si	95	106	132	121	47	91
C11	146	142	187	189	21	123
C1 2	145	148	160	136	119	133
N	105	105	164	128	25	76
C1	135	117	235	133	92	75
C 2	105	176	245	206	74	80
C 3	124	141	194	167	5 5	71
C4	191	113	204	160	77	112
C5	130	126	20 3	184	86	92

FIGURE 4.7.1 SiCl₄2Py



3°10' for k=1. The remaining two reflections with $\Delta 4/\sqrt{w}$ were on the 8th and 9th l_F levels, where the instrument and crystal setting inaccuracies are more significant (cf. sections 2.2 and 2.3).

When these 10 reflections were given zero weight, $\sum w \Delta^2$ dropped by 16% and after six more cycles reached its minimum value of 1286 on an absolute scale. R = 0.0878, m-n = 1246-79 = 1167 and $\sum w \Delta^2/(m-n) = 1.102$.

Table B at the end of the thesis lists the $|F_0|$'s with the phases obtained from this final calculation of structure factors, and the resulting electron density map is shown in figure 4.6.1.

4.7 Molecular geometry

The atomic coordinates of the final model are given in table 4.7.1 as fractions of the reduced cell edges, together with their standard deviations. Final anisotropic B_{ij}'s are listed in table 4.7.2 and bond lengths and angles and their standard deviations in 4.7.3 and 4.7.4. A perspective view of the structure along the b axis is shown in figure 4.7.1, drawn by PAMOLE.

A molecular scan by A5 gave the angle Si-N-C3 as 180° and the shortest intermolecular distances (<3.5Å) as (in Å): C11-H3 C11-H4 C11-H5 C12-H3 C12-H4 C12-H5 C5-H2 C2-H5 H2-H5 3.199 3.122 3.398 3.196 3.185 3.379 3.446 3.457 2.437

Intermolecular distances are generally larger than those of SiF_h , 2Py, and the looser packing of SiCl_h , 2Py enables the pyridine

Table 4.7.3

Bond	Length (Å)	σ(Å)
S1-C11	2.186	0.001
Si-C12	2.192	0.002
S1-N	1.966	0.007
N-C1	1.355	0.007
C1-C2	1.363	0.015
C2-C 3	1.370	0.013
C3-C4	1.381	0.009
C4-C5	1.351	0.014
C5-N	1.356	0.010
C1-H1	1.014	
C2-H2	1.027	
C3-H3	1,006	
C4-H4	1.006	
C5-H5	1.015	

Table 4.7.4

Intramolecular h	cond angles (°)	<u>δ(°)</u>
C11-S1-C12	91.0	0.1
C11-S1-N	90.0	0.1
C12-S1-N	90.5	0.2
S1-N-C1	120.9	0.6
S1-N-C5	121.2	0.4
C1-N-C5	118.0	0.8
N-C1-C2	122.4	0.8
C1-C2-C3	119.3	0.6
C2-C3-C4	118.4	0.9
C3-C4-C5	120.6	0.7
C4-C5-N	121.3	0.6
N-C1-H1	118.9	
C2-C1-H1	118.8	
C1-C2-H2	119.3	
C3-C2-H2	121.4	
C2-C3-H3	121.0	
C4-C3-H3	120.6	
C3-C4-H4	119.2	
C5-C4-H4	120.1	
C4-C5-H5	117.2	
N-C5-H5	121.5	

ring to lie in a position equidistant from Cl1 and Cl2, unlike SiF₄,2Py (see section 3.7). By dropping perpendiculars from Cl and C2 onto the line Cl1-Cl2, it was calculated that the pyridine ring bisects the angle Cl1-Si-Cl2 to within 20'.

The best plane lx' + my' + nz' = p through C1-C5 was found as described in Appendix D with respect to orthogonal axes x', y', z' chosen according to Appendix C. l = -0.19482, m = -0.45491, n = +0.86897 and p = +0.02137Å. Atomic deviations from this plane are (in Å):

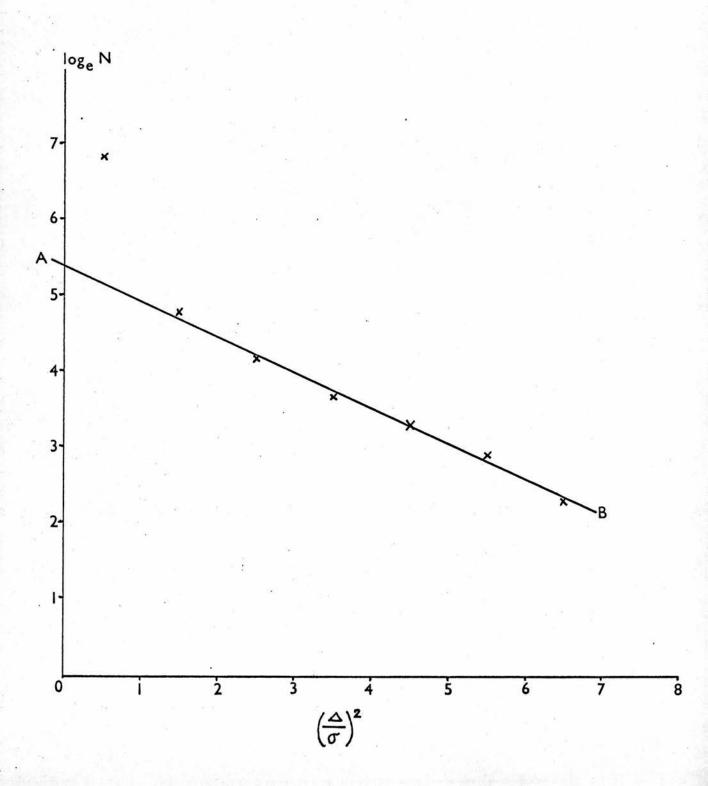
Thus, as with SiF₁₄,2Py the structure is planar, and it is confirmed that the perpendicular distances of Cl1 and Cl2 from the pyridine plane are insignificantly different.

The plane Si-Cl1-Cl2 was calculated :

$$-0.77127x' - 0.47381y' - 0.42503z' = 0$$

The angle between it and the best fit pyridine plane given above is 90°12'. The pyridine plane has the following intercept equation with respect to the reduced triclinic cell.

$$\frac{x}{9.41569} - \frac{y}{0.04698} + \frac{z}{0.02137} = 1$$



The pyridine rings are layered, almost perpendicular to c of the reduced cell, with separation $\approx \frac{1}{2}c = 3.58\text{Å}$; since $\beta = 90^{\circ}$, the pyridine planes are also approximately parallel to <u>a</u> (cf. large intercept on a, 9.416Å, of the best fit pyridine plane given above.)

The absoluteness of the weights applied to the $|F_0|$ values was checked as described in section 3.7 for SiF_4 ,2Py, and gave the results shown in figure 4.7.2. Best least squares straight line AB has intercept $log_e A = 5.39$ and slope = -B = -0.47, which is almost the theoretical value of $\frac{1}{2}$ for a normal distribution. The first point deviates from this Gaussian curve as in figure 3.7.2 for SiF_4 ,2Py, and probably for the same reason given in section 3.7.4.8 Conclusions

A comparison of the final structural models for SiF_{μ} , 2Py and $SiCl_{\mu}$, 2Py indicates that the pyridine ring geometry is the same, within the listed standard deviations (cf. tables 3.7.3, 3.7.4 and 4.7.3, 4.7.4). Mean Si-F and Si-Cl bonds are 1.65 and 2.19Å. Standard deviations of equivalent atomic coordinates, bond lengths and angles are larger for the chloride complex, as are $\sum_{i} \sqrt{\frac{2}{m-1}}$ and R. Both compounds are layered in the crystal lattice, with approximately equal separation between the pyridine rings (~3.6Å). $SiCl_{\mu}$, 2Py temperature factors are lower (cf. tables 3.7.2 and 4.7.2) and hence Fourier peaks are higher (cf. figures 3.6.1 and 4.6.1) due to less thermal vibration.

The molecular orientation in the reduced triclinic cell is not identical for both compounds, and a comparison of the reduced cells' parameters (\underline{a} of $\operatorname{SiF}_{\underline{h}}$, $\operatorname{2Py} = \underline{c}$ of $\operatorname{SiCl}_{\underline{h}}$, $\operatorname{2Py}$) confirms that they are not isomorphous. Another pair of primitive triclinic cells may exist, in which both molecules have identical orientations, and if these were identified from appropriate vector transformations, then a comparison could be made between them to test for isomorphism. It was decided however that this problem was not of sufficient importance to pursue further.

The structure of SiCl₄, 2Py has been shown to be molecular with a centrosymmetric trans configuration. This result contradicts the stereochemistry assigned from infrared vibrational analysis.

The infrared spectra of addition compounds of the type

MH4L2 where M is silicon, germanium or tin, H = halogen and L is
a monodentate ligand, have been interpreted using a simplified

model in which the coupling between M-H and pyridine vibrations

was neglected. For a trans adduct only one fundamental M-H

stretching vibration of perturbed planar MH4 was predicted. By

considering the MH4 residue of a cis isomer

distorted as shown due to the addition of the
ligands, and using group theory arguments, a

closely spaced triplet of i.r. absorptions was predicted with a

weaker vibration at lower frequency (all M-H stretching vibrations).

The infrared spectrum of SiCl₄,2Py followed this pattern and also was similar to the spectra of bidentate ligand adducts of silicon tetrachloride, which can exist only in a cis configuration. The necessary distortion of a trans isomer to produce the observed SiCl₄,2Py absorption bands was considered to be too great.

Crystal-field effects, causing separation of degenerate peaks, are one of the possible reasons for misinterpretation of absorption spectra, listed by Beattie et al (1963). However this cannot be the case with SiCl₄,2Py since it was shown in section 4.7 that the pyridine rings are completely symmetric with respect to the chlorines. The packing symmetry of the fluoride adduct is lowered however due to repulsion between intermolecular close contacts (see sections 3.7 and 3.11), but this has not caused any resolution of the Si-F stretching band.

The crystallographic results reported in this thesis clearly show that the assumption that the MH₄ unit can be treated separately when interpreting i.r. spectra is not generally valid. In view of these results, recent force constant calculations (Beattie, Gilson and Ozin, 1968) using the whole SiCl₄,2Py molecule have indicated how the i.r. spectrum with three strong lines in the M-H stretching region can arise for a trans isomer.

Further pyridine adducts of tetrahalides of Group IV metals, whose stereochemistry has been deduced from their solid state spectra on the basis of the simple model discussed above are:

GeF ₄ ,2Py	trans	(Ozin, 1967)
SnF ₄ ,2Py	cis	(Muetterties, 1960)
GeCl ₄ ,2Py	trans	(Hulme et al, 1960; Beattie et al, 1963)
SnCl ₄ ,2Py	trans	(Beattie et al, 1963)
	cis	(Clark and Wilkins, 1966)
SiBr ₄ ,2Py	cis	(Beattie et al, 1964)
SnBr ₄ ,2Py	cis	(Clark and Wilkins, 1966)

The cis assignments obviously require revision.

Preliminary x-ray investigations of $SnCl_{4}$, 2Py and $SnBr_{4}$, 2Py have subsequently been carried out in this laboratory and confirm (Clark and Wilkins, 1966) that they are isomorphous in monoclinic space group C2/m. A two dimensional Fourier synthesis indicated a trans configuration for the chloride complex and hence also for the bromide. Miss M. Milne, Chemistry Department, University of Southampton is analysing the i.r. vibrations of $SnBr_{4}$, 2Py in more detail utilising the whole molecule, and has calculated that the observed complex spectrum is consistent with a trans stereochemistry.

None of the octahedral complexes $MH_{\downarrow}L_{2}$ so far studied in any detail by x-ray diffraction techniques has been a cis isomer, and further x-ray investigations would be desirable to confirm that the whole series is trans.

5. AN X-RAY DIFFRACTION STUDY OF MERCURY DIBENZYL

5.1 Introduction

The structural chemistry of mercury compounds has been recently reviewed (Grdenić, 1965) and it is apparent that there is a lack of structural data for the di-alkyl and di-aryl derivatives, although recent data presented at the 7th International Congress of Crystallography has improved the situation (Pakhomov, 1966).

Several mercury dialkyl and diaryl compounds were available and mercury dibenzyl, $({}^{\circ}_{6}{}^{\circ}_{5}.{}^{\circ}_{6}{}^{\circ}_{2})_{2}{}^{\circ}_{1}{}^{\circ}_{1}$, was selected for structural investigation since some additional data concerning bond energies had been determined kinetically for this compound (Calvert, 1958). From the unusually low mercury-carbon bond dissociation energy it was anticipated that these bonds should be especially long.

5.2 Description of crystals

Pure mercury dibenzyl had been made by D. Calvert using the method of Hein and Wagler (1925) and was recrystallised from spectroscopic grade iso-octane under vacuum conditions. Colourless needle crystals of approximately rectangular cross-section were obtained. On prolonged exposure to x-rays it became apparent that the crystal was decomposing, a black deposit of free mercury being observed in those parts of the crystal exposed to the beam. A similar decomposition was also detected on exposure of the crystal to visible light.

5.3 Unit cell dimensions and space group

Rotation, Weissenberg and precession photographs indicated that the structure was tetragonal with a = 12.91 ± 0.02 Å and c = 7.08 ± 0.03 Å, along the needle axis of the crystal. Measured density = 2.19 ± 0.03 gm/cm³. Calculated density = 2.155 ± 0.015 gm/cm³ for four molecules in the unit cell.

The following conditions limiting possible reflections were noted: hk0: h + k = 2n; 001: l = 2n. This suggested $P4_2/n$ as the space group with eight symmetrically related positions in the unit cell. Therefore one half of the molecule is the asymmetric unit and the mercury atoms must be at special positions. It was observed that those lines with l = 2n were very much stronger than those with l = 2n + 1. Applied to space group $P4_2/n$, this special condition gives the equivalent mercury positions as $\frac{1}{2}(3/4,1/4,z; 3/4,1/4,1/2+z)$ when the unit cell origin is at the centre of symmetry.

Further strong reflections due to diffraction by the Hg atoms were: h + k + 1/2 = 2n for 1 even, which implies near bodycentring of the Hg atoms in terms of c = 3.54Å, with equivalent positions (x,y,z) and (x + 1/2, y + 1/2, z + 1/4) in the unit cell. Combining the two sets of equivalent positions gives the following mercury atomic coordinates, where the z coordinate may only be a close approximation: $\pm (3/4,1/4,3/8; 3/4,1/4,7/8)$.

5.4 Absorption

The linear absorption coefficient $\mu = \rho \sum p_i(\mu/\rho)_i$ where ρ = density of crystal

 p_i = fractional weight of element i in the unit cell $(\mu/\rho)_i$ = mass absorption coefficient of atom i for the radiation used.

Therefore for MDB, $\mu = \rho [p_{Hg}(\mu/\rho)_{Hg} + p_{C}(\mu/\rho)_{C} + p_{H}(\mu/\rho)_{H}]$ = 133.5 cm⁻¹ for MoKa radiation.

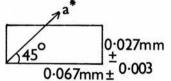
Thus the mercury atoms in crystals of MDB absorb x-rays to a great extent and in order that comparatively simple absorption corrections could be applied, initial attempts were made to grind crystal surfaces to a cylindrical or spherical form using a modified version of Bond's method (1951) but these were unsuccessful.

To minimise absorption effects, very small crystals with cross-section as square as possible were selected for alignment on the linear diffractometer as described in section 2.3 (case A) with c along the goniometer axis. However, several initial crystals had to be abandoned because very variable peak counts for 001 reflections were obtained when the crystal was rotated through 360° (see section 2.3). Since the best available crystal still gave significant fluctuations, corrections for x-ray absorption were necessary and were applied to diffracted intensities using a

programme written by Dr. A.J. Cole of the Computing Laboratory.

The view along the needle axis (\underline{c}) of the crystal was determined as

For each reflection recorded by the diffractometer, the positions of the



crystal and detector, ϕ and Υ , with respect to the incident x-ray beam (see figure 2.1.2 and section 2.1) are found from the formulae:

$$\gamma = 2\sin^{-1}[(h^2 + k^2)^{\frac{1}{2}}a*/2\cos\mu]$$

$$\phi = \frac{\gamma}{2} + 90^{\circ} - \tan^{-1}(k/h)$$

for a* initially parallel to the incident beam (Buerger, 1960).

Assuming a rectangular crystal of infinite length the absorption programme calculated the path length rof x-rays through the crystal for each diffraction maximum, and evaluated the corrected intensity Ie^{µr}.

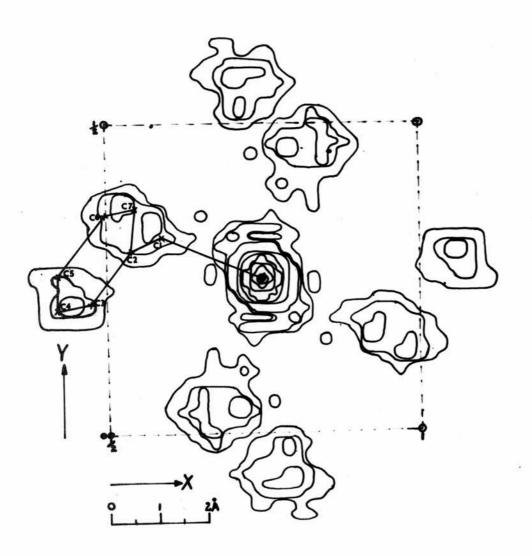
5.5 Two dimensional analysis

MDB was the first compound studied, using the linear diffractometer, and the very considerable instrumental difficulties discussed in section 2.2 had not in some cases been discovered and in others resolved. Several attempts were made to measure accurately the intensities of diffracted MoKA radiation in one quadrant of the copper sphere as described in section 2.4. a* = b* = 0.0551 r.l.u. c* = 0.1004 r.l.u. From preliminary experiments, a low generator current was chosen and data were collected quickly in order to minimise radiation damage to the crystal. Zero level intensities

Figure 5.5.1

Projection of electron density in MDB, for two of the four molecules in the unit cell.

Contours at equal but arbitrary intervals.



were satisfactory and gave the results reported in this section.

X-ray form-factors for mercury have been calculated recently from relativistic Hartree-Fock atomic fields (Doyle and Turner, 1967).

hkO data were processed as usual and structure factor calculations were computed using the mercury x and y coordinates determined from space group considerations alone. Several cycles of refinement of the scale and isotropic temperature factor reduced R to 0.146, when a two dimensional Fourier synthesis was computed with the $|F_0|$ values and calculated phases (0 or π). This is shown in figure 5.5.1. Using a model of the molecule, only one possible molecular orientation was found which fitted the projection of electron density and is shown on figure 5.5.1. The four molecules in the unit cell appeared to pack with two Hg atoms on each four-fold screw axis, $\frac{1}{2}$ cell apart, and the attached benzyl groups stacked one above the other, all having the same orientation but each successively rotated through 90° .

in the asymmetric unit and all atoms were assigned isotropic B values. Four SFLS cycles to refine the 23 parameters reduced coordinate shifts to the 4th decimal place and R to a minimum at 0.084. The final fractional x and y coordinates and B's are given in table 5.5.1. Another two dimensional electron density map was computed with the last F₀ values but the resolution of the benzyl group was no better than in figure 5.5.1 This lack of

Table 5.5.1

Atom	<u>x/a</u>	<u> 3/p</u>	<u>B</u>	z/c
Hg	0.7500	0.2500	4.47	0.36
C1	0.5882	0.3177	5.74	0.36
C2	0.5391	0.2969	3.81	0.51
C 3	0.4741	0.2135	3.74	0.54
C4	0.4186	0.2014	3 .39	0.69
C 5	0.4209	0.2596	4.64	0.87
c 6	0.4976	0.3516	5.12	0.86
C 7	0.5457	0.3663	4.07	0.67

improvement, in spite of including the carbons, was a result of the excessive heaviness of the mercury (Z = 80). Most of the magnitudes and phases of the overall structure factors were equal to those calculated from the mercury position alone, and the contributions of the lighter carbons to the F_c 's were as small as the experimental error involved in the measurement of intensities. The Hg-C1 bond length was estimated as 2.26Å. No further refinement could be achieved using only zero level intensity data.

5.6 Three dimensional analysis

An investigation of the three dimensional structure of MDB was undertaken with intensities from levels $1 = 0 \rightarrow 6$, prior to discovery of instrument fault (4) (section 2.2). Since considerable time was spent attempting to analyse the data, which were subsequently found to be erroneous for 1>0, a brief summary of the methods employed is given.

The first problem considered was to determine if the Hg atom of the asymmetric unit was situated exactly at z=3/8 i.e. was the condition for diffraction by mercury atoms, h+k+1/2=2n for 1 even, exact or only a close approximation. The l=2n+1 diffraction maxima were receiving no contribution from the Hg atoms from symmetry considerations (see section 5.3). Using different parts of the observed data for SFLS calculations and including only the Hg, R was reduced to a minimum in each case given below.

Data	Hg position	<u>R</u>
h + k + 1/2 = 2n, for $1 = 2n$	0.75, 0.25, 0.375	0.110
all $l = 2n$	0.75, 0.25, 0.3546	0.103
h + k + 1/2 = 2n, for $1 = 2n$	0.75, 0.25, 0.3546	0.093
h + k + 1/2 = 2n + 1, for $1 = 2n + 1$	0.75, 0.25, 0.3546	0.161

It was therefore concluded that Hg z-coordinate was not exactly 3/8. This was borne out by the observation from photographs that the intensity difference between h + k + 1/2 = 2n and 2n + 1 reflections (for 1 even) decreased with increasing sine. Calculations, with the structure factor equation for P4/n and Hg not at z = 3/8, showed that as 1 increased, the mercury contribution to h + k + 1/2 = 2n + 1 reflections increased, and to h + k + 1/2 = 2n reflections decreased.

A three dimensional difference Fourier synthesis was computed with $(F_{\rm o}-F_{\rm c})$ for all 1=2n reflections, where $F_{\rm c}$ was calculated from the Hg position given above. A difference Fourier eliminated the diffraction ripple in a Fourier synthesis surrounding the heavy Hg atomic peak due to series termination. This could have affected the positions of the light atoms and especially those nearest the heavy atom.

All 7 carbons were located; the x and y coordinates obtained were equal within 0.01 to those values found from the electron density projection and given in table 5.5.1. The z coordinates obtained are given in table 5.5.1. Using 653 reflections with

intensity estimates \geqslant 100 counts from all levels 1 = 0-6 least squares refinement of the atomic positions and B values was attempted. R was reduced to 0.09 but the geometry of the benzene ring was poor with large standard deviations (\sim 0.1Å for bond lengths and \sim 6° for bond angles). This situation could not be improved because of the poor quality data and the dominance of the structure by the mercury. Additional difficulties were due to the Hg occupying a special position, and the 1 = 2n + 1 intensities being so weak with a high measurement inaccuracy. The R factor with the carbons included was insignificantly different from the value obtained using only Hg. Any Fourier synthesis would tend to show only the Hg atom clearly; carbon atoms would be seen with difficulty and their positions would always be inaccurate.

Photographic techniques using a Nonius integrating precession camera were adopted for more accurate determination of intensities, and initial films were measured. However photographic measurements were terminated in view of the results deduced from the space group considerations outlined in the following section.

5.7 Space group considerations

On the basis of space group $P4_2/n$, l=2n reflections are receiving contributions from all atoms in the molecule and intensities with 1 odd from only the benzyl groups. Hence the expected ratio of intensities is $\sum_{\frac{1}{2}Hg,C1-C7} z^2 / \sum_{C1-C7} z^2 = 7.3/1.$

But the ratio observed was $\sim 30/1$ and possible reasons for this anomaly were considered. Pseudo-symmetry within the asymmetric unit could result in carbon contributions to 1 = 2n + 1 levels very nearly cancelling, causing those intensities to be very small. The benzene ring of the asymmetric unit is situated with its centre at approximately (1/2,1/4,1/2), or equivalently (0,1/4,1/2) (see table 5.5.1 and figure 5.5.1), which are pseudo-special positions.

For space group P4/n with origin at 1 there are four expressions for A (Vol. I, International Tables for X-ray Crystallography) for the following four combinations of indices:

(i) h + k = 2n (ii) h + k = 2n (iii) h + k = 2n+1 (iv) h + k = 2n+1k + 1 = 2n k + 1 = 2n+1 k + 1 = 2n k + 1 = 2n+1

The plane of the benzene ring is approximately parallel to c with a mirror plane through its centre almost parallel to the ab plane. Expressions (iii) and (iv) for A contain the factor $\sin 2\pi lz$, and hence with a mirror plane at z=0 or 1/2, vanish for 1 odd and even, considering carbons C2-C7. An inversion centre was assumed for the benzene ring at (0,1/4,1/2); trigonometrical manipulation of the structure factor equations for cases (i) and (ii) in conjunction with possible combinations of h, k and 1, gave the result that expression (i) equalled zero for l=2n+1, but did not vanish for l=2n, and vice versa for expression (ii). Thus considering the atomic positions of C2-C7 of the benzyl group

their contribution to F for P4/n would be small for all 1 values except where h, k, l = 2n and h, k = 2n, l = 2n + 1. These calculations therefore showed no reason why 1 odd levels were so much weaker than 1 even levels.

It was concluded that the unit cell has $c=3.54\text{\AA}$ and contains two molecules, with stacking faults causing the appearance of very weak intermediate 1 layer lines and pseudo-tetragonal symmetry. Since tetragonal symmetry can no longer be obeyed, the space group must be monoclinic with c the unique axis, $\gamma=90^{\circ}$ and systematic absences on hkO, h+k=2n+1.

New axes (subscript m for monoclinic) were chosen as shown, looking down c.

$$\gamma_{m} = 135^{\circ}$$
 $\gamma_{m}^{*} = 45^{\circ}$

$$\underline{a}_{m} = \underline{a};$$

$$\underline{b}_{m} = \underline{b} - \underline{a};$$

$$\underline{c}_{m} = \underline{c}$$

$$h_{m} = h;$$

$$k_{m} = k - h;$$

$$1_{m} = 1$$

Conditions for reflection are now: hkO; k = 2n. The space group is therefore P2/b with four symmetrically related units, equivalent positions \pm (x,y,z; \bar{x} , 1/2 - y, z) and half the MDB molecule as the asymmetric unit. The mercury atoms lie on special positions (0,1/4,z) and $(0,3/4,\bar{z})$.

Strong reflections receiving most of the mercury contribution are k + 1 = 2n, and hence the Hg's are nearly A-faced centred with equivalent positions (x,y,z) and (x,y + 1/2, z + 1/2). Hg atomic

positions are therefore $(0,1/4,\sim 3/4)$ and $(0,3/4,\sim 1/4)$ which are equivalent to (3/4,1/4,3/8) and (1/4,3/4,1/8) with respect to the original tetragonal unit cell (cf. section 5.3).

It seems likely that the crystals of MDB exist as blocks of single crystals of space group P2/b. These blocks are intermittently turned through 90° about the needle axis c, giving rise to an apparent space group P4/n and the two benzyl group orientations seen in figure 5.5.1. Isolation of any one block to determine the true atomic locations would be impossible. In addition, due to radiation damage to the crystal, any accurate determination of intensities would require one crystal per level, which would involve careful correlation between each level of intensity data, especially in view of the high absorption of x-rays.

An accurate determination of the detailed structure of MDB would be difficult, if not impossible, due to the reasons given above, and it was decided that the relative unimportance of the compound did not justify the length of time necessary. The required estimate of the Hg-C bond length had been obtained and the study undertaken so far had provided considerable experience, both experimental and theoretical, for the subsequent structure investigations reported in Chapters 3 and 4.

				В	LOOP2
BEGIN		CARD-79	TOOR		OUT3,ZERO7
	SF	CARD-7	LOOP3		OUT3-3,ZERO7
	SF	CARD-14			OUT3-6,ZERO7
	SF	CARD-21		TD	. [1] [1] [1] [1] [1] [1] [1] [1] [1] [1]
	SF	CARD-28		TF	OUT2+2,H
	SF	CARD-35		CF	OUT2+1
	SF	CARD-42		MF	OUT2+3,OUT2+2
	SF	CARD-45		TF	OUT2+5,K
	SF	CARD-48		CF	OUT2+4
	SF	CARD-51		MF	OUT2+6,OUT2+5
	MF	CARD-50, CARD-49		TF	OUT2+8,L
	MF	CARD-47, CARD-46		CF	OUT2+7
	MF	CARD-44, CARD-43		MF	OUT2+9,OUT2+8
LOOP1	TF	H, CARD-50		SF	INTS-5
	TF	K, CARD-47		TF	OUT5, INTS
	TF	L,CARD-44		CF	INTS-5
	TF	INTS, ZERO7		CF	OUT4+1
L00P2	NOP			MF	OUT5, INTS
BACK	Α	INTS, CARD-30		SF	CARD-58
	Α	INTS, CARD-16		TF	OUT1, CARD-54
	Α	INTS, CARD-2		CF	OUT1 -4
	S	INTS, CARD-37		BNF	NFLAG, OUT5
	S	INTS, CARD-23		TF	OUT5, ZERO7-1
	S	INTS, CARD-9	NFLAG	WNCD	OUT1-4
		CARD-79		PRN	OUT1-4
	SF	CARD-7		C	TEST,H
	SF	CARD-14		BNZ	LOOP1
	SF	CARD-21		H	
	SF	CARD-28	CARD	DS	80
	SF	CARD-35	H	DS	2
	SF	CARD-42	K	DS	2
	SF	CARD-45	L	DS	2
	SF	CARD-48	INTS	DS	7
	SF	CARD-51	ZERO7	DC	7,0
	MF	CARD-50, CARD-49	OUT1	DS	5
	MF	CARD-47, CARD-46	OUT2	DNB	5
	MF	CARD-44, CARD-43	OUT3	DS	9
	C	H, CARD-50	OUT4	DNB	2
	BNZ	LOOP3	OUT5		6
	C	K,CARD-47	OUT6		26
	BNZ	LOOP3	OUT7		27
	C	L,CARD-44	RECRE		1,@
		LOOP3	TEST	DC	2,99
	BNZ	LOUP	a called de		BEGIN
				22412	

APPENDIX A Computer Programmes

The following programmes were used on an IBM 1620 Model II computer, which has 60,000 digits of core store, card input and output, line printer, digital plotter and three disk drives.

All programmes were written by the author in symbolic programming system language (SPS), except A2-A5 which are Computing Department library programmes.

A.1 Data processing for linear diffractometer

For each pair of oscillation cycles using balanced filters, a card is obtained from the linear diffractometer IBM card punch in the form:

where x represents a digit from 0 to 9.

The net integrated intensity $I(hkl) = [N_1 - (b_1 + b_1')] - [N_2 - (b_2 + b_2')]$ is calculated and, if more than one card is present for all reflections, the intensities are added together for each reflection. The card output, suitable for input to A2, is of the form:

A.2 Intensity data processing programme by E.J. Gabe

This programme reduces the intensity estimates I(hkl) obtained from A1 for linear diffractometer data or measured as

described in section 2.6 from equi-inclination Weissenberg photographs, to a consistent set of $|F_0|^2$ and $|F_0|$ values by applying appropriate scale and Lp^{-1} factors. Reciprocal cell parameters are supplied in directive cards together with $\sin^2\mu$ and a scale factor for each equi-inclination level of data. For each reflection the card output is in the format:

A.3 Structure factor and least squares programme (SFIS)

Written by G.A. Mair the programme is in three parts. Part 1, the input routine, interprets a series of directives and stores the input F data (from A2) on to disk. Part 2 calculates structure factors F_0 according to equations (3) (1.1) and (7) or (8) (1.3) and accumulates the least squares totals. The final part calculates parameter shifts from the least squares totals (see 1.4), the new parameters, $\sum_{w} \Delta^2$ and R. Also calculated are positional variances, covariances, new bond lengths and angles and their standard deviations from the equations given in section 1.6. Atoms may be given either isotropic or anisotropic temperature factors, a mixture being permissible, and not all the atoms included in the structure factors calculation need be included in the least squares refinement procedure. Structure factors F are stored on disk and may be printed and/or punched together with F, $A = |F| \cos \phi$ and $B = |F| \sin \phi$.

Some of the directive cards required are worth mentioning. The "unit cell" directive requires the six R_{ij} values for the cell, calculated from the formula:

$$\sin^{2}\theta = (\lambda^{2}/4) \left| d*(hkl) \right|^{2} (d*(hkl) \text{ in } A^{-1})$$

$$= (\lambda^{2}/4) (h^{2}a*^{2}+k^{2}b*^{2}+l^{2}c*^{2}+2klb*c*cos\alpha*+2hla*c*cos\beta*+2hka*b*cos\gamma*)$$

$$= h^{2}R_{11} + k^{2}R_{22} + l^{2}R_{33} + klR_{23} + hlR_{13} + hkR_{23}$$

Values of atomic scattering factor f_o , for each atom included in the F_c calculations, must be given in the "formfactors" directive at intervals of $\sin^2\theta$. Mair has already calculated these for some elements using $CuK\bar{\alpha}$ wavelength from the values of f_o given at intervals of $\sin\theta/\lambda$ in International Tables, Vol. III. Other atomic formfactors required were read off a graph of $f_o v$. $\sin^2\theta$ (calculated using $CuK\bar{\alpha}$ radiation), and thus in the above formula for the R_{ij} 's, the wavelength λ used, and given in the directive, was 1.5418 $\hat{\alpha}$ even though Mo was used for all data collection.

Also given in directive cards are the fractional atomic coordinates, temperature factors, the lattice parameters and equivalent positions of the unit cell and the scale factor for the F_o values to put them on the same scale as the F_c 's. One of four weighting schemes could be used. For photographic data and initial diffractometer data cycles the scheme given by equation (11), section 1.5 was used, and for the final stages of structure refinement with diffractometer data, equation (12). This latter scheme requires $\sqrt{w(hkl)}$ punched in columns 79 and 80 of the $|F_o|$ data cards as 0.xx.

The number n of parameters in the least squares calculation, for no atoms in special positions, is: 9 x (no. of atoms with anisotropic B_{ij}'s) + 4 x (no. of atoms with isotropic B) + 1 (the scale factor). The fudge factor (section 1.4) was normally chosen as 0.5, increasing to 0.8 as refinement neared completion.

A.4 Fourier programme by G.A. Mair

A three dimensional Fourier synthesis is calculated using the data output from A3. The programme may also be used to compute a Patterson synthesis from the $|F_0|^2$ output of A2, but extra care must be taken with the directives.

The input data cards are sorted so that for sections of x, y or z constant (x_3) , h, k or l respectively is the most rapidly moving index (h_3) . On each section, the horizontal direction (x_1) has its corresponding index h_1 least rapidly moving.

The equation for the electron density or Patterson function (equation (2) or (4) in section 1.1) must be expanded for the appropriate space group to give a sum of terms of the form: $\frac{C}{V}(\frac{1}{2} R_{h_1 h_2 h_3} + \frac{1}{2} R_{h_1 h_2 h_3} + \frac{1}{2}$

```
P(u,v,w) = \frac{1}{V} \sum_{n=0}^{\infty} [F(hk1)]^{2} \cos 2\pi (hu + kv + 1w)
                 = \frac{2}{V} \sum_{hkl=0}^{+\infty} |F(hkl)|^2 \cos 2\pi (hu + kv + lw)
= \frac{2}{V} \sum_{h=0}^{+\infty} \sum_{h=0}^{+\infty} \left[ \left[ F(hk1) \right]^2 + \left[ F(hk1) \right]^2 + \left[ F(hk1) \right]^2 \right] \cos 2\pi h u \cos 2\pi k v \cos 2\pi l w
                                                    ]sin2πhusin2πkvcos2πlw
          + [- + - + ]sin2πhucos2πkvsin2πlw
For P1, \rho(xyz) = \frac{1}{V} \sum_{hkl=-\infty}^{+\infty} |F(hkl)| \cos[2\pi(hx+ky+lz)-\phi(hkl)]
                   = \frac{2}{V} \sum_{h|x|=0}^{+\infty} |F(hk1)| \cos[2\pi(hx+ky+1z)-\phi(hk1)]
                             + |F(\bar{h}kl)|\cos[2\pi(-hx+ky+lz)-\phi(\bar{h}kl)]
                             + |F(h\bar{k}1)| \cos[2\pi(hx-ky+1z)-\phi(h\bar{k}1)]
                             + |F(hk\bar{l})|\cos[2\pi(hx+ky-lz)-\phi(hk\bar{l})]
= \frac{2}{V} \sum_{hkl=0}^{+\infty} [A(hkl) + A(hkl) + A(hkl) + A(hkl)] \cos 2\pi h \times \cos 2\pi k y \cos 2\pi l z
           +[- + - + ]s c
           +[B(hkl)-B(\bar{h}kl)+B(h\bar{k}l)+B(hk\bar{l})]s c
           +[+ + - + ]c
           +[+ + + - ]c ~~c
           A(hkl) = |F_{Q}(hkl)| \cos\phi(hkl) \qquad B(hkl) = |F_{Q}|\sin\phi(hkl)
```

The number of terms in the expansion of P(uvw) or $\rho(xyz)$ is given in the directives and also for each term the signs of the R coefficients (F_0^2 for a Patterson and A and B for a Fourier) together with the trig factors. The R's are chosen to be F_0^2 , F_0 , A or B according to the setting of further directives. Mesh intervals must be integrals of 1/240 of the cell edges, and for all syntheses intervals of 1/30 of the cell edges were chosen.

A.5 Scan of bonds, angles and intermolecular distances by F.R. Ahmed

This programme carries out scans of intramolecular bond lengths and angles and of intermolecular distances, given the fractional atomic coordinates in the asymmetric unit of the unit cell.

During structure refinement the latest SFLS card output from A3 is sorted into equi-inclination levels, and at the end of each level a blank card is inserted. Using the whole deck of cards as input, A6 evaluates \(\sum_{0} \) and \(\sum_{0} \) for each level and prints the results as \(\sum_{0} \

Programmes 7 - 11 were written in SPS by the author to find the absolute weights w(h) (equation (12), 1.5), for reflections measured on the linear diffractometer, and to put them into suitable format for input to A3. Decimal points are not punched and all programmes require a blank card at the end of the input data.

A.7 Using the linear diffractometer data cards as input (see A1)

```
A7
                                                   A6
              80
                                                   80
         DS
                                    CARD
                                              DS
CARD
              6
                                                   8
         DS
                                              DS
B
                                    FO
                                                   8
         DC
              50,0
                                    FC
                                              DS
                                                   1,@
         DC
IB
               30,0
                                              DC
         DC
               1,0
                                    ZERO
                                              DC
                                                   8,0
BEGIN
         RNCD CARD-79
                                    START
                                              TF
                                                   FO, ZERO
         SF
              CARD-42
                                              TF
                                                   FC, ZERO
         SF
              CARD-35
                                    BEGIN
                                              RNCD CARD-79
         SF
                                              C
              CARD-28
                                                   ZERO, CARD-53
         SF
                                             BE
              CARD-21
                                                   END
         SF
              CARD-14
                                              A
                                                   FO.CARD-53
         SF
              CARD-7
                                              A
                                                   FC, CARD-43
         CM
              CARD-50,0
                                             B
                                                   BEGIN
         BE
                                              PRN
              END
                                    END
                                                   FO-7
              CARD-37, CARD-23
         A
                                              DEND START
         S
              CARD-37, CARD-16
                                                   8A
         S
              CARD-37, CARD-2
                                                   80
         TF
              B, CARD-37
                                    CARD
                                              DS
         A
              CARD-37, CARD-30
                                                   5,0
                                    NOF
                                              DC
         S
              CARD-37, CARD-9
                                    SIB
                                              DC
                                                   12,0
         S
               CARD-30, CARD-9
                                              DC
                                                   1,0
         S
              CARD-30,B
                                    BEGIN
                                              RNCD CARD-79
         LD
               94, CARD-37
                                              SF
                                                   CARD-49
         D
               89, CARD-30
                                              CM
                                                   CARD-42.0.7
         SF
               87
                                              BE
                                                   END
         AM
               95,5,10
                                              Α
                                                   SIB.CARD-42
         TF
               IB-53,92
                                              MA
                                                   NOF, 1,7
         MF
              CARD-50, CARD-49
                                             В
                                                   BEGIN
         MF
              CARD-47, CARD-46
                                    END
                                              PRN
                                                   NOF-4
         MF
              CARD-44.CARD-43
                                              DEND BEGIN
         SF
               CARD-51
                                                   A9
         SF
              CARD-48
                                                   80
         SF
               CARD-45
                                    CARD
                                              DS
         TF
               IB-68, CARD50
                                    NOF
                                              DC
                                                   5,0
         TF
               IB-65, CARD-47
                                    F02
                                              DC
                                                   12,0
         TF
               IB-62, CARD-44
                                    FOFC2
                                              DC
                                                   10,0
         MF
               IB-67, IB-68
                                              DC
                                                   1,0
         MF
               IB-64, IB-65
                                    BEGIN
                                              RNCD CARD-79
               IB-61, IB-62
         MF
                                              SF
                                                   CARD-57
         CF
               IE-29
                                                   CARD-53,0,7
                                              CM
         CF
               IB-79
                                             BE
                                                   END
         WNCD IB-79
                                             SF
                                                   CARD-47
         PRN
              IB-79
                                              S
                                                   CARD-43, CARD-53
         B
              BEGIN
                                             M
                                                   CARD-53, CARD-53
END
         CALL EXIT
                                             A
                                                   F02,99
         DEND BEGIN
                                             M
                                                   CARD-43, CARD-43
                                             A
                                                   FOFC2.99
                                             MA
                                                   NOF, 1, 7
                                             B
                                                   BEGIN
                                    END
                                             PRN
                                                   NOF-4
                                             DEND BEGIN
```

The input data consists of two cards per reflection, paired on an IBM card sorter. The first card is from the latest SFIS output and the second contains (K/4Lp)[(I+B)/(I-B)] as described above. $c^2 = 0.0xxxxx$ is punched in the appropriate programme card (in the listing given, as 12597 for $SiCl_{\mu}$,2Py). If pairing has been done incorrectly then a checking procedure causes no card to be punched for that reflection, and the \sqrt{w} value for the previous

```
contd.
              A10
              80
CARD1
        DS
                                            TFM
                                                 79,0,7
              80
CARD2
        DS
                                            LDM
                                                 87,10000,7
        DC
              50.0
                                            D
                                                 87.XNPL1
RW
        DC
                                            SF
              30,0
                                                 77
                                                  88,5,10
        DC
              1,0
                                            AM
F02
        DS
              10
                                            TF
                                                 RW-50,87
        DS
              11
                                            CF
                                                 RW-29
Α
XN
        DS
              11
                                            WNCD RW-79
              11
XNPL1
        DS
                                   ERROR
                                            PRN RW-79
XNTEST
        DS
              11
                                            В
                                                 BEGIN
BEGIN
        RNCD CARD1-79
                                   END
                                            CALL EXIT
        CM
              CARD1-53,0,7
                                            DEND BEGIN
        BE
              END
                                                  A11
        MF
              CARD1-68, CARD1-67
              CARD1-65, CARD1-64
                                            DS
                                                  80
        MF
                                   CARD1
                                                  80
              CARD1-62, CARD1-61
                                            DS
        MF
                                   CARD2
              CARD1-53, CARD1-53
                                            DC
                                                  1.0
        M
        TF
              FO2,99
                                   BEGIN
                                            RNCD CARD1-79
        MM
              FO2, 12597,7
                                            CM
                                                  CARD1-50,0,7
                                            BE
        RNCD CARD2-79
                                                  END
        TF
              RW-61, CARD2-61
                                            MM
                                                  CARD1-50,13714,7
        TF
              RW-64, CARD2-64
                                            SF
                                                  87
        TF
              RW-67, CARD2-67
                                            AM
                                                  93,55555,7
                                                  CARD1-68, CARD1-67
              CARD2-62, CARD2-61
        MF
                                            MF
              CARD2-65, CARD2-64
                                                  CARD1-65, CARD1-64
        MF
                                            MF
              CARD2-68.CARD2-67
                                                  CARD1-62, CARD1-61
        MF
                                            MF
              CARD2-68.CARD1-68
        C
                                            RNCD CARD2-79
        BNE
                                                  CARD2-68, CARD2-67
              ERROR
                                            MF
              CARD2-65, CARD1-65
                                                  CARD2-65, CARD2-64
        C
                                            MF
        BNE
                                            MF
                                                  CARD2-62, CARD2-61
              ERROR
                                                  CARD2-68, CARD1-68
              CARD2-62, CARD1-62
                                            C
        C
        BNE
              ERROR
                                            BNE
                                                  ERROR
        Α
              96.CARD2-42
                                            C
                                                  CARD2-65, CARD1-65
        SF
              86
                                            BNE ERROR
              A,96
                                                  CARD2-62, CARD1-62
        TF
                                            C
        TF
              XNPL1,A
                                            BNE
                                                  ERROR
SORT
        TF
              XN, XNPL1
                                            TF
                                                  CARD2.88
        TF
              XNTEST, XNPL1
                                            CF
                                                  CARD2-1
        TFM
                                                  CARD2-67, CARD2-68
              79,0,7
                                            MF
        LD
              92,A
                                            MF
                                                  CARD2-64, CARD2-65
        D
              89,XN
                                                  CARD2-61, CARD2-62
                                            MF
              XN,88
        A
                                            WNCD CARD2-79
        MM
              XN,50,10
                                    ERROR
                                            PRN CARD2-79
        TF
             XNPL1,97
                                                  BEGIN
                                            В
        S
             XNTEST, XNPL1
                                    END
                                            CALL EXIT
        CF
             XNTEST
                                            DEND BEGIN
        CM
             XNTEST.5
        BP
              SQRT
```

correctly paired reflection is repeated on the line printer.

The direct square root operation in SPS requires numbers to be converted to floating point format and to avoid this, Newton's method was used to find the square root. This is an iterative cyclic procedure given by the formula $x_{n+1} = \frac{1}{2}(A/x_n + x_n)$ where A is the number whose square root is required. x is the improved approximation for \sqrt{A} from x_n , which is initially chosen as A. x_{n+1} becomes x_n for the next cycle, and so on until the difference between x_{n+1} and x_n is less than the least significant digit required for w, when the process is terminated. Two paired input cards are again needed for each reflection. The first is w from A10 and the second, the original F input card for A3, which requires w punched as 0.xx on it. This programme multiplies each absolute \sqrt{w} by D = 0.99 $\sqrt{w_{max}}$ and forms a new set of data cards for SFLS calculations, plus a line printer output. D is punched as .xxxxx on a programme card (in the given listing D = 0.13714 for $SiF_h.2Py$). If the input cards have been incorrectly paired then, for that reflection, no card is punched and w appears as 00 on the printer. This programme finds those reflections which have, on an absolute scale, $|\Delta| = |F| - |F| > ss$ where s = 1/w. s was taken as

3 or 4 and is given on a programme card. The input data contains

into the programme. The first card is the latest SFLS output

two paired cards per reflection and a pairing check is incorporated

		A12		A13	contd.
CARD2	DS	80		TF	D2,99
CARD1	DS	80		RNCD	CARD-79
	DC	1,@		M	CARD-50,D
BEGIN		CARD1-79		AM	99,55,10
	CM	CARD1-53,0,7		SF	87
	BE	END		TF	CARD-30,97
	MF	CARD1-68, CARD1-67		AM	CARD-50,5,10
	MF	CARD1-65, CARD1-64		M	CARD-51, CARD-51
	MF	CARD1-62, CARD1-61		AM	94,55555,7
	S	CARD1-53, CARD1-43		TF	W,89
	CF	CARD1 -53		M	W,D2
		CARD2-79		SF	89
	MF	CARD2-68.CARD2-67		TF	CARD-50,99
	MF	CARD2-65, CARD2-64		PRN	CARD-79
	MF	CARD2-62, CARD2-61			CARD-79
	C	CARD2-68, CARD1-68	****	В	BEGIN
	BNE	ERROR	END		EXIT
	C	CARD2-65, CARD1-65		DEND	BEGIN
	BNE	ERROR			A14
	C	CARD2-62, CARD1-62	CARD	no	80
	BNE	ERROR	CARD	DS DC	
	LDM D	92,40000,7	OUTPUT	DC	50,0 3 0,0
	AM	95, CARD2-50 88,5,10	001101	DC	1,0
	S	CARD1-53,87			*+12
	BNP	BEGIN			*+12,1236(A2)
	TFM	CARD1-43,0,7		CF	OUTPUT-79
ERROR	MF	CARD1-67, CARD1-68		CF	OUTPUT-29
	MF	CARD1-64, CARD1-65	BEGIN		CARD-79
	MF	CARD1-61, CARD1-62			*+12,-80(A1)
	PRN	CARD1-79		SM	CARD-56,100,7
	В	BEGIN		BNN	NEXT
END	CALL			SF	OUTPUT+1(A1)
	DEND	BEGIN		AM	OUTPUT+5(A1),1,7
		A 1 7		CF	OUTPUT+1(A1)
		A13		BCXM	BEGIN, -1 (A2)
W	DS	10		В	NEXT+24
D	DS	5	NEXT	BCXM	BEGIN+24,5(A1)
D2	DS	10		В	NEXT - 2h
CARD	DS	80			OUTPUT-79
220-20-20-20-20-	DC	1,@		PRN	
BEGIN		CARD-79			EXIT
		CARD-53,0,7		DEND	BEGIN-48
		END			
		CARD-53, CARD-43			
		D, CARD-53			
	M	CARD-53, CARD-53			

during the final stage of structure refinement using the correct diffractometer data weighting scheme, and the second data card contains absolute \sqrt{w} (from A10). The value of $(\sqrt{\Delta} - s) > 0$ is printed as xxx.xx together with the indices of the reflection in the usual format. A blank card is required at the end of the data.

A.13 The same input data is used for A13 as for A12 and $\sqrt[h]{\Delta}$ and w Δ^2 are evaluated for each reflection. The results are punched and printed with w Δ^2 in cols 20-30 as xxx.xxxxxxx and $\sqrt[h]{\Delta}$ in cols 40-50 as xxx.xxxxxxxx (indices in usual format). A.14 The card output from A13 is used to find the number N of reflections with w Δ^2 values in each of the 16 intervals 0 \rightarrow 0.99, 1 \rightarrow 1.99 up to 15 \rightarrow 15.99 and the values of N are given on the line printer (16 numbers, each of five digits). Index registers are used to modify the addresses of certain instructions and the total number of cards is given in the programme e.g. 1236 for SiCl_h,2Py.

A.15 This programme was written for ${\rm SiCl}_4$,2Py to change the h and k indices (h_L and k_L) on the data cards obtained from the linear diffractometer (see A1) to those of the F cell (h_F and k_F) according to the equations given in section 4.4.

A.16 For SiCl₄,2Py the set of $|F_0|$ values from A2 has F cell indices $(h_F k_F l_F)$ and A16 changes these to reduced cell indices (hkl) by

```
A15
                                              A16 contd.
CARD
         DS
              80
                                             TF
                                                   CARD-62,97
H
         DS
              2
                                             LD
                                                   99, CARD-65
         DS
K
              2
                                             DM
                                                   98,2,10
BEGIN
         RNCD CARD-79
                                             TF
                                                   CARD-68.97
         SF
              CARD-51
                                             LD
                                                   99,K
         SF
              CARD-48
                                             DM
                                                   98,2,10
         SF
              CARD-45
                                             TF
                                                   CARD-65,97
         MF
              CARD-50, CARD-49
                                                   CARD-67, CARD-68
                                             MF
         MF
              CARD-47, CARD-46
                                             MF
                                                   CARD-64, CARD-65
         MF
              CARD-44, CARD-43
                                             BNF
                                                   POS, CARD-62
         TF
              H, CARD-50
                                             CF
                                                   CARD-62
         TF
              K, CARD-47
                                             B
                                                   FINISH
         LD
              99, CARD-44
                                    POS
                                             SF
                                                   CARD-61
         DM
              98,2,10
                                             WNCD CARD-79
                                    FINISH
         BD
              ODD, 99
                                             B
                                                   BEGIN
EVEN
         A
              CARD-50,H
                                    END
                                             CALL EXIT
         CF
              CARD-51
                                             DEND BEGIN
         MF
              CARD-49, CARD-50
                                                   A17
         A
              CARD-47,K
         CF
              CARD-48
                                    CARD
                                                   80
                                             DS
         MF
              CARD-46, CARD-47
                                    K
                                             DS
                                                   2
         CF
              CARD-45
                                    BEGIN
                                             RNCD CARD-79
         MF
              CARD-43, CARD-44
                                             MF
                                                   CARD-68, CARD-67
         В
              FINISH
                                             MF
                                                   CARD-65, CARD-64
ODD
         S
              CARD-50,99
                                             MF
                                                   CARD-62, CARD-61
         S
              CARD-47,99
                                             SF
                                                   CARD-69
         B
              EVEN
                                             SF
                                                   CARD-66
        WNCD CARD-79
FINISH
                                             SF
                                                   CARD-63
        B
              BEGIN
                                             TF
                                                   K, CARD-65
         DEND BEGIN
                                                   CARD-65, CARD-68
                                             TF
                                             A
                                                   CARD-68, CARD-62
              A16
                                                   CARD-68, CARD-62
                                             A
              80
CARD
         DS
                                             A
                                                   CARD-68,K
K
              2
         DS
                                             TF
                                                   CARD-62, CARD-65
BEGIN
         RNCD CARD-79
                                                   CARD-65,K
                                             S
         SF
              CARD-49
                                             A
                                                   CARD-62,K
         CM
              CARD-42,0,7
                                             CF
                                                   CARD-69
        BE
              EMD
                                             CF
                                                   CARD-66
              CARD-68, CARD-67
         MF
                                             CF
                                                   CARD-65
        MF
              CARD-65, CARD-64
                                             MF
                                                   CARD-61, CARD-62
        MF
              CARD-62, CARD-61
                                                   CARD-64, CARD-65
                                             MF
        TF
              K, CARD-65
                                             BNF
                                                   POS, CARD-68
              CARD-68, CARD-62
        Α
                                             CF
                                                   CARD-68
              CARD-65, CARD-62
        Α
                                             \mathbf{B}
                                                   FINISH
        S
              CARD-62.K
                                    POS
                                             SF
                                                   CARD-67
        TF
              K, CARD-62
                                    FINISH
                                             WNCD CARD-79
              99, CARD-68
        LD
                                             B
                                                  BEGIN
        DM
              98,2,10
                                             DEND BEGIN
```

application of the unit cell vector transformation equations given in section 4.3 i.e.

$$\begin{bmatrix} h \\ k \\ 1 \end{bmatrix} = \begin{bmatrix} 0 & \frac{1}{2} & \frac{1}{2} \\ 0 & -\frac{1}{2} & \frac{1}{2} \\ -\frac{1}{2} & 0 & -\frac{1}{2} \end{bmatrix} \begin{bmatrix} h_{\mathbf{F}} \\ k_{\mathbf{F}} \\ 1_{\mathbf{F}} \end{bmatrix}$$

A blank card at the end of the input data terminates the calculations.

A.17 This final SPS programme written by the author converts the reduced cell indices (in cols 11-19) of a deck of cards (e.g. output from A3) back to F cell values. The matrix used is inverse to the one above:

→redu	aced	cell	indices
F cell	-1	-1	-2
indices	+1	-1	0
	+1	+1	0

according to the notation in International Tables, Vol.I.

APPENDIX B Calibration of the Stoe precession camera

A Buerger precession camera (Buerger, 1944) was used to photograph layers of the reciprocal lattice of SiF₄,2Py (section 3.3). The original black cardboard in the film cassette between the crystal and film had become buckled and worn and was replaced by cardboard and black paper. Calibration of the crystal to film distance F, set at 60mm for zero level photographs, was therefore necessary.

Quartz has been widely used as a standard for calibration (Bradley and Jay, 1933; Evans et al, 1949; Barnes et al, 1951) and its lattice parameters have been accurately determined by many workers including Miller and Du Mond (1940) and Lipson and Wilson (1941). Although quartz gives differences in lattice spacing, depending on its variety and origin (Keith, 1950 and 1955), these are significant in only the 4th decimal place. Due to inaccuracies in measurement of reciprocal lattice spacings from precession photographs, the minimum error in SiF_{\(\psi\)},2Py cell dimensions was 0.005\(\text{A}\), and hence no greater accuracy than ~0.1mm was necessary for the determination of F. Quartz parameters were therefore sufficiently accurate for the purpose required, and a single quartz crystal was supplied by the Geology Department.

Using unfiltered Cu radiation the crystal was aligned on the precession camera by Fisher's method (1952 and 1953), which consists of locating the centre of the circle of precession, formed by the

ends of prominent Laue streaks. The angle μ , between the incident beam and the normal to the plane being photographed, was initially taken as 10°, increasing to 20° and 25° as crystal setting was improved by calculated corrections to the dial and goniometer arcs. Account must be taken of the angles that the arcs make with the horizontal and vertical directions. The crystal was finally set, to within 5' on the dial and 10' on the goniometer arcs, with c* along the dial axis and b as the axis of precession.

hOl was recorded with CuKa radiation, $\lambda = 1.54178 \text{Å}$, and $\mu = 30^{\circ}$. The layer screen with annular radius r_s , is set at a distance s from the crystal, where $s = r_s$ cot $\cos^{-1}(\cos \mu - d^*)$. d^* is the height of the reciprocal level in r.l.u. and hence for zero level photographs, s is simply $r_s \cot \mu$.

The lattice parameters of the quartz hexagonal unit cell are: a = 4.9027kX, c = 5.3934kX or 4.9126Å and 5.4043Å (1kX = 1.00202Å). $a* = 2/a\sqrt{3} = D/nF\lambda$ where D is the distance in mm measured on the film over n spacings parallel to a*. Similarly F may also be found from c* = 1/c. The mean of all F values obtained was $59.74 \pm 0.05mm$, which was used for subsequent calculations of reciprocal lattice parameters from precession photographs recorded by this camera.

APPENDIX C Calculation of hydrogen positions

For both SiF4,2Py and SiCl4,2Py the first step was orthogonalisation of the oblique axes of the reduced triclinic unit cell.

Choose standard orthogonal axes x',y',z' such that y' coincides with b, x' is the projection of a on to the plane perpendicular to b and z' is perpendicular to x' and y'. In terms of oblique coordinates (x,y,z) (in A), orthogonal coordinates (x',y',z') (in A) are:

$$x' = x \sin \gamma + z(\cos \beta - \cos \alpha \cos \gamma)/\sin \gamma$$

$$y' = x\cos \gamma + y + z\cos \alpha$$

$$z' = z[\sin^2\alpha - (\frac{\cos\beta - \cos\alpha\cos\gamma}{\sin\gamma})^2]^{\frac{1}{2}}$$

For SiF_h, 2Py this becomes:

$$\begin{bmatrix} x' \\ y' \\ z' \end{bmatrix} = \begin{bmatrix} 0.9951 & 0 & -0.45171 \\ -0.09928 & 1 & -0.33737 \\ 0 & 0 & 0.82595 \end{bmatrix} \begin{bmatrix} x \\ y \\ z \end{bmatrix}$$

and for SiCl, 2Py

$$\begin{bmatrix} x' \\ y' \\ z' \end{bmatrix} = \begin{bmatrix} 0.91745 & 0 & -0.19805 \\ -0.3979 & 1 & -0.4563 \\ 0 & 0 & 0.8673 \end{bmatrix} \begin{bmatrix} x \\ y \\ z \end{bmatrix}$$

In the pyridine ring shown,

N-C3-H3, H1-C1-C4-H4 and

H2-C2-C5-H5 are straight lines.

The coordinates of N and C1-C5 were

HI CI C3 H3

taken from the latest SFLS cycle and were orthogonalised using

the appropriate matrix above. The C-H bond length is 1.08Å (Pauling, 1948) but for calculation of H positions it was assumed to be 1 Å, both for simplicity and because the carbon coordinates used have been calculated with no hydrogens included. To compensate for their absence, the carbon positions have been moved slightly from their true positions towards their corresponding H atom.

Express the orthogonal coordinates of C4 with respect to C1 as origin e.g. $x''_{C4} = x'_{C4} - x'_{C1}$. Now, $x''_{H1}/x''_{C4} = (-1)/C1 - C4$ and $C1 - C4 = \int (x''_{C4})^2 + (y''_{C4})^2 + (z''_{C4})^2$. Hence $x'_{H1} = x''_{H1} + x'_{C1}$, the orthogonal x' coordinate of H1 may be calculated. Similarly for y'_{H1} and z'_{H1} . The orthogonal coordinates (x',y',z') of all the hydrogens were found by this method, and then converted to reduced cell oblique coordinates (x,y,z), for inclusion in structure factor calculations, by application of the appropriate inverse matrix below.

SiF₄, 2Py:
$$\begin{bmatrix} x \\ y \\ z \end{bmatrix} = \begin{bmatrix} 1.00492 & 0 & 0.54959 \\ 0.09977 & 1 & 0.46303 \\ 0 & 0 & 1.21073 \end{bmatrix} \begin{bmatrix} x' \\ y' \\ z' \end{bmatrix}$$
SiCl₄, 2Py
$$\begin{bmatrix} x \\ y \\ z \end{bmatrix} = \begin{bmatrix} 1.08998 & 0 & 0.24890 \\ 0.43770 & 1 & 0.62515 \\ 0 & 0 & 1.15300 \end{bmatrix} \begin{bmatrix} x' \\ y' \\ z' \end{bmatrix}$$

APPENDIX D Least squares best plane

A least squares determination of the best plane lx' + my' + nz' = p through the five carbon atoms of the pyridine ring in SiFh, 2Py and SiClh, 2Py was made according to the theory given in section 1.4. Atomic coordinates with respect to the reduced triclinic cell were orthogonalised by the appropriate matrix in Appendix C, and initial approximate values of 1, m, n and p were obtained by calculating the plane through C1, C3 and C5. With respect to orthogonal axes x', y', z' this plane has equation:

$$\begin{vmatrix} x' & y' & z' & 1 \\ x'_{C1} & y'_{C1} & z'_{C1} & 1 \\ x'_{C3} & y'_{C3} & z'_{C3} & 1 \\ x'_{C5} & y'_{C5} & z'_{C5} & 1 \end{vmatrix} = 0$$

$$= Ax' + By' + Cz' + D = 0.$$

1, m, n and p were found from the equations:

$$1 = \frac{sA}{E}, \quad m = -\frac{sB}{E}, \quad n = -\frac{sC}{E}, \quad p = \frac{sD}{E}$$
where $s = sign$ of D and $E = (A^2 + B^2 + C^2)^{\frac{1}{2}}$

The deviation of atom i from this plane is lx; + my; + nz; $p = \Delta_i$, where x_i^i , y_i^i , z_i^i are the orthogonal coordinates in \mathring{A} of atom i. It is required to minimise $\sum_{i=1}^{3} \Delta_{i}^{2}$ with respect to the three independent variables m, n and p. $(1 = (1 - m^2 - n^2)^{\frac{1}{2}})$. This occurs when $\sum_{i=1}^{5} \Delta_i \frac{\partial \Delta_i}{\partial u} = 0$ for u = m, n, p.

 Δ_{i} is not linear in m, n and p but $\delta_{u} = u - u'$, where u' is

the approximate value of m, n or p, and $\Delta_{\bf i}$ can be represented by the first two terms of a Taylor series: $\Delta_{\bf i} = g_{\bf i} + \sum_{\bf u=m,n,p} \frac{\partial \Delta_{\bf i}}{\partial {\bf u}} \delta_{\bf u}$.

This gives the 3 normal equations for u = m, n and p:

$$\sum_{i=1}^{5} \frac{\partial \Delta_{i}}{\partial u} \sum_{u=m,n,p} \frac{\partial \Delta_{i}}{\partial u} \cdot \delta_{u} = -\sum_{i=1}^{5} \Delta_{i} \frac{\partial \Delta_{i}}{\partial u}$$

It can be shown that $\frac{\partial \triangle_1}{\partial m} = -\frac{mx'_1}{1} + y'_1$;

$$\frac{\partial \Delta_{\mathbf{i}}}{\partial n} = -\frac{nx'_{\mathbf{i}}}{1} + z'_{\mathbf{i}}; \frac{\partial \Delta_{\mathbf{i}}}{\partial p} = -1.$$
 Hence:

$$\begin{bmatrix} \left(\frac{m^{2}}{12}\sum_{\mathbf{x}^{2}}\frac{2m}{1}\sum_{\mathbf{x}\mathbf{y}+\Sigma}\mathbf{y}^{2}\right) & \left(\frac{mn}{12}\sum_{\mathbf{x}^{2}}\frac{n}{1}\sum_{\mathbf{x}\mathbf{y}-\frac{m}{1}}\sum_{\mathbf{x}\mathbf{z}+\Sigma}\mathbf{y}\mathbf{z}\right) & \left(\frac{m}{1}\sum_{\mathbf{x}-\Sigma}\mathbf{y}\right) \end{bmatrix} \begin{bmatrix} \delta_{\mathbf{m}} \\ \delta_{\mathbf{m}} \end{bmatrix} \begin{bmatrix} \frac{m}{1}\sum_{\mathbf{x}-\Sigma}\mathbf{y} \\ \frac{mn}{12}\sum_{\mathbf{x}^{2}}\frac{n}{1}\sum_{\mathbf{x}\mathbf{y}+\frac{m}{1}}\sum_{\mathbf{x}\mathbf{y}+\Sigma}\mathbf{y}\mathbf{z} \end{bmatrix} & \left(\frac{n}{12}\sum_{\mathbf{x}^{2}}\frac{2n}{1}\sum_{\mathbf{x}\mathbf{z}+\Sigma}\mathbf{z}^{2}\right) & \left(\frac{n}{1}\sum_{\mathbf{x}-\Sigma}\mathbf{z}\right) \\ \left(\frac{m}{1}\sum_{\mathbf{x}-\Sigma}\mathbf{y}\right) & \left(\frac{n}{1}\sum_{\mathbf{x}-\Sigma}\mathbf{z}\right) & 5 \end{bmatrix} \begin{bmatrix} \delta_{\mathbf{m}} \end{bmatrix} \begin{bmatrix} \frac{m}{1}\sum_{\mathbf{x}-\Sigma}\Delta_{\mathbf{x}} \\ \delta_{\mathbf{m}} \end{bmatrix} \begin{bmatrix} \frac{m}{1}\sum_{\mathbf{x}-\Sigma}\Delta_{\mathbf{x}} \\ \sum_{\mathbf{x}}\Delta_{\mathbf{x}} \end{bmatrix} \begin{bmatrix} \frac{m}{1}\sum_{\mathbf{x}}\Delta_{\mathbf{x}} \\ \sum_{\mathbf{x}}\Delta_{\mathbf{x}} \end{bmatrix}$$

Using the initial 1, m, n and p values and the known orthogonal coordinates of the five carbon atoms, the three simultaneous equations were solved for the shifts δ_m , δ_n and δ_p , giving improved values of 1, m, n and p. These, together with the new residuals, Δ , were used for a 2nd cycle, which gave shifts significant in only the 6th or 7th decimal place in all cases.

The best fit plane lx' + my' + nz' = p was found with respect to the oblique axes (x,y,z) of the reduced cell by means of the equations and appropriate matrix given in Appendix C. When y = z = 0, $x' = x\sin\gamma$, $y' = x\cos\gamma$ and z' = 0. Substitution into lx' + my' + nz' = p, gives x = a, the intercept on the x axis. Similarly for intercepts b and c on y and z, and the least squares best fit plane $\frac{x}{a} + \frac{y}{b} + \frac{z}{c} = 1$ is obtained.

Table A

SiF₄,2Py

Observed and calculated structure factors for linear diffractometer (L) and photographic (P) data

**	Tr	+	(7)	(77.)	/m \	(77.)
Η	K	\mathbf{L}	(F _o) _L	(F _c) _L	$(F_o)_p$	(F _c) _P
000000000000000000000000000000000000000	00000001111111111112222222222222233333333	1234567122334455677012233445567801233445567	364 7566 7566 7566 7566 7566 7566 7566 75	474020 474020 476850 4351440 4351440 4351440 4351440 4351440 4351440 4351440 4351440 436000 436000 436000 43600 43600 436000 436000 436000 43600	- 750 4220 4320 4376 4376 4376 43774 43270 40070	742 620 776 -1600 378 2962 4394 1024 -258 1092 -258 1092 -258 1340 -1722 1812 -1866 -1722 1812 -1866 -1988 -

•

000000000000000000000000000000000000000	80123344567801234567012234560112345612233445667		282 148 4728 3355520 1562 1562 1563 1562 1668 1668 1668 1668 1668 1668 1668 16	280 150 150 150 150 150 151 151 151 151 15		- 40028 - 4	- 2242 - 1994 -
		012334456780123456701223456011234561223344566	012534456780123456701223456011234561223344566	0 1 2 3 4 4 608 4 4 2 2 8 8 8 1 3 3 0 8 5 5 5 2 1 6 8 8 1 5 5 5 2 2 1 6 2 2 3 3 4 4 5 6 6 6 1 2 2 3 3 4 4 5 6 6 6 1 4 4 5 6 6 6 1 4 4 5 6 6 6 1 4 5 6 6 1 4 5 6 6 1 4 5 6 6 1 6 1 6 1 6 1 6 1 6 1 6 1 6 1 6 1	0 144 150 -608 -680 384 718 532 718 534 722 718 532 388 390 1454 532 388 390 1454 550 558 516 1454 551 150 580 388 390 1454 510 1454 510 1420 184 1421 184 1422 184 1430 184 1440 180 132 246 220 248 220 248 236 236 188 354 272 256 236 86 354 278 254 236 188 354 290 1802 1340 1340 222 33 144 130	0	0 144 150 240 1 -608 -680 -600 2 444 384 402 3 722 718 678 -3 168 532 540 388 390 354 1470 -5 558 510 492 -6 552 516 552 -6 552 516 552 -7 420 442 366 -8 162 184 - 0 -562 -556 -498 -1 430 514 378 -2 - 426 -498 -1 430 514 378 -2 - 498 526 -3 460 666 546 54 526 580 558 958 962 224 220 150 222 -3 - - 120 -2 266 652 420

1 - 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	001-11-222333344455556778001-11-222233334444555566	8 48 0 8 2 1 8 3 3 5 6 2 2 1 3 3 3 2 3 7 6 5 6 6 8 8 8 8 6 6 6 6 6 6 6 8 8 8 6 6 6 6 6 6 6 6 8 8 8 6 6 6 6 6 6 6 6 8 8 8 6	1946 1924 1982 1982 1982 1982 1983 1879 1983 1879 1983 1879 1983 1879 1983 1879 1983 1879 1983 1879 1983 1879 1879 1879 1879 1879 1879 1879 1879	-12 14 -46 5 8 21 8 92 7 92 4 96 63	- 48
-1 1 -1 -1 1	2 4 -4 5 -5 -5 -5 -6 6	346	280 482 300 692 674 176	3'	72 326

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Table B

SiCl₄,2Py

Observed and calculated structure factors

H	K	L	(F _o)	(F _c)	H	К	L	(F _o)	(F _c)
000000000000000000000000000000000000000	0000111111222222233333444444455555566666777		26444488602664600008264660000820648220662880046666648846888600098264662800682046822066288668886688868886888688868886888	314 1942280 102280 103240 1032	000000000000000000000000000000000000000	00011111122222223333334444444555555666666777	2571234567023456702345691234579123458012469124	-388 -3988 -3988 -3918 -	-48462628002 -484662628002 -484660460086660 -4840662420044406624200 -4840602420044406624200 -4840602420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -484062420044406624200 -4840624200444066244200 -4840624200444066244200 -4840624420 -4840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -8840624420 -88406244420 -88406244420 -88406244420 -88406244420 -88406244420 -88406244420 -88406244420 -8840624440 -8840624440 -8840624440 -8840624440 -8840624440 -8840624440 -8840624440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440 -884062440

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-8	5	-3	764	808	-8	5	-4	- 262	- 328
-8	6	0	486	504	-8	6	1	770	716
-8	566	-1	- 252	- 28	-8	6	1 2	- 272	- 418
-8		-2	- 252 1002	- 28 906	-8 -8 -8	6667	-3 0 -1	1052	1048
-8	6	-4	- 276	- 318	-8	7	0	1472	1226 306
-8	6 7	-1.	894	- 318 688	-8	8	-1	1472 376	306
-8		-1. -2	- 454	- 416	-9	8 2 3	0	- 752	- 746
-9	8 2 3	2	1030	1042	-9 -9 -9	3	0	- 644	- 774
-9	3	2	824	944	-9	4 5 5	0 -1	428 476	416
-9		-2 1 -2	1002	1026	- 9	5	0	476	484
-9	4 5 5	ı	434 838	514	- 9	5	-1	380	386
-9	5	-2	838	918	-9	6	0	894	934
-8888889999999999999999999999999999999	6	-1	306	500	-9	6	-2	286	416 484 386 934 128

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